JPL Hardware Requirements
Certification Review (HRCR)Flight Spare (FS)
Spectrometer Long Wavelength (SLW)
Bolometer Detector Assembly (BDA)
10209800-4 S/N 015

SPIRE Element Herschel Space Observatory Project

> May 26, 2005 Updated August 16, 2005

Change Log

Issue	Date	Section	Changes
1.0	26 May 05		Initial version (HRCR review)
1.1	16 Aug 05		Distributed PDF version
		1	Included signed HRCR form
		3	Updated ECR / NCR numbers in Issues, added RFW-022
		5	Corrected ECR / NCR numbering, included images of signed
		3	ECR/NCRs. Added ECR-003 for completeness.
		6	Added RFW-022 (BDA test Temperature), corrected
		U	numbering: 005->005v1, included images of signed versions.
		8	Added Spectrometer Filter change procedure and updated
		0	General handling document.
		9	Added RFW-022 reference
		10	Incorporated updated performance data, (v4)
		13	Added planned final electrical test
		14	Added alignment measurement summary, annotated feedhorn
		14	data.

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RAL EIDP Table Of Contents Vs. HRCR Contents

EIDP Section	EIDP	HRCR Box #	Comments/Notebook Section
1	Shipping Documents		Shipper and Final IR
2	Transportation, Packing, Handling & Integration Procedures	20	Section 8
3	Certificate of Conformance / Delivery Review Board MoM		HRCR form is the CofC
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10	Operational Manual	20	
11	Top Level Drawings (inc. Family Tree)	14	Section 4
12	Interface Drawings	26	Section 13
13	Functional, Block & Mechanical Drawings	14	Section 4
14	Electrical Circuit Drawings		See Electrical Handling Doc.
15	Serialized Components List		In the build books – not shipped
16	Mass Properties/ Power Budget		Mass found in header of HRCR
17	Qualification Status List / Test Matrix	22	Qual. Report to be supplied later, Summary in Section 11
18	Test Reports		To be supplied later, Summaries in Sections 9 and 10
19	Open Work / Deferred Work / Open Tests	5	
20	Calibration Data		Section 10
21	Historical Record		Section 12
22	Manufacturing Logbook(s)		To be retained at JPL
23	Operating Time / Cycle Record	24	Section 12
24	Connector Mating Record	24	Section 12
25	Age Sensitive Items Record		NA for BDA
26	Pressure Vessels – History/Test Record		NA
27	Temporary Installation Record		Section 12
28	Reference List of EIDPs (Lower level)		300mK Filter EIDP - Section 14
29	Other Useful Information		Section 14

JPL Hardware Requirements Certification Review – SPIRE Element

Assembly/Subsystem			PEM					Phone			Section Date		Date	Date		
SPIRE			Martin Herman			an	3	(818) 354-8541 386		386	26 May, 2005		e			
Drawing/ Part No.	Dwg. Rev.	Nomencla	clature Serial No.			Serial No.	Model	Ту	/pe		Final IR No.			Mass (gra As Meas.		
10209800-4	В	Bolomete Assembly		tecto	or		015	FS	SL	LW	926211		ĺ		527 g / 5	
Check applicable answer and give no remarks column	ecessary expl	anation in	Y e s	N o	N / A		·	Remarks			Data Attachments	(Package	Sec. #)	Signature & Date	Approval	
Are all drawings and specifications or released and frozen?			x									None (Cog E Mah	wäliß	5-26-05
Do the released drawings and speci approved changes?			X									s None (S	Sec. 5)	PEM	n Her	6/405
Is hardware identical to other hardw provide difference list.	,	,		X			vious Hardware wa erence list attache	as PFM SLW BDA S/N00 d	8. See			None (Sec. 6)		tt Hunt	
4 Does the hardware meet the requirer requirements, specifications, waivers a difference list.	nd/or ICDs ? If	no, provide	X				See Issues (section 3). See section 11 for detector performance matrix. 17. Open MRBs Environments/Ref				S DIV	10/05				
Have all IR discrepancies and MRBs been dispositioned and agreed to by Engineering/ QA?			X					ψ**			18. Open P/FRs on to ☐ Attached ☑	None (Sec. 7)	Mission A	ssurance Mgr.	25/26/05
Is complete as-built list information included in the build book?		build book?	X								19. Open P/FRs on s ☐ Attached	None (Project _	-)-20	5/26/05
Have all required environmental tests & analyses been completed?			x			See	section 9.				20. Handling Docume	ents None (Sec. 8)	PI	Bok	5/27/05
Is all required assembly and/or subsystem level functional testing complete?			x								21. Shortage List Attached	None (I	N/A)		U	
Have all piece parts, processes and materials been approved by JPL?		n approved	x			See	MIUL coverpage i	n section 14.	22. Require		22. Requirements Ve		Matrix			,
Does this hardware meet all conta requirements?	mination contro	ol	X								23. Qualification Stat		Í			
Are all required shipping containers, shipping procedures, and special handling procedures ready?			X			See	section 8 for hand	dling procedures.			24. Connector Mate /		.og			
12. Is additional work required to bring this hardware to flight readiness?								None (Sec. 12)							
13. Is this hardware acceptable for flig	ht?	٠.	x								26. ICDs Attached	None (Sec. 13)			

Difference List

Part	Previous hardware:	Current hardware	Notes:
	10209800-4 PFM SLW SN 008	10209800-4 FS SLW SN015	
10209860 suspension	no side screws into invar spacers	side spacer screws were used	screws had been eliminated in error when the vespel safety
assy.			spacer was eliminated from the design. Units after SN009
			(PFM SSW) have screws installed.
10209890 middle ring	suspension Ring-A is pinned to flexure	suspension Ring-A is pinned to	Old pins were partially machined away after assembly in early
assy (part of	mounting plate with both old pins and	flexure mounting plate only new	suspension units (up to suspension SN006). Final design used
suspension)	smaller new invar pins.	invar pins.	only the new pins.

Inspection Report Page 1 of 1

JPL Poms	*** INSPECTION REPORT *** Printed Copies are for Reference Only - check with PDMS for official version			ence Only - Please Action			Action BROWSE		Status "IR & IR IRDI Initiated"		
REFERS TO:											
Part Number		Dash	Number		Revision	L	atest Rev	Serial 1	Number	:	Quantity
10209800-4		(with pa	rt numbe	r)	В		B	0	15		1
		Y ON CEMEN	DETEC		DD 4 47						
Nomenclature:	_	LOMETER	DETEC	TOR A							
Prgm/Project:	HSO	-PLANCK			Inspection	Date:	06-APR-20	005			
COGE:	WEI	LERT, MARK A.			ECO/ECI:						
QAE:	HUG	HES, SCOTT P.			Reference	Designa	tor: SPIRE				
JPL/Mfr:	JPL				Lot No.:						
Type of Inspection:	Final	l-Ship			Insp. Std /	Spec No	<u>).:</u>				
Type of Item:	Fligh				AIDS No.						
Location:	JPL				Work Ord	er No.:					
Manufacturer:	JPL				CAGE Co	de:					
Supplier:	JPL				Receipt No	<u>).:</u>					
Parts received by:					Property /	ID:					
Received date:	Ī				PO/CT No	.:					
Oty Accepted:	ĺ				Line No.:						
Qty Rejected:	0				Rel / Mod	No.:					
QA Alert?	1				CAN Requ	ired?					
IMTE Code:	None	•			IMTE Nur	nber:					
IMTE Code No. 2:	None	•			IMTE Nui	nber No	. 2:				
IMTE Code No. 3:	None)			IMTE Nui	nber No	. 3:				
IMTE Code No. 4:	None)			IMTE Nui	nber No	4:				
Orig Nomenclature:											
DISCREPANT ITEMS	S:										
Item	Disc	rep Code	Qty	Zone	S/N	J	Description		Re-W	ork	Files
<u> </u>					lo Discrepant						
<u>Item</u>		<u>I</u>	Disposition				Root Caus Code		spo ode	Disp.	Stamp Date
			7	This IR has N	Jo Discrenant	Items	<u>Code</u>		<u>oue</u>	Appr.	Date
This IR has No Discrepant Items Inspection Report Notes: HARDWARE LISTED ABOVE HAS BEEN COMPLETED INSPECTIONS AND TESTING AND ACCEPTABLE TO DELIVER TO NEXT INTERGRATION RUTHERFORD APPLETON LABORATORY SPACE & SCIENCE TECHNOLOGY DEPT.											
CHILTON, DIDCOT (JAFOF	(D, ENGLAND UN	TED KINGD	OM OXII O	ųx attn: El	uc SAV	v i ek PH#1235 4	+4 0385			
		Initiated by VALENZUELA, LORRAINE V.	OGE	Signed by QAE			Closed by				
Number of Files Atta	ached	Date 17-MAY-2005		Date		Da	ite		Date		
Reserved by	R	Reserved on	Reaso	<u>n</u>							

Issues FS SLW BDA 10209800-4 S/N 015

Configuration / Processing:

• The maximum height of 300 mK stage exceeds ICD drawing 10209721 allowed range by 1.0 mm due to changes in the spectrometer 300 mK filter stack thickness. See attached ECR: HR-SP-JPL-ECR-007 in section 5. This change has been incorporated into Rev-C of the ICD drawing 10209721.

Several other ECRs related to the BDA hardware have been incorporated into released drawings. These do not apply directly to the SLW BDA type, but they affect the same drawings. They are included for reference:

- A focus position shift caused by an internal mechanical interference fix was incorporated into ICD drawing 10209721 Rev C per HR-SP-JPL-NCR-007 (attached in in section 5) This is applicable only to -2 PMW and -3 PSW BDAs.
- A pixel map modification was incorporated into electrical schematic 10209725 Rev C per HR-SP-JPL-ECR-005v2 (attached in section 5). This is applicable only to -2 PMW and -3 PSW BDAs. This drawing revision also incorporated JPL ECR 1026751.

Environmental Test:

- Shake tests were performed with non-flight-like 8-32 mounting screws, instead of 6-32. See attached email regarding this issue: (M. Herman, 15 May 2003) -- *This same issue applied to all the previous BDAs.*
- Shake tests were performed in accordance with approved waivers HR-SP-JPL-RFW-005v1 (Sine Vibration Omission), HR-SP-JPL-RFW-006 (Vibration Test Levels), and HR-SP-JPL-RFW-022 (BDA Vibration Test Temperature). See Waiver List (section 6).

Martin Herman, 04:34 PM 8/11/2003 -0700, Waiver Request (vibration fastners)

Date: Mon, 11 Aug 2003 16:34:04 -0700

From: Martin Herman < Martin.I.Herman@jpl.nasa.gov>

Subject: Waiver Request (vibration fastners) X-Sender: miherman@pop.jpl.nasa.gov

To: Mark.A.Weilert@jpl.nasa.gov Cc: Henry.Abakians@jpl.nasa.gov

Date: Thu, 15 May 2003 11:41:18 -0700

To: Matt Griffin Matt.Griffin@astro.cf.ac.uk, Eric Sawyer <e.c.sawyer@rl.ac.uk, Chris

Brockley-Blatt <cb@mssl.ucl.ac.uk>, Berend Winter <bw@mssl.ucl.ac.uk>

From: Martin Herman < Martin.I.Herman@jpl.nasa.gov>

Subject: Waiver Request (vibration fastners)

Cc: Ben.A.Parvin@jpl.nasa.gov, Jamie Bock <jjb@astro.caltech.edu>, Gary Parks

<Gary.S.Parks@jpl.nasa.gov>, kalyani@squid.jpl.nasa.gov

Bcc:

X-Attachments:

Dear Matt and SPIRE Team,

To refresh everyone's memory. We requested the following information:

What type of fasteners will be used in Europe to mount the BDA? In our ICD, 6-32 fasteners are called for. However, the current test hardware uses 8-32 fasteners. We are looking to be consistent with the flight implementation.

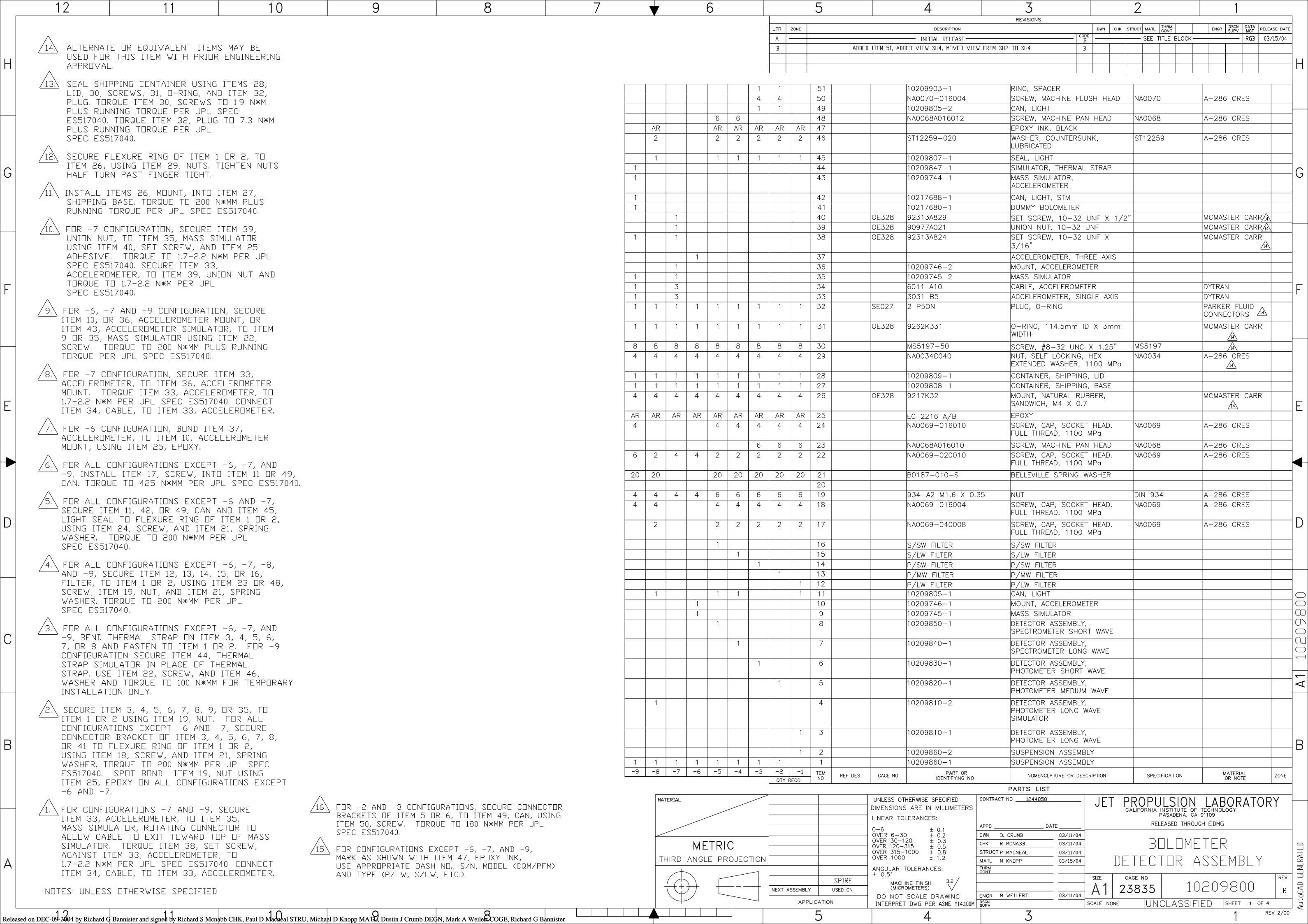
The answer (Thanks Chris) was 6-32. Our current test fixture uses 8-32 and we are getting ready for vibration testing of the CQM next week. Therefore, we had a mechanical engineer look into this issue. His (Paul MacNeal) response was:

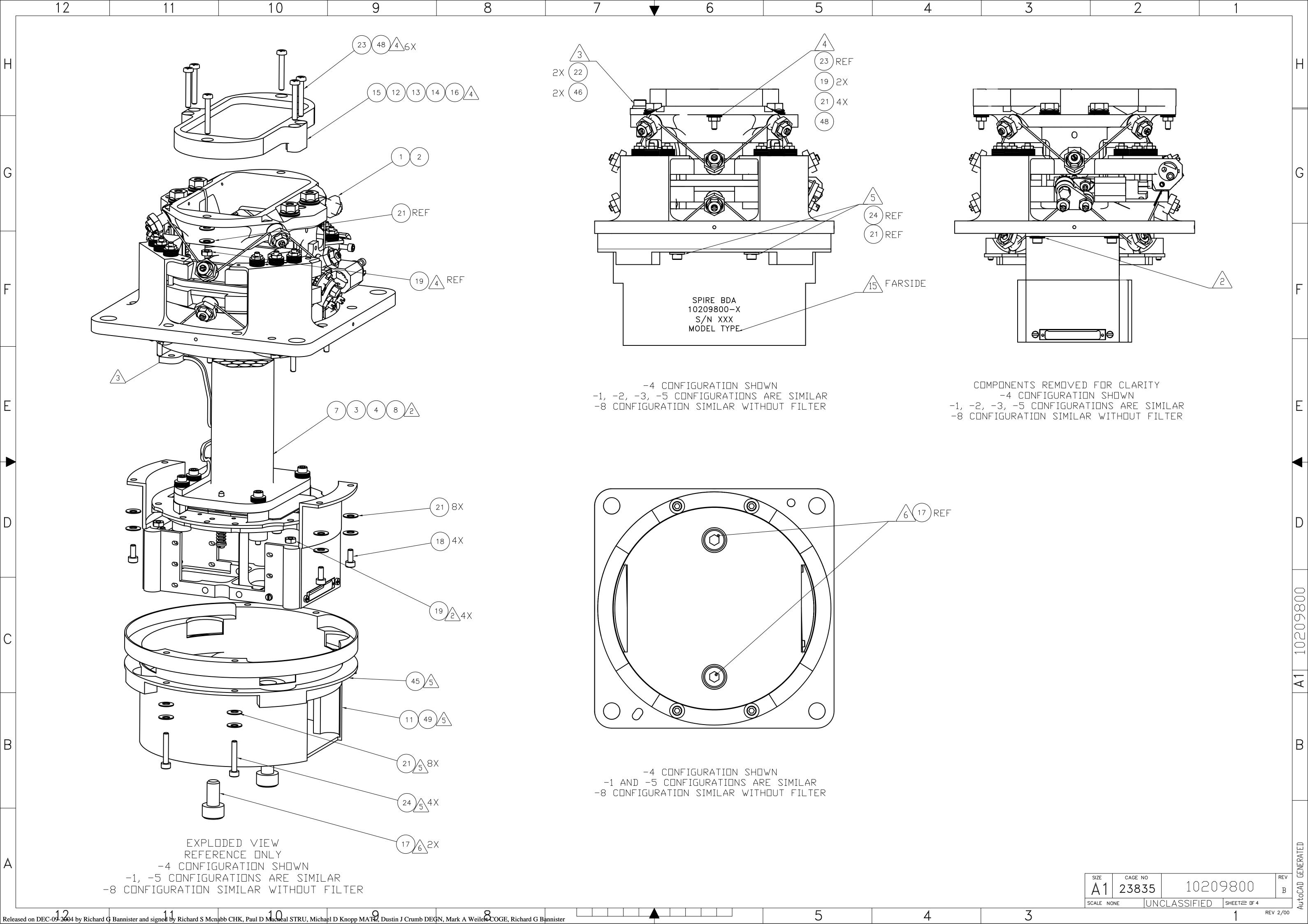
It will acceptable to use four #8-32 fasteners for the vibration tests at JPL. The reasons are....

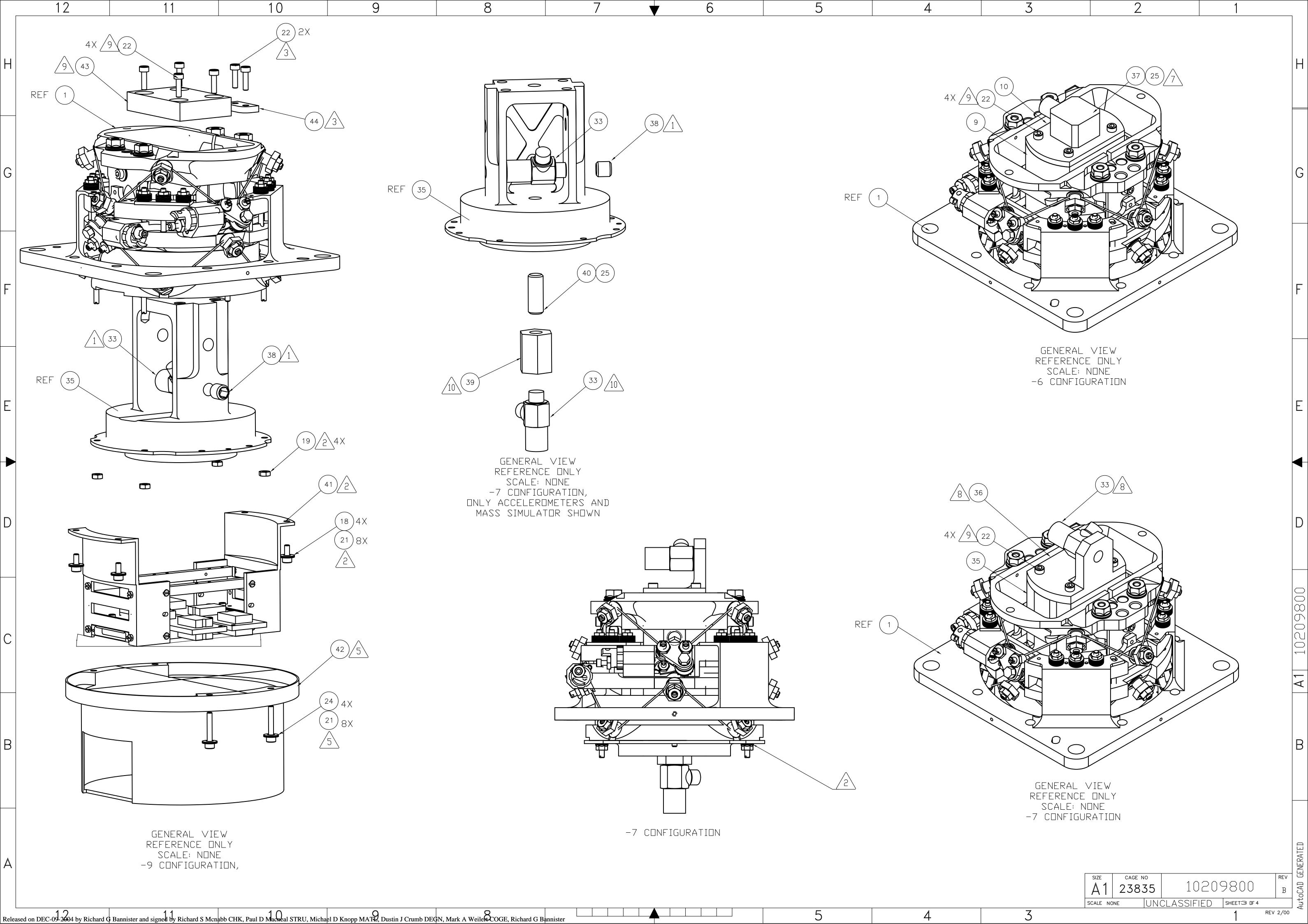
- The test fixture has already been built using #8-32 tapped holes,
- 2) The use of #6-32 fasteners torqued to full value should be able to resist over 200 G's of lateral force before allowing slippage, and therefore is not a critical component of the vibration test, and
- 3) The test is primarily performed to verify integrity of the flexures, braid, and other components, and not the interface fasteners.

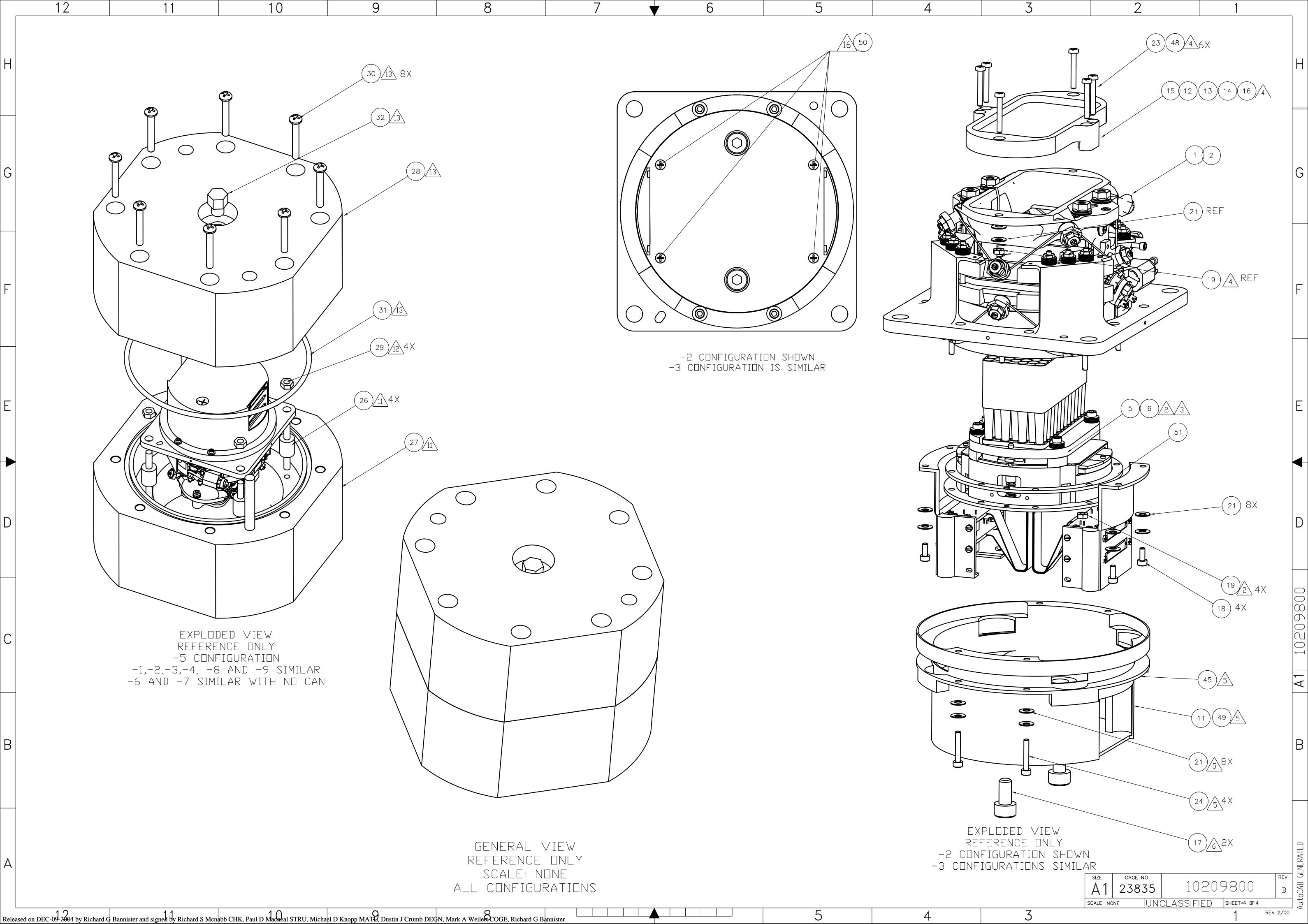
Based on this information, we are requesting a waiver for the CQM PLW vibration and for future QM, CQM, PFM and FS tests. The change for future test is small, but the fiscal situation is extremely challenging and no technical risk to the program is evident with the existing approach.

Thanks, Marty









ECR/NCR List FS SLW BDA 10209800-4 S/N 015

All of these have been incorporated into released drawings.

- 1. HR-SP-JPL-ECR-003 Changes to the 300mK filter clamp fixing holes.
- 2. HR-SP-JPL-ECR-007 Spectrometer BDA Envelope Height

NOTE: The following ECRs do not apply directly to the SLW BDA type, but they represent changes to the applicable ICDs and top level drawing so they are included here for reference.

- 3. HR-SP-JPL-ECR-005v2 300mK Stage Assembly BDA Kapton cable routing design error. (applies only to PMW and PSW BDAs)
- 4. HR-SP-JPL-NCR-007 PMW and PSW focal position shift



Document / Engineering Change Request

PRODUCT ASSURANCE Space Science and Technology Department

DOCUMENT /ENGINEERING CHANGE REQUEST NO.: HR-SP-JPL-ECR-003

PROJECT:	SPIRE	ORIGINATOR:	Martin Herman, JPL
SYSTEM:	FPU	SIGNATURE	
SUB-SYSTEM:	300mK Filter Stacks	DATE	22 nd May 2003

1) TITLE OF CHANGE: Changes to the 300mK filter clamp fixing holes.

2) AFFECTED ITEMS / WORK PACKAGES: 300mK Filters

3) CLASSIFICATION OF CHANGE: (Highlight as required) URGENT ROUTINE

4) DOCUMENTS AFFECTED (TITLE, NUMBER, ISSUE, PARAGRAPH):

Filters - Interface Control Document - SPIRE-UCF-PRJ-001151 issue 2.2

Figure 13 – "Filter assembly GA" – drawing number BDA.01.006

Figure 14 - "BDA upper filter ring" - drawing number BDA.01.003

5) DESCRIPTION OF CHANGE:

- 1. The drawings BDA.01.006 and BDA.01.003 will be combined into one interface drawing. Title will be "300mK Filter ICD", drawing number will be "Filt-CQM/PFM-200"
- 2. Add missing dimension for length of projecting mounting legs 2.75 \pm 0.02mm in sector H8
- 3. Add box for total stack thickness and mass per channel in sector A8
- 4. Change existing callout in sector D4 from "6 x 2.00mm thru" to "6 x 2.00mm thru. Counterbore 3.8mm dia., 1.00mm deep. Countersink 2.40mm dia., 45 $^{\circ}$ "
- 5. Modify existing parts in accordance with the new ICD FILT-CQM/PFM-200

(Figure 1. may be used for reference)

6) RELATED FACTORS: (Highlight as required)

SPACECRAFT	PERFORMANCE	POWER	OTHERS (SPECIFY)
GROUND SEGMENT	ELECT INTERFACES	WEIGHT	
LAUNCH VEHICLE	MECH. INTERFACES	SCHEDULE	
PAYLOAD	TEST/VERIFICATION	COST	

7) NEED / JUSTIFICATION FOR CHANGE:

Late specification of fixtures to be used by JPL

SPIRE-UCF-PRJ-001151 issue 3 Issued accordingly ECR Closed

ATTACHMENTS:	DISTRIBUTION:	CHANGE	Digitally	
Draft version of new ICD –		APPROVED	signed by Eric	
incomplete – for reference			Clark	
only			0 1/1/	
300MK_FILTER_ICD_170403		SIGNATURE:	Compare Date:	
weilert.doc			2005.07.13	
Shown as figure 1.			11:17:10	
		DATE:	+01'00'	



Ε

D

С

В

DETECTOR

8

PLW PMW PSW SLW SSW DIMENSION A

5.394 5.275 5.482 6.629 6.422

Document / Engineering Change Request

PRODUCT ASSURANCE Space Science and Technology Department

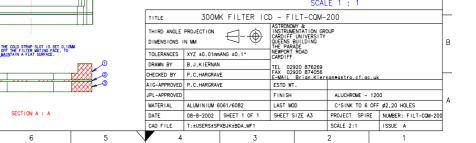


Figure 1 Preliminary draft of new ICD for reference only. Additional proposed changes to this drawing will be implemented by Cardiff, and sent to JPL for approval.



DOCUMENT / ENGINEERING CHANGE REQUEST (ECR)

PRODUCT ASSURANCE Space Science and Technology Department

DCR / ECR Number:

HR-SP-JPL-ECR-007

Spacecraft / Project	HERSCHEL	Originator's Name	Martin Herman	
System / Experiment / Model	SPIRE /	Signature		
Sub-System		Date	November 20,20	003
Assembly		Classification	Urgent	Routine
Sub-Assembly		Ref. Doc. / Drwg No.	JPL dwg 10209	721
Item	Bolometer Detector Assembly (BDA)	Reference		

ECR/DCR Title	Spectrometer BDA Envelope Height
---------------	----------------------------------

ECR Description

On the ICD Drawing 10209721 sheet 2, zone H4, the current maximum height dimension is 42.5 mm from the BDA mounting plate. This dimension needs to be changed to 43.6 to encompass the two spectrometer BDA types, SLW and SSW. Photometer BDA types do not require this change. The current dimension will be replaced with a note giving the two BDA type dependent values. The allowed 300mK stage shift given in note 9 will remain.

Need / Justification For Change

The Spectrometer BDA (types SLW and SSW) 300mK filter stacks were at some point increased in thickness due to the addition of a lens. This change was not flowed down into the BDA ICD. The SLW BDA S/N008 maximum height was measured at 44.04 mm from the mounting plate, which is 1.04 mm higher than the current allowed ICD range. The nominal 42.5 mm height plus the 0.5mm allowed displacement of the 300mK stage (see ICD note 9) gives the current 43.0 mm max height.

Affected Items / Work package (Title, Number, Issue, Para)

ICD drawing 10209721 rev B

Related Factors (Highlight as applicable)								
Spacecraft Performance Power Others (Specify)								
Ground Segment	Elect. Interfaces	Weight						
Launch Vehicle	Mech. Interfaces	Schedule						
Payload	Test/Verification	Cost						

Attachments	Distribution

Change Approved Project	Signale Not Vertex Vertex	Digitally signed by Eric Sawyer Date: 2005.07.22 13:26:54 +01'00'	Change Approved Customer	N/A
Project Closure	Es Chint.	Digitally signed by Eric Clark Date: 2005.07.22 14:19:40 +01'00'	Customer Closure	N/A

Issue 04



DOCUMENT / ENGINEERING CHANGE REQUEST (ECR)

PRODUCT ASSURANCE **Space Science and Technology** Department

DCR / ECR Number: HR-SP-JPL-ECR-005v2

Spacecraft / Project	HERSCHEL	Originator's Name	Anthony Turner
System / Experiment / Model	SPIRE /	Signature	
Sub-System		Date	<mark>1/19/2004</mark>
Assembly	10209800 -2 and -3	Classification	Urgent Routine
Sub-Assembly	10209820 and 10209830	Ref. Doc. / Drwg No.	10209775
Item	Kapton cables assemblies, 10217706 and 10209825	Reference	

ECR/DCR Title	300-mK Stage Assembly-BDA Kapton cable routing design error
---------------	---

ECR Description

Kapton cable right (10217705) was designed for a length of 73.93mm and Kapton cable left (10209824) was designed for a length of 68.87mm. This length designation forces the shorter cable to route into connector positions J01 and J02 on the 10209820 and 10209830 Detector Assembly-BDA builds while the longer cable will route into the J03 and J04 connector positions. This routing will cause a swap in the pixel maps for each connector denoted in wiring schematic 10209725-A under the 10209800-2 and 10209800-3 columns. Below is the correct switch in pixel maps for each column (only the first pixel of the original column is denoted for all connectors but the entire column should be switched accordingly):

10209800-2 P/MW: J01 - first pixel A7, J02 - first pixel E7, J03- first pixel A13, J04 - first pixel R1

10209800-3 P/SW: J01 - first pixel D6, J02 - first pixel F12, J03- first pixel R1, J04 - first pixel E1

In order to:

- (1) maintain the existing pixel allocation, and
- (2) ensure that the readout of the PTC Channels is carried out on DCU J22 the JFET-BDA harnesses need to be swapped and physically relabelled as follows:

JFP J37 → JFP J39

JFP J39 → JFP J37

JFP J40 → JFP J38

JFP J38 \rightarrow JFP J40

JFP J29 \rightarrow JFP J31

JFP J31 → JFP J29

JFP J30 \rightarrow JFP J32

JFP J32 \rightarrow JFP J30

The SPIRE Block Diagram (Issue 5.8) needs to be updated to reflect this change.

JPL drawing (10209725 Rev B) needs to be updated.

SPIRE Block Diagram (Issue 5.8) needs to be updated.

The re-labelling of the connectors (MDM 51S) will mean that the corresponding BDA-JFET harnesses will have a 180° twist in them between the FPU wall and the JFET rack.

Need / Justification For Change

The current flex cable assembly/routing will not correctly map to the pixel locations denoted in 10209725-A wiring schematic, SPIRE. The current schedule/budget will not allow for an acquisition of replacement cables which may have at least a 12-20 week lead from the manufacture. All sub-assembly builds (10209820 and 10209830) would have to be placed on hold until the new cables arrive. The schedule impact could be up to 6 months. The above pixel map designation change would have a minimal effect on the software side, save from rebuilding flex kapton cables and keep the project on its current schedule.

Affected Items / Work package (Title, Number, Issue, Para)

All 10209820 and 10209830 sub assemblies.

Drawing 10209775-A

SPIRE Block Diagram (Issue 5.8)



DOCUMENT / ENGINEERING CHANGE REQUEST (ECR)

PRODUCT ASSURANCE
Space Science and Technology
Department

DCR / ECR Number:

HR-SP-JPL-ECR-005v2

SPIRE Block Diagram (Issue 5.8) JPL drawing (10209725 Rev B					
	Related Factors (Highlight as applicable)				
Spacecraft	Performance	Power	Others (Specify)		
Ground Segment	Elect. Interfaces	Weight			
Launch Vehicle	Mech. Interfaces	Schedule			
Payload	Test/Verification	Cost			

Attachments	Distribution

Ref SPIRE-RAL-MoM-002462v1 NRB ECR Closed

Change Approved Project	Change Approved Customer	
Project Closure	Customer Closure	

Issue 04



NON-CONFORMANCE REPORT (NCR)

PRODUCT ASSURANCE Space Science and Technology Department

NCR Number:

HR-SP-JPL-NCR-007

Spacecraft / Project	Herschel	Originator's Name	Martin Herman	
Experiment / Model	SPIRE / PFM+FS	Signature		
Sub-System		Date	July 1, 2004	
Assembly		Lovel (Usebset it assistants)	Major	Minor
Sub-Assembly		Level (Highlight if applicable)	Major	IVIIIIVI
Item	PMW and PSW BDA	NRB Reference		
	(10209800 -2 and -3)	NKB Reference		
Serial Number	11, 12, 14,15 (TBC)			

NCR Occurred During (Highlight if applicable) Manuf	acture Inspection	Test	Integration	Other
--	-------------------	------	-------------	-------

NCR Title	PMW and PSW focal position shift

NCR Description

An internal mechanical interference problem discovered during the manufacture of the PMW BDA has required a shift of the feedhorn and detector position with respect to the exterior envelope of the BDA. The exterior BDA envelope is unchanged. This NCR applies to PFM and FS models of the PMW and PSW BDAs.

This problem causes a non-conformance with the focus position specified in the ICD drawing 10209721 (see sheet 2, zone G3, and values tabulated on sheets 5-7). The PMW nominal focus position is changed by 1.0mm from 33.2mm to 32.2mm. The PSW focus position is changed by 1.2mm from 25mm to 23.8mm.

Front-short and back-short distances at the detectors are not affected by this change. The distance from the 300mK filter to the feedhorn entrance plane is increased by the shifts given above.

Other effects of this NCR are a small mass increase (approximately 4 grams) and a slight CG shift (estimated z-cg decrease of ~0.5mm). (Note that the PFM PMW, which is the only affected unit yet assembled, has a mass of 605g including the mass increase. This is still less than the 632g ICD limit.)

Cause of NCR

Disposition / Corrective Action

USE AS IS

Closed ref SPIRE-RAL-MoM-002462v1 NRB

Document or Drawing Affected (Title, Number & Issue)

Estimated COST OF NCR (cost of : correction, Materials, Resource, and delay to Project etc.)

NOD 01 005D	PA Manager (Or Deputy)	Project Manager (Or Deputy)	Date
NCR CLOSED (Signatures Required)	Digitally signed by Eric Clark Date: 2005.07.18 11:18:22 +01'00'	Closed ref SPIRE-RAL-MoM- 002462v1 NRB	

Waiver List

- 1) HR-SP-JPL-RFW-005v1 (Sine Vibration Omission)
- 2) HR-SP-JPL-RFW-006 (Vibration Test Levels)
- 3) HR-SP-JPL-RFW-022 (BDA Vibration Test Temperature)



REQUEST FOR WAIVER / DEVIATION (RFW/RFD)

PRODUCT ASSURANCE
Space Science and Technology
Department

RFW/RFD Number: HR-SP-JPL-RFW-005v1

Spacecraft / Project	Herschel	Originator's Name	Kalyani Sukhatme	
System / Experiment /	SPIRE	Signature / Date		
Model				
Sub-System	detectors	Request Type	Waiver (RFW)	Deviation
		(Highlight applicable request)		(RFD)
Assembly		Organisation	Jet Propulsion Laboratory	
Sub-Assembly		Ref. Doc. / Drwg No.	SPIRE-JPL-PRJ-000456	
Item		References		
Serial No.		References		

RFW/RFD Title	BDA and JFET module sine test deletion
---------------	--

End Items(s) Affected (Hardware, Software)						
Name	CI-Nu	CI-Number		Model(s)		
Bolometric Detector Assemblies			CC	M, PFM, FS		
JFET Modules			CC	M, PFM, FS		
Requi	irement / Interface Docu	ments Affecte	ed			
Specification/Drawing Title	Number	Issue	Date	App. Paragraph		
BDA-SSSD (SPIRE-JPL-PRJ-		3.2	Jan 7,	BDA-DES-10, JFET-DES-		
000456)			2003	07		
,						
Description of Deviation / Discrepancy / Non-Conformance						

High Level Sine- Vibe Test is not performed on these units

Other Items or Requirements (Potentially) Affected

Need for RFW/RFD and Rationale for Acceptance

The hardware has to be qualified under a cold vibration test and is installed in the cold vibration facility for the purpose of the test. The high level sine vibration test configuration will put the hardware and the personnel at risk since the cold vibration facility is not structurally capable of withstanding the high levels. Obtaining additional resources (cost and schedule) for developing a new set-up is not feasible at this time.

Up issue RFW to 5v1 with this note added

There is no Requirement to do a high level sine test on previously Qualified units, Only Random Acceptance level test are required.

	Approved	Rejected	Name	Date
Engineering:	REF SPIRE – RAL-MOM-		Digitally signed by Eric Clark Date: 2004.12.22 08:57:49 Z	20 December 04
Product Assurance:	002250			20 December 04
CCB-Chairman:				
Principle Investigator				
Product Assurance:				
Co-Investigator				
Prime Contractor				
ESA Project Office				



REQUEST FOR WAIVER / DEVIATION (RFW/RFD)

PRODUCT ASSURANCE Space Science and Technology Department

RFW/RFD Number:

HR-SP-JPL-RFW-006

Spacecraft / Project	Herschel	Originator's Name	Martin Herman	
System / Experiment / Model	SPIRE/ AII	Signature / Date		
Sub-System	Detector	Request Type (Highlight applicable request)	Waiver (RFW)	Deviation (RFD)
Assembly	BDA	Organisation	Jet Propulsior	n Laboratory
Sub-Assembly		Ref. Doc. / Drwg No.		
Item		References		
Serial No.		References		

RFW/RFD Title Random vibration test levels not the same.	
--	--

End Items(s) Affected (Hardware, Software)						
Name CI-Number Model(s)						
BDA	QM			M, CQM, PFM, FS		
R	equirem	ent / Interface Docu	ments Affecte	ed		
Specification/Drawing Title	Specification/Drawing Title Number			Date	App. Paragraph	
BDA-SSSD	BDA-DES-10		3.2	Jan 7, 03		

Description of Deviation / Discrepancy / Non-Conformance

- 1) Random Vibration Test Levels are not the same as given in the BDA-SSSD (Issue 3.2), BDA-Des-10
- 2) There are five different flavours of the BDA. The qualification vibration test is done on only one QM unit which is of the PLW type.

Other Items or Requirements (Potentially) Affected

Need for RFW/RFD and Rationale for Acceptance

- 1. The random vibration test levels are as specified by Berend Winter (MSSL) in an email on May 2, 2003, which superseded the BDA-SSSD
- 2. The qualification test program in using the PLW flavour as the only Qual Model, is given in Interoffice Memorandum, Oct. 3, 2003, Henry Abakians, Subject: SPIRE BDA Random Vibration Test Program [IOM 5132-03-167]

	Approved	Rejected	Name	Date
Engineering:	REF SPIRE – RAL-MOM-		Digitally signed by Eric Clark	20 December 04
Product Assurance:	002250		Date: 2004.12.21 09:09:53 Z	20 December 04
CCB-Chairman:				
Principle Investigator				
Product Assurance:				
Co-Investigator				
Prime Contractor				
ESA Project Office				



INTEROFFICE MEMORANDUM

5132-03-167 October 3, 2003

Project: Herschel/Planck

TO:

Martin Herman

FROM:

Henry Abakians

SUBJECT:

SPIRE BDA random vibration test program

This IOM outlines the random vibration test program for Herschel/Planck project's SPIRE element. Due to schedule and cost constrains, our proposed test program does not strictly conform to JPL's standard random vibration program; however, it maintains a medium to low risk posture.

The recommendations will concentrate on the vibration environment since that is the source of highest stresses on the unit. The SPIRE qualification program also includes thermal cycling and accelerated aging, but it will not be addressed in this IOM.

The SPIRE element of the JPL Herschel/Planck project has several Bolometer Detector Assemblies (BDA). These BDAs are identical in their outer housing, and primarily vary in a thermally isolated suspension which contains the bolometer array and the feedhorn (the suspension is held on to the housing via two rows of braided Kevlar strings). There are five flavors to these suspensions: PSW, PMW, PLW, SSW, SLW (P: photometer, S: spectrometer, LW: long wave, MW: medium wave, SW: short wave). The suspensions also vary in their mass and center of gravity (PLW the heaviest, SSW the lightest).

In a traditional JPL Qual/FA test program, a Qual unit for each BDA flavor would be tested (3-axis, 2 min. per axis), and all subsequent flight units would be FA tested (3-axis test, FA levels, 1 min. per axis). In a traditional Protoflight program, all flight units would be protoflight tested (3-axis test, Qual levels, 1 min. per axis).

The SPIRE element has evolved into a Qual/FA/Protoflight test program. We have built and successfully tested a qual unit (CQM, PLW). It was random vibrated at Qual levels and durations (2 minutes) in three axes. This unit successfully passed the random vibration test, and remained within the specifications (performance or otherwise). Our proposed test program for all subsequent BDAs is as follows:

BDA type	test program	random vibe axis	duration
PSW	PF	x	2 min
PMW	PF	x	2 min
PLW	Qual/PF	3 axis Qual	2min/axis
		PF-x axis only	1 min
SSW	PF	x	2 min
SLW	PF	x	2 min

The test program deviates from a standard JPL program; however, we believe it maintains an acceptable risk posture for the following reasons:

- 1-The vibration in the z-direction is substantially more benign than x and y. Therefore, we can eliminate the random vibration test in the z-direction for all flight units (this is based on the CQM test results).
- 2-There is sufficient cross-talk between x and y (based on CQM test results). Therefore, we can eliminate the y direction shake and perform the test in the x-direction for an additional 1 minute (x is the more severe direction; moreover, since we are not concerned with low cycle fatigue failure—substantiated by the CQM test—we feel justified in extending the x-direction test duration to 2 minutes, thus indirectly testing for y-direction).

While it is clearly more desirable to test in y-direction directly, eliminating this test is primarily driven by cost and schedule constraints: all our test are performed at or below 100K, thus a one axis vibration will require a minimum of 3 work days; however, extending a 1 minute test to 2 minutes will not impact schedule, cost, or the safety of the hardware.

- 3-We have tested the heaviest assembly (PLW) for our qualification program. This ensures that our design is validated for the highest possible stresses in the Kevlar string.
- 4- Force transducers will be utilized in 3 directions. Their responses will be correlated with the CQM results providing additional assurance on hardware workmanship, reliability and robustness.

Concurrence:

John Forgrave

Environmental requirements Engineering, Group Supervisor

Concurrence:

Paul MacNeal, Dynamics Engineer

Herschel/Planck

Concurrence:

Fim Larson Mission Assurance Manager

Herschel/Planck

Distribution:
Bill McAlpine
Margaret Frerking
Michael O'Connell
Gary Parks
Kalyani Sukhatme
Mark Weilert



REQUEST FOR WAIVER / DEVIATION (RFW/RFD)

PRODUCT ASSURANCE Space Science and Technology Department

RFW/RFD Number:

HR-SP-JPL-RFW-022

Spacecraft / Project	Herschel	Originator's Name	Mark Weilert	
System / Experiment / Model	SPIRE / CQM, PFM, FS	Signature / Date		22 July 2005
Sub-System	Detectors	Request Type (Highlight applicable request)	Waiver (RFW)	Deviation (RFD)
Assembly		Organisation	Jet Propulsion	Laboratory
Sub-Assembly	BDA	Ref. Doc. / Drwg No.	SPIRE-JPL-PRJ-000456; Herschel-Planck ERD, JPL D-19155 Rev B.	
Item	10209800 -1 thru -5	Deference		
Serial No.	6,8,9 & 12 thru 19	References		

RFW/RFD Title	BDA vibration test temperature.
,	227 this attention took temperature.

End Items(s) Affected (Hardware, Software)					
Name	C	-Number		Model(s)	
Bolometric Detector Assemblies (all typ	es)		CQ	M, PFM, FS	
R	equirement / Interface D	ocuments Affect	ed		
Specification/Drawing Title	Number	Issue	Date	App. Paragraph	
BDA-SSSD (SPIRE-JPL-PRJ- 000456)		3.2	Jan 7, 2003	BDA-DES-10	

Description of Deviation / Discrepancy / Non-Conformance

BDA Cold vibration tests were performed with the BDA temperature at T < 100K instead of T < 90K as required in the SSSD sec. 3.4. Note that the Herschel-Planck Environmental Requirements Document (ERD), JPL D-19155 Rev B lists 100K for the required test temperature.

Other Items or Requirements (Potentially) Affected

Need for RFW/RFD and Rationale for Acceptance

The hardware is tested in the cold vibration facility which contains a liquid nitrogen cooled cold plate which typically reaches 81K minimum. The BDA temperature is measured on the Kevlar-isolated portion of the BDA, which cools down extremely slowly below about 120K. The 100K maximum test temperature used is the lowest that can be practically obtained without waiting an excessive amount of time during the test. The difference in vibration behaviour between 100K and 90K will be minimal, so this change does not affect the validity of the test results. Also note that the temperature of the mounting flange and other non-suspended parts of the BDA are likely less than 90K since they have much better thermal contact to the cold plate.

	Name	Approved (Sign & Date)	Rejected (Sign & Date)
Engineering:	Eric Sawyer	Digitally signed by Eric Sawyer Date: 2005.07.22 12:17:10 40100'	
Product Assurance:	Eric Clark	Digitally signed by Eric Clark Date: 2005.07.22 09:04:15 +01'00'	
CCB-Chairman:			
Principle Investigator			
Product Assurance:			
Co-Investigator			
Prime Contractor			
ESA Project Office			

Open Problem / Failure Report (PFR) List

Open PFR's on This Hardware (FS SLW BDA 10209800-4 S/N 015): NONE

Open PFR's on Similar Hardware:

NONE

SPIRE Bolometer Detector Assembly Handling Document

Prepared by Mark Weilert

20 August, 2003 revised 20 Nov. 03 revised 9 August, 05

WARNINGS

BDA is Contamination Sensitive: Open red shipping container only in an ISO 14644-1 class 7 (FED-STD-209 Class 10000) or cleaner cleanroom. Handle BDA with approved nitrile or polyurethane ESD safe cleanroom gloves only. (See end of document for notes and JPL approved products).

BDA is ESD Sensitive: Handle with approved² wrist straps, ESD-safe gloves and ESD smocks at an approved ESD protected workstation³. All personnel within 1 meter of unprotected ESD sensitive hardware shall be certified for ESD awareness⁴. Note that no connector savers or other connector protection are shipped with the BDA, per the business agreement. Refer to attached electrical handling document for other important safety precautions. Follow all instructions for the use of wrist straps, ESD smocks, static protected work areas, ionizers, packing/unpacking and cable handling per JPL standard D-1348, rev. F (This document is available through the public domain by the following URL: http://standards.jpl.nasa.gov/contractor/docs/d1348f.html.)

ESD - Ionizer: Prior to mate or demate of any connector, turn on an ionizer approved⁵ for ESD sensitive components in clean room environment at least 5 minutes in advance and place/hold both sides of the connections in front of the ionized air stream for a minimum of 10 seconds before mating/demating operation. Position the ionizer near the hardware within the required distance per manufacturer's manual. Different makes and models of ionizers have different positioning requirements. During the mating/demating operations, it is necessary to follow the requirements for handling ESD sensitive hardware.

ESD - Connection to GSE: It is essential to ensure that all signal and bias lines of the GSE are grounded prior to mating the BDA hardware to the GSE. A

safe-to-mate check *must* be performed prior to connecting the BDA to the GSE. No excessive voltages and currents on all signal and bias lines shall be observed while the hardware is connected.

QA Oversight: Quality Assurance personnel should witness all handling, electrical testing, operation and integration of BDA flight hardware. At a minimum, a "two person" rule should be invoked at all times, where oversight by an independent party is provided to ensure hardware safety during handling, test and integration operations.

BDA is Fragile: Do not drop or otherwise shock. Take care to avoid applying unnecessary force to the Kevlar suspended portion of the BDA. In particular, do not torque the thermal strap interface fasteners to greater than 320 N*mm. The BDA is preferably held/supported either by its square mounting flange, or by the light-seal can which holds the electrical connectors. Note that the red shipping container provides only minimal shock isolation, and should be treated as equally fragile while the BDA is inside. Because the Kevlar tension is higher at room temperature than cold, DO NOT SHAKE TEST AT ANY TEMPERATURE ABOVE 100K (except for low-level survey shakes, 0.25g typical). A full level shake at room temperature risks catastrophic failure. Avoid touching Kevlar braid with anything, it is sensitive to abrasion or cutting by seemingly smooth objects.

BDA is Humidity Sensitive: The Kevlar tension increases with moisture absorption. Keep in a dry environment when possible during storage or while not being handled. While being actively handled, hardware should be placed in a humidity-controlled cleanroom. Maintain humidity level at 35%-50% RH typical, for ESD safety.

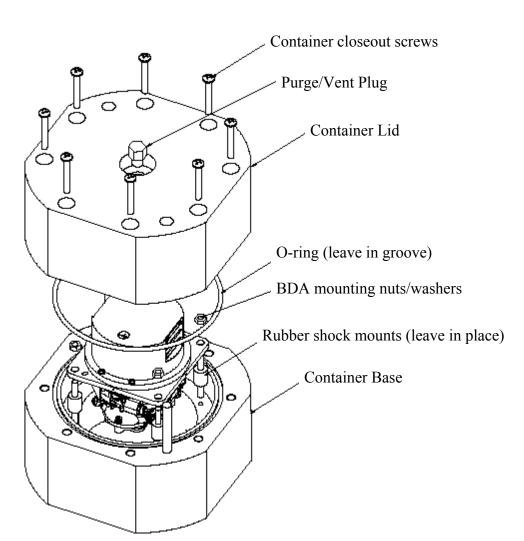
BDA is Temperature Sensitive: The Kevlar tension and creep increases at high temperatures, **DO NOT BAKE OUT AT ABOVE 80°C.**

Unpacking Procedure:

The BDA is shipped in a multi-layer container, a custom shipping container (red) inside a case inside a case. The case should be opened only in a reasonably clean area in order to protect the red shipping container, which should only be opened in a class 10000 or better clean room at an ESD-safe workstation. The red shipping container has three shockmonitors attached to the top, labeled 10g, 20g and 50g. The monitors have steel balls and springs which are contained between plastic rails if the unit has not seen the marked shock level. If the monitors have experienced their specified shock, some of the balls will be loose in the bottom. Please note the state of the three shock monitors and report the result to JPL. These monitors may need to be removed from the top of the red shipping container before it is opened, since they probably obstruct access to the vent plug. They are attached with a double-stick tape adhesive and may be pulled off by applying force to the white base. (Avoid just pulling on the clear case, as this will likely open up the monitor and spill the contents.) **NOTE: The cases holding the red shipping container must be returned to JPL for use in future shipments.**

Opening the Red Shipping Container:

An exploded view of the container is shown below. The top is the side with the vent plug in the center. Make sure the area around the plug is clean, then remove the plug to equalize the pressure. The 8 closeout screws are next loosened alternately (with a 1/8"



hex key) to relieve pressure on the o-ring seal, and then backed off completely to disengage the screws from the base. The container lid is then lifted straight up to open the container. Two guide pins prevent significant sideways motion of the lid until it is high enough to clear the BDA. The BDA is removed from the shipping container base by removing the mounting nuts and washers from the rubber shock mounts and lifting the BDA straight up.

For re-installation of the BDA into the red container, note that the light can must be up, as shown, to prevent the container lid from hitting the BDA. Also, the epoxy terminations of the Kevlar braids should be oriented towards the cutouts in the container base.

NOTES:

¹ JPL approved ESD safe cleanroom gloves are:

Nitrile

Ansell-Edmont Nitrilite ht Ansell-Edmont Nitrilite Silky ht Ansell-Edmont Silky Ultra-Clean Safeskin Critical (white) ht

Polyurethane:

Wilshire Technology DuraCLEAN

http://www.ansellpro.com/ce/products3.asp?pid=87 http://www.ansellpro.com/ce/products3.asp?pid=149 http://www.ansellpro.com/ce/products3.asp?pid=150

http://www.safeskin.com/crit nt glv.asp

call in US, 323-259-6469 for ordering information

Speidel Twist-o-Flex TM brand metal expansion bracelet wrist straps 3M model 4600 adjustable molded thermoplastic wrist straps

² JPL approved wrist straps are:

³ All work areas shall be certified and operated in compliance with the requirements of the following subsections sections of JPL-STD D-1348 rev. F section 2.3: subsections: 6, 8-11, 14-19, 21, 23-27, 29-36, 38-43 and 45.

⁴ All personnel shall be trained and certified to the requirements of section 2.3.3 of JPL STD_D-1348 rev. F.

⁵ The ionizer performance shall be verified to comply with the requirements of JPL-STD-D-1348 rev. F, Table 1 for devices with human body model ESD sensitivity less than 50 volts. The ionizer shall discharge from ± 1000 volts to less than ± 20 volts in less than 20 seconds and have a float potential of less than ± 20 volts.

SPIRE

Subject: Spectrometer BDA Filter Replacement Procedure Prepared by: Mark Weilert	
Document No: D-31978	
Issue: 1	Date: 4-May-05
Checked by:	Date:
Approved by:	Date:

SPIRE

Project Document

Page: Page 2 of 9 Ref: D-31978

Spectrometer BDA Filter Replacement Procedure

Issue: 1

Date: 3 May 05

Distribution

RAL SPIRE: Doug Griffin, Bruce Swinyard, Eric Sawyer and Eric Clark

JPL SPIRE: Jamie Bock, Jim Newell, and Martin Herman

SPIREProject Document
Page: Page 3 of 9
Ref: D-31978

Spectrometer BDA Filter Replacement Procedure Issue: 1

Date: 3 May 05

Change Record

Issue1 (initial issue)

Date
4-May-05

SPIRE

Project Document

Page: Page 4 of 9 Ref: D-31978

Spectrometer BDA Filter Replacement Procedure

Issue: 1 Date: 3 May 05

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Figure 2 (Pictures of Typical Staking)	page 9

Attachments

10209800-B.pdf (BDA top-level assembly Drawing, as included in HRCR package)

SPIRE

Project Document

Page: Page 5 of 9 Ref: D-31978

Spectrometer BDA Filter Replacement Procedure

Date: 3 May 05

Issue: 1

1 Introduction

The removal and replacement of the BDA filter is in principle a simple procedure, consisting of removing the screws, removing the filter, replacing the filter, replacing the screws, torquing the screws, and staking the screws. This procedure applies to both SSW and SLW BDA's, part #'s 10209800-5 and 10209800-4, respectively.

The difficulty is due to the drive for the screws, which is an offset-cruciform drive ("Torq-set" drive, per NA0025). The driver we use is a commercially available part, but the filter screws use a very small size and we tried a couple of different drives before finding a good one.

Also, since the filter removal and re-installation applies significant force to the suspended portion of the BDA, if the unit were at JPL we would perform metrology measurements before and after the process to see if the suspended portion of the BDA had shifted. This worry can be reduced somewhat by trying to hold the BDA by the top ring (to which the filter attaches) during the screw removal and torquing.

Detailed procedures follow below. Item numbers refer to the parts list in drawing 10209800, which is included in the HRCR package and attached. See sheet 2 of the drawing for the filter installation detail, which is reproduced in figure 1 below.

2 Warnings

The BDA is shock, ESD, and contamination sensitive. Handle in accordance with the general handling requirements listed in the SPIRE BDA Handling Document, JPL D-26653, included in the HRCR package.

This procedure could cause a shift in the location of the suspended portion of the BDA. Checking the position of the suspended portion with respect to the mounting flange before and after is recommended.

All procedures should be performed with QA witness, and a calibrated torque wrench should be used.

3 Filter Removal

3.1 Remove the 6x item 48 screws, 2x item 19 nuts and 4x item 21 Belleville washers holding filter to the top ring of the BDA.

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Issue: 1

Spectrometer BDA Filter Replacement Procedure

Date: 3 May 05

The two end screws are held into nuts which must be held to loosen the screws. The loosening torque can be applied to the screw or the nut as desired.

Note that the screws are staked with epoxy. This epoxy will break away when the screws are loosened. Take care to contain the epoxy bits so they do not fall into the BDA assembly.

- 3.2 Retain all screws, nuts, and washers for later re-installation.
- 3.3 Lift the filter off the top ring.

4 Filter Installation

- 4.1 Place new filter into position on the BDA top ring. Note that the filter will only go on in one orientation due to the clearance slot for the thermal strap.
- 4.2 Attach the filter using the 6x item 48 NA0068A016012 screws removed during disassembly. Use an item 19, nut, and two item 21 Belleville spring washers in series (<>) at each of the two thru-hole locations. Finger tighten screws in an alternating pattern, such as that suggested in figure 1 below.

Note that residual staking epoxy must be cleaned from the parts before re-use. This can easily be accomplished by heating the screws, washers or nuts slightly with a heat gun, which softens the epoxy enough for removal with a sharp tool. **Do not use a heat gun on the assembled unit.**

ALTERNATE OPTION:

If you have sufficient clearance above the top of the BDA in the next level of assembly, it is acceptable to use NA0069-016012 socket-head cap screws for the filter installation instead of the NA0068 screws which were originally installed. This will avoid the problems with the offset-cruciform drive, but will leave the heads of the screws extending above the top of the filter. Make sure that the screws are not longer than 12mm (measuring from under the head), because the clearance from the end of the screw to the bottom of the threaded holes is a bit tight. The location of the washers and nuts, as well as the torquing and staking in the following steps is unchanged.

4.3 Torque all item 48 screws to 200N*mm in the same pattern as above.

The end screws must have the nuts held with a small closed-ended wrench during torquing. Torque is applied to the screws in all cases.

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Spectrometer BDA Filter Replacement Procedure Issue: 1

Date: 3 May 05

4.4 Stake the six filter screws using item 25, 2216A/B epoxy.

The four central screws are staked at the heads, while the end screws are staked at the nut such that epoxy connects the screw to the nut. See figure 2 for pictures of typical staking.

4.5 Cure epoxy for 24 hours minimum at room temperature.

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Spectrometer BDA Filter Replacement Procedure

Issue: 1 Date: 3 May 05

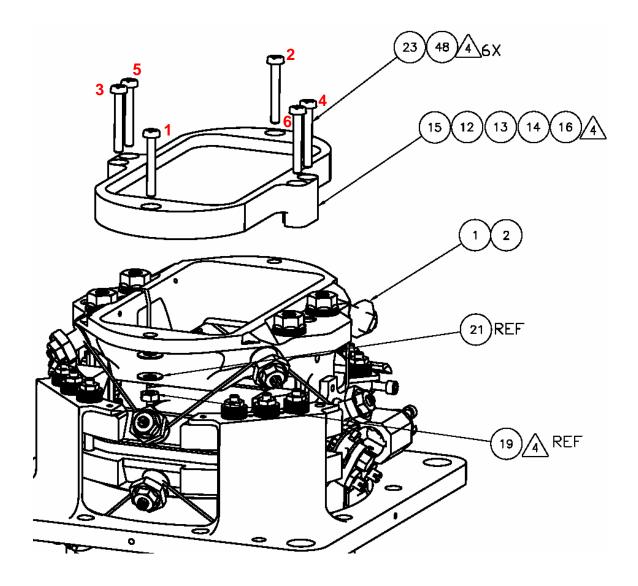


Figure 1

Filter Detail from Drawing 10209800 rev B, showing suggested screw tightening pattern in red. See attached full drawing for part number references.

Project Document

Spectrometer BDA Filter Replacement Procedure

Ref: D-31978 Issue: 1

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Date: 3 May 05



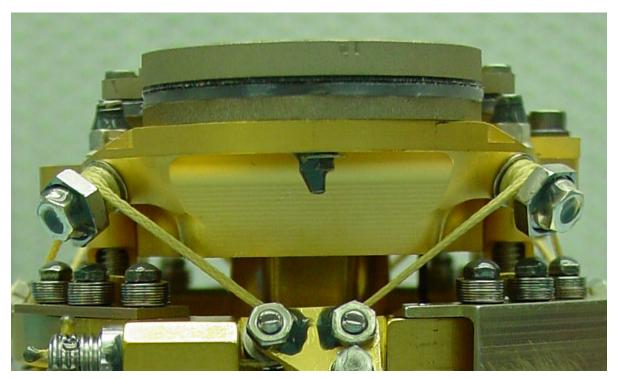


Figure 2

Typical Fastener Staking.

Subject: BDA Electronic Handling Procedure, SPIRE	S/LW-FS
Prepared by: Anthony Turner	
Document No:	
Issue: Draft	Date: 5/24/05
Checked by:	Date:
Approved by:	Date:

Project Document

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Electronic Handling Procedure S/LW-FS

Issue: Date:

Distribution

SPIRE Project Document Page: Page 3 of 9
Ref:
Electronic Handling Procedure S/LW-FS
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Handling.....

Signal Requirements.....

Device Isolation.....

Room Temperature Detector Values Check.......

Load Resistor-Detector Continuity Check.....

2.

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Electronic Handling Procedure S/LW-FS Issue:

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Glossary

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Electronic Handling Procedure S/LW-FS

1. Introduction:

This document provides the Electronic Handling Procedure for the Flight Spare-Spectrometer Long Wavelength Bolometer Detector Array.

2. Handling:

- 1. **BDA is Contamination Sensitive**: Handle BDA with Gloves only in a FED-STD-209 Class 10000 clean room (ISO 14644-1 class 7) or better.
- 2. **BDA is ESD Sensitive**: Electronic parts included in the S/LW-FS science instrument are subject to electro-static discharge failures. Please handle with appropriate ESD hardware handling procedures. Handle with grounding straps, ESD-safe gloves, ESD smocks at an ESD-safer workstation.

3. Signal Requirements:

The interface circuit for the BDA contains a series of resistive networks as depicted in figure 1. Two high resistive load resistors ($\sim 6-14 \text{ M}\Omega$) are coupled to a NTD Ge thermistor (R bolo) through a lithographed metalization circuit and provide the bias circuitry for the device. The maximum DC input voltage for the bias lines V+ and V- lines is +/- 1 V, and the maximum AC input voltage is 100mV rms.

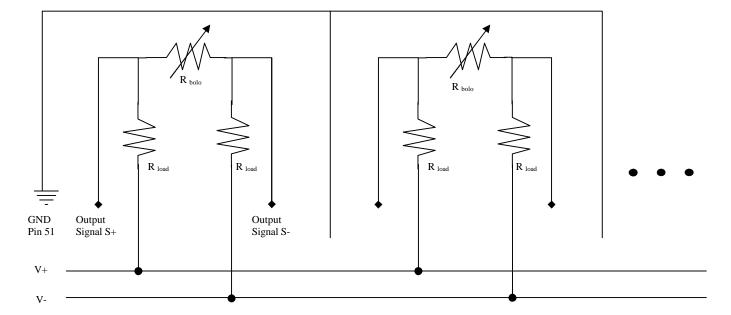


Figure 1: Interface circuit of the Bolometer Detector Array

Project Document

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Ref: Issue:

Electronic Handling Procedure S/LW-FS

Date:

DC Voltage-Current Limits for Room Temperature Detector Values Check:

Signal	Pin	Nominal Value	Max Value
V+	25	+50mV	+1 V
V-	50	-50mV	-1 V
I+,I-	25,50	10μΑ	25μΑ

DC Voltage-Current Limits for room temperature Load Resistor-Detector Continuity Check:

Signal	Pin	Nominal Value	Max Value
V+	25	+50mV	+1 V
V-	50	-50mV	-1 V
I+, I-	25,50	<0.5μΑ	1μA

4. Device Isolation Check:

The 300mK stage Kevlar suspended portion of the detector chassis is grounded directly to the electronic ground on pin 51 of the nanonics 51-pin connectors on each side. A resistance of less than 200Ω can be checked from the thermal strap of the 300mK stage to electrical ground pin 51. The 2K stage is electrically isolated from the electronic ground via the Kevlar supports. Measuring from pin 51 to any metal section of the 2K stage will yield an open circuit.

5. Room Temperature Detector Values Check

The final measured DC resistance value for each of the bolometer detector at room temperature is shown in the Table 1. The measurements bypass the load resistors in the circuit measuring directly through the output signal pins on the two nanonics 51-pin connectors. All measurements were performed with a Fluke 87 True RMS multi-meter set in the $4k\Omega$ range. All measurements are in $k\Omega$ unless designated otherwise. Channels that are out of range are re-measured using the $40M\Omega$ range to determine their value. The failure mode of any particular channel is also designated in table 1. The designation for the failure modes are open- Channel open at 300mK, short-channel shorted at 300mK, and float- channel floating at 300mK.

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Ref:

Electronic Handling Procedure S/LW-FS

Issue: Date:

Table 1: S/LW-FS Room Temperature DC Detector Measurements J05 connector

Connector	G: 1	Nanonics	Nanonics	Detector	Resistance	Failure
Label	Signal	Pin From	Pin To	Label	(kohms)	Mode
J05	1	1	26	R1	4.52M	
	2	2	27	T1	1.583	
	3	3	28	C1	1.944	
	4	4	29	DK1	110.4k	open
	5	5	30	B1	1.943	
	6	6	31	D1	1.863	
	7	7	32	E1	1.789	
	8	8	33	A 1	1.893	
	9	9	34	C2	1.81	
	10	10	35	D2	1.769	
	11	11	36	B2	1.784	
	12	12	37	E2	1.691	
	13	13	38	A2	1.813	
	14	14	39	C3	1.813	
	15	15	40	D3	1.817	
	16	16	41	В3	1.898	
	17	17	42	E3	1.841	
	18	18	43	C4	1.946	
	19	19	44	DK2	1.927	
	20	20	45	D4	1.975	
	21	21	46	C5	2.018	
	22	22	47	B4	2.083	
	23	23	48	А3	2.135	
	24	24	49	T2	1.673	
	V+ to V-	25	50		0.747M	
	V-to gnd	50	51		>30M	
	V+ to gnd	25	51	51 >:		
	Chassis to gnd				68.0 ohms	

note: DK1 has an almost open circuit on the web lead of the detector. Deemed an open circuit.

Page: Page 9 of 9

Ref: Issue:

Electronic Handling Procedure S/LW-FS

Date:

6. Load Resistor-Detector Continuity Check

A DC continuity check of the load resistors in series with the bolometer detectors will complete the electrical checkout at room temperature. The test can be performed with a Fluke 87 True RMS multi-meter set on the 40M Ω scale. The data set measures from V+ to output signal S+ and V- to output signal S- for each channel. The nominal value read for the live bolometer channels (room temp detector DC resistance ~ 1.5-2.0 k Ω) should read approximately 5-8M Ω . Channels with open bolometer channels will give values 10M Ω or higher. The Data sets for the S/LW-FS for the final test through the entire circuit are shown in Table 3.

Table 3: S/LW-FS Load Resistor- Detector DC Continuity Check J05 connector

			Resistance	Resistance
Connector	Signal	Detector Label	V+ to S+	V- to S-
Label	Signai	Detector Laber		
J05	1	R1	(Mohms) 5.68	(Mohms) 5.68
303	2	T1	4.67	4.68
	3		4.68	4.68
		C1		
	4	DK1	4.64	4.72
	5	B 1	4.66	4.68
	6	D1	4.64	4.68
	7	E1	4.63	4.64
	8	A1	4.6	4.6
	9	C2	4.6	4.6
	10	D2	4.6	4.61
	11	B 2	4.6	4.6
	12	E2	4.6	4.6
	13	A2	4.6	4.6
	14	C3	4.6	4.6
	15	D3	4.6	4.6
	16	В3	4.56	4.58
	17	E3	4.6	4.58
	18	C4	4.52	4.56
	19	DK2	4.56	4.56
	20	D4	4.6	4.56
	21	C5	4.6	4.52
	22	B 4	4.62	4.52
	23	A3	4.55	4.52
	24	T2	4.52	4.51

EIDP Coverpage For SLW BDA (SN015)

Unit Identfication					
Name	SL	W BDA			
Part #	10209800-4				
S/N	#015				

Environmemtal Testing							
			Duration				
	Axes		or Number of				
	Tested	Temperature	Cycles	Pass/Fail	Requirement	Source	Waiver #
							HR-SP-JPL-
			2 min per		, ,	SSSD	RFW-006, HR-SP-JPL-
Random Vibration Test	X	100 K	axis	Р	1 min per axis	Sec # 3.4	RFW-022
						SSSD	HR-SP-JPL-
High Level Sine Vibe Test	None	NA	NA	NA	X, Y, Z at 90 K	Sec # 3.4	RFW-005v1
					None (other than		
					as part of the		
					assembly		
Bakeout	NA	NA	NA	NA	procedure)	D-20549	
					1 thermal cycle		
		RoomT to			roomT to 77 K		
Thermal Cycles	NA	~ 6 K	2	Р	(max 5)	D-20549	

Other Testing	Frequ	iency [Hz]					
	Pre-full	Post-full			Minimum		
	level	level			Performance	Source	Waiver #
Lowest Resonant					> 200 Hz	SSSD	
Frequency	268 Hz	268 Hz			(Goal: >250 Hz)	Sec # 3.1.3	NA
Metrology Measurements v	vere perfo	rmed before a	and after the Vi	bration Tes	st and the Therma	l Cycles	
	Motion			Meets	Performance		
	in X/Y	Motion in Z		Goal?	Goal	Source	Waiver #
Maximum motion due to					125 μm in X/Y	SSSD	
Random Vibration Test	23 μm	32 μm		Υ	and 500 μm in Z	Sec # 3.1.1	NA
Maximum motion due to					125 μm in X/Y	SSSD	
the 1st thermal cycle	13 μm	10 μm		Υ	and 500 μm in Z	Sec # 3.1.1	NA
Maximum motion due to					125 μm in X/Y	SSSD	
the 2nd thermal cycle	11 μm	8 μm		Υ	and 500 μm in Z	Sec # 3.1.1	NA
Cumulative Maximum					125 μm in X/Y	SSSD	
motion	48 μm	67 μm		Y	and 500 μm in Z	Sec # 3.1.1	NA
Cold Continuity Measurem	ents were	made during	each of the the	ermal cycle	<u> </u> S		
					Requirement	Source	Waiver #
Cold Continuity Test					·		
(1st Thermal Cycle)				Р	None	NA	NA
Cold Continuity Test							
(2nd Thermal Cycle)				Р	None	NA	NA



ENVIRONMENTAL TEST AUTHORIZATION AND SUMMARY (ETAS)

AUTHORIZATION SECTION							
PROJECT			LOG NO.				
Herschel SITO YSTEM/ASSEMBLY TITLE			HS038	DATE ISSUED			
SLW BDA SN015				03/07/2005			
REFERENCE DESIGNATION NUMBER	PART NO. (IF MULTIPLE, AT 10209800	TACH LIST)	REV.	SERIAL NO.			
HARDWARE TYPE	T SUOUT ODADS	Потигр	PRE-ENVIRONMENTAL INSPECTION	ON REPORT NUMBER (ATTACH IR)			
☐ EM QUAL ☐ FLIGHT ☐ WIRING HARNESS	FLIGHT SPARE	OTHER PART NO.	REV.	SERIAL NO.			
EM QUAL FLIGHT	Пем Пse	Tractico.	114				
TEST DESCRIPTION (CHECK ALL APPLICABLE)			TYPE OF TEST				
SINE VIBRATION PYROSHOCK	ACOUSTIC EMC	OTHER	QUALIFICATION	☐ FLIGHT ACCEPTANCE			
RANDOM VIBRATION THERMAL VAC.	THERMAL ATMOSPHERE		PROTO FLIGHT	RETEST			
WILL ALL TESTS/LEVES/DURATIONS REQUIRED BY TH							
YES NO (IF NO, ATTACH EX		ENTER PROJ. DOC. NO.	AND REV.				
YES NO (IF NO, ATTACH E)		BRIEF EXPLANATION					
HAVE ALL DESIGN ANALYSES BEEN COMPLETED AND		MPLEMENTED?					
YES NO (IF NO, ATTACH E)		BRIEF EXPLANATION					
IS THE TEST ARTICLE IDENTICAL TO OTHER FLIGHT U							
YES NO (IF NO, ATTACH EX	KCEPTIONS LIST)	BRIEF EXPLANATION					
ARE ALL PFRs AGAINST THIS UNIT CLOSED? YES NO (IF NO, ATTACH E)	(OFRICALOT)	BRIEF EXPLANATION					
YES NO (IF NO, ATTACH E) HAVE ALL WAIVERS AND ECRS BEEN APPROVED AND		BRIEF EXPENDATION					
YES NO (IF NO, ATTACH E)		BRIEF EXPLANATION					
		UTHORIZED BY					
COGNIZANT ENGINEED DA			DATE ENVIRONMENTAL REQU	UIREMENTS ENG DATE			
A/Air 3/8/05	- Monto	1/ 3/	18/2 July 1	for Thewell			
318103	Control of the Contro		(1) (Xamaere Va	unguela 3-8-40			
		ARY SECTION					
TEST AGENCY (IF MULTIPLE, ATTACH SUMMARY AND JPL Building 144	TEST DATES) TEST INITIAT 03/08/05	TION DATE ACCUMUL	ATED OPERATING HOURS PRIOR T	TO FIRST ENVIRONMENTAL TEST			
SERIAL NUMBERS ACTUALLY TESTED	TEST TERMINA	ATION DATE OPERATIN	IG HOURS DURING ENVIRONMENTA	AL EXPOSURE			
	TEST	DESCRIPTION					
VIBRATION ACOUSTIC	PYROSHOCK SHOCK	THERMAL VAC	CUUM TEMPERATURE ATM	MOSPHERE OTHER			
AXES: X Y Z	AXES: X Y	Z PRESSURE: <1E-5					
SINE VIBRATION		290K to 7K	110 05 0101 50				
RANDOM VIBRATION 🖾 🔲 🔲	SHOCKS/AXIS:	NO OF CYCLES: 2	NO OF CYCLES:				
EMC COND. SUSC.	COND. EMIS.	☐ ISOLATION	TEMP. LEVEL (°C) AND ACCUMULA	ATED DURATION (HRS.)			
<u> </u>				h COLD: °c, h			
ESD RAD. SUSC.	RAD. EMIS.	MAGNETICS	HOT:°c,	h COLD:°c,h			
WERE THERE ANY PFRS GENERATED DURING ENVIRO ☐ YES NO (IF NO, ATTACH EX		LIST PFR NOS. / BF	RIEF EXPLANATION				
ARE THE POST ENVIRONMENTAL DAMAGE INSPECTIO		LIST PFR NOS. / BF	RIEF EXPLANATION				
YES NO (IF YES, ATTACH A	COPY OF THE INSPECTION	, i					
REPORTS. IF NO), ATTACH EXPLANATION)		and the second s				
WERE ALL PLANNED TESTS/LEVELS/DURATIONS ACHI		LIST PFR NOS./BF	RIEF EXPLANATION				
YES NO (IF NO, ATTACH EX	 						
TESTS HAVE NOT BEEN SUCCESSFULLY COMPLE COGNIZANT ENGINEER DA	· 1		AT NEED TO BE TAKEN. DATE ENVIRONMENTAL REQU	JIREMENTS ENG. DATE			
OOGNIZANI ENGINEEN	TEO/INIO/IE ING/IZINOTI	THI CONTINUE TO		of turnal to all of			
				ALCEN MOLLISMA SECTION			
ARDWARE HAS SUCCESSFULLY COMPLETED TH	1		REMAINING ACTIONS HAVE BEEN T. DATE ENVIRONMENTAL REQU				
OCGINIZANT ENGINEER DA	1 LOUINION WON / INST	CWMQ/FIFREF REF	DATE LIVERONIVIEW FALL REQU				
8/23/o	۲			11.11 6 33-00			
10 30 00 310710	-			PAGE 1 JPL 2683 R 1/98 FF			



ENVIRONMENTAL TEST AUTHORIZATION AND SUMMARY (ETAS)

		OTHE	R AUTHO	ORIZATI	ON PROVI	SIONS AN	ND EXPLANAT	TIONS	en de la companya de La companya de la co	
s a 1-axis coinside a cold vibra BDA response. A	ation facil	ity. 3 fc	orce tran	sducers	will be m	ounted in	the BDA loa	d path in orde	A unit mounted or to measure the ment from 290K to	o
·)										



ENVIRONMENTAL TES JTHORIZATION AND SUMMARY (ETAS) ENVIRONMENTAL TEST SUMMARY

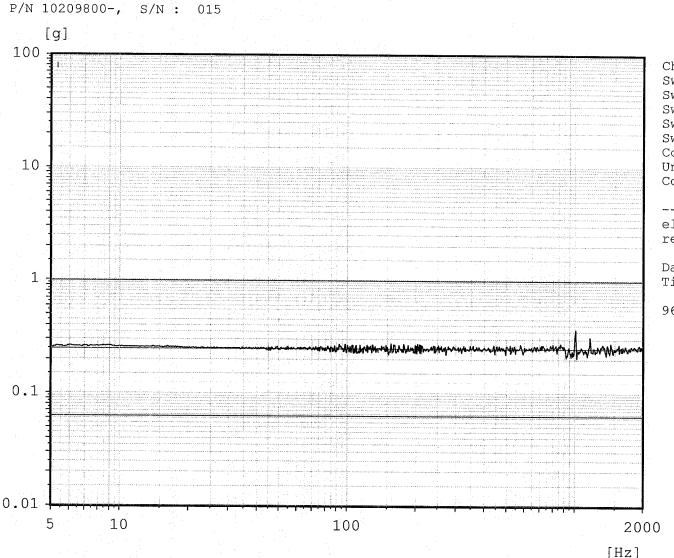
ENVIRONMENTAL LOT COMMANT									
HARDWARE	S/N	ETAS	TEST ENVIRONMENT LEVELS & DURATION	DATE TEST PERFORMED	TEST AGENCY	PASS/ FAII	COMMENTS		
HARDWARE BDA (10209800)	S/N 15	38	LATERAL 2 minute Random Vibe +3dB/octave 20-100Hz 0.06 g^2/Hz 100-138.5 Hz +36dB/octave 138.5-170 Hz 0.7 g^2/Hz 170-200 Hz -48dB/octave 200-220 Hz .1 g^2/Hz 220-300 Hz -9 dB/octave 300-2000 Hz Total Input: 8.0 Grms Spectrum to be notched in order to get 15 g's response RMS LONGITUDINAL (not done on this unit) 2 minute Random Vibe +3dB/octave 20-100Hz 0.08g^2/Hz 100-400Hz -12dB/octave 400-2000Hz Total Input: 6.2 Grms Spectrum to be notched in order to get 15 g's response RMS Each axis1/4 g sine sweep 20-2000 Hz each axisT ~ 100 K 2 Thermal cycles from 290K to 7K	PERFORMED	AGENCY	FAIL	COMMENTS		
							·.		

Sine
101713, Run #3, axis
Spire BDA

Control channel

Before Shake, Cold





Chan.type: X

Sweep type: logarithmic

Sweeps done: 1
Sweeps req.: 1
Sweep direct.: up

Sweep rate: 4.00 Oct/min

Contr.strat.: Maximum

Unit: g

Contr.strat.: Closed loop

-- Testing time --

elapsed: 000:02:09 remaining: 000:00:00

Date: 03-08-05 Time: 12:57:23

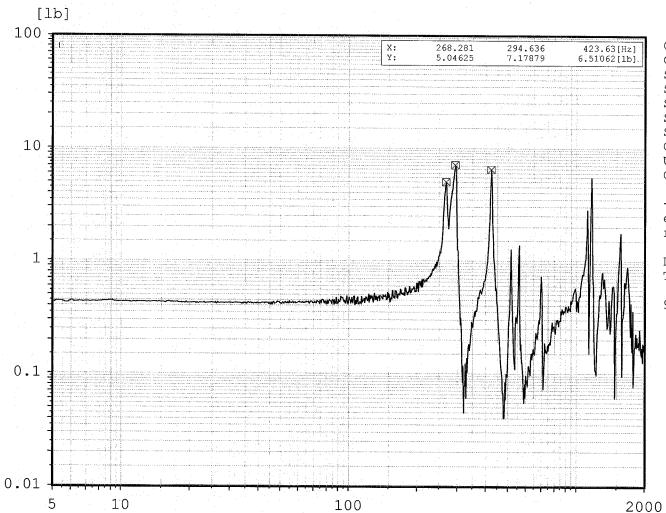
101713, Run # , axis Spire BDA

P/N 10209800-, S/N : 015

Force Sum X

Before Shake, Cold





Chan.no: 6

Chan.type: W RMS Sweep type: logarithmic

Sweeps done: 1
Sweeps req.: 1
Sweep direct.: up

Sweep rate: 4.00 Oct/min

Contr.strat.: Maximum

Unit: lb.

Contr.strat.: Closed loop

-- Testing time --

elapsed: 000:02:09 remaining: 000:00:00

Date: 03-08-05 Time: 12:57:23

964#2/Amp #1/ M+P #2

[Hz]

101713, Run # , axis

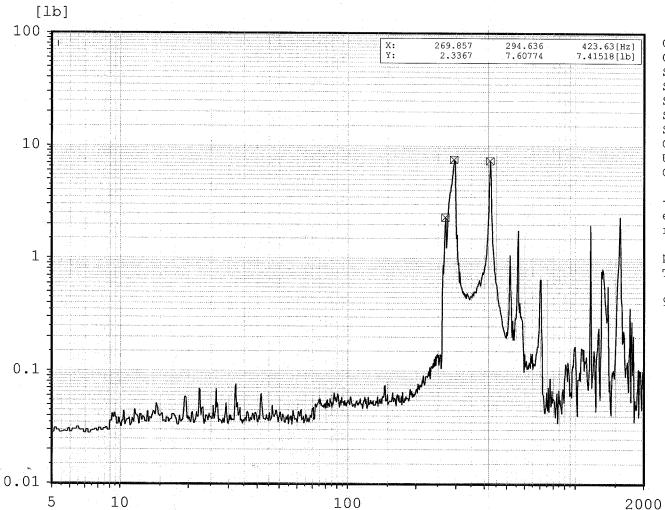
Spire BDA

P/N 10209800-, S/N: 015

Force Sum Y

Before Shake, Cold





Chan.no: 7

Chan.type: W RMS Sweep type: logarithmic

Sweeps done: 1
Sweeps req.: 1
Sweep direct.: up

Sweep rate: 4.00 Oct/min

Contr.strat.: Maximum

Unit: lb

Contr.strat.: Closed loop

-- Testing time --

elapsed: 000:02:09 remaining: 000:00:00

Date: 03-08-05 Time: 12:57:23

964#2/Amp #1/ M+P #2

[Hz]

101713, Run # , axis

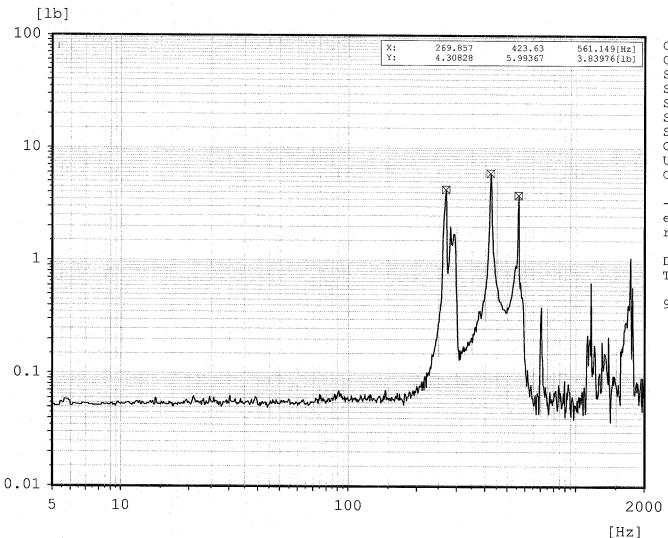
Spire BDA

P/N 10209800-, S/N: 015

Force Sum Z

Before Shake, Cold





Chan.no: 8

Chan.type: W RMS Sweep type: logarithmic

Sweeps done: 1
Sweeps req.: 1
Sweep direct.: up

Sweep rate: 4.00 Oct/min

Contr.strat.: Maximum

Unit: lb

Contr.strat.: Closed loop

-- Testing time --

elapsed: 000:02:09 remaining: 000:00:00

Date: 03-08-05 Time: 12:57:23

Control channel

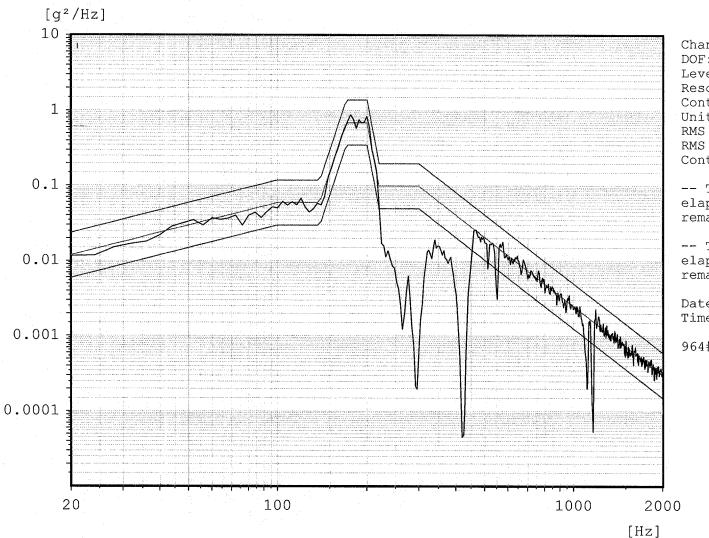
101713, Run # 4, X axis

SPIRE BDA

P/N 10209800-, S/N: 015

0dB, Cold





Chan.type: Χ DOF: 180 Level: 0.0 dB Resolution: 4 Hz Contr.strat.: Maximum g²/Hz Unit: RMS (act.): 7.036 q RMS (req.): 7.945 g Contr.strat.: Closed loop

-- Time on act. level -- elapsed: 000:02:00 remaining: 000:00:00

-- Time total --

elapsed: 000:03:06 remaining: 000:00:00

Date: 03-08-05 Time: 13:16:46

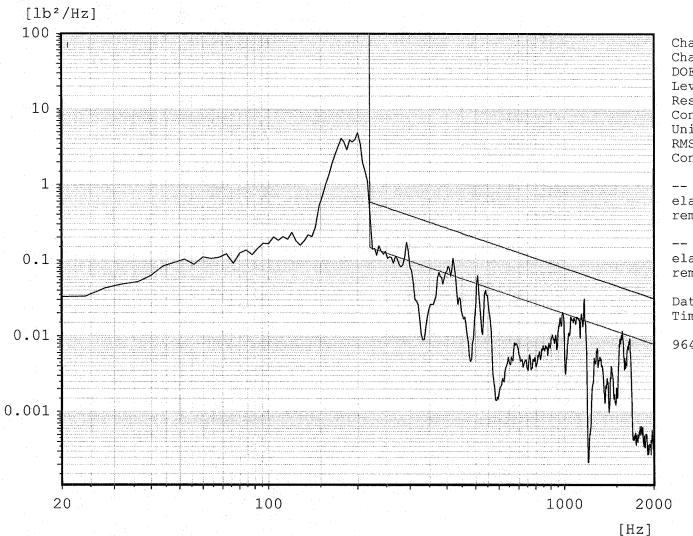
101713, Run # 4, X axis

SPIRE BDA

P/N 10209800-, S/N: 015

Force Sum X 0dB, Cold





Chan.no: 6 Chan.type: W DOF: 90 0.0 dB Level: Resolution: 4 Hz Contr.strat.: Maximum lb²/Hz Unit: 15.31 lb RMS (act.): Contr.strat.: Closed loop

-- Time on act. level -elapsed: 000:02:00 remaining: 000:00:00

-- Time total --

elapsed: 000:03:06 remaining: 000:00:00

Date: 03-08-05 Time: 13:16:46

101713, Run # 4, X axis

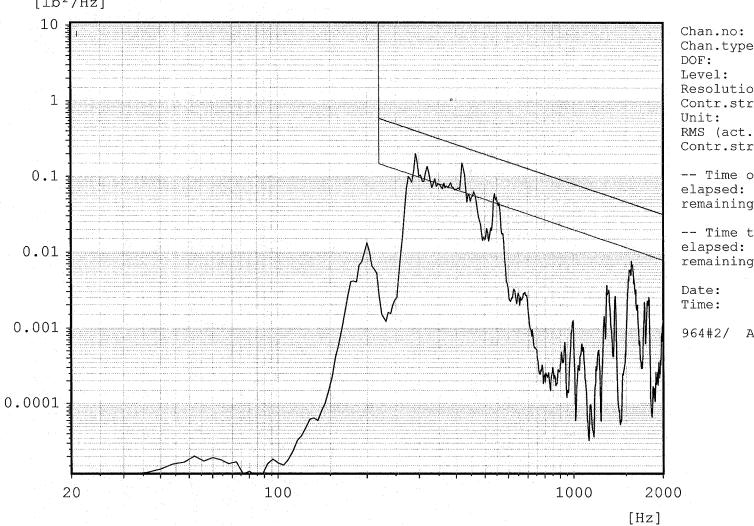
SPIRE BDA

P/N 10209800-, S/N: 015

 $[lb^2/Hz]$

Force Sum Y 0dB, Cold





7. Chan.type: W 90 0.0 dB Resolution: 4 Hz Contr.strat.: Maximum lb²/Hz 4.762 lb RMS (act.): Contr.strat.: Closed loop

-- Time on act. level -elapsed: 000:02:00 remaining: 000:00:00

-- Time total --

000:03:06 remaining: 000:00:00

03-08-05 13:16:46

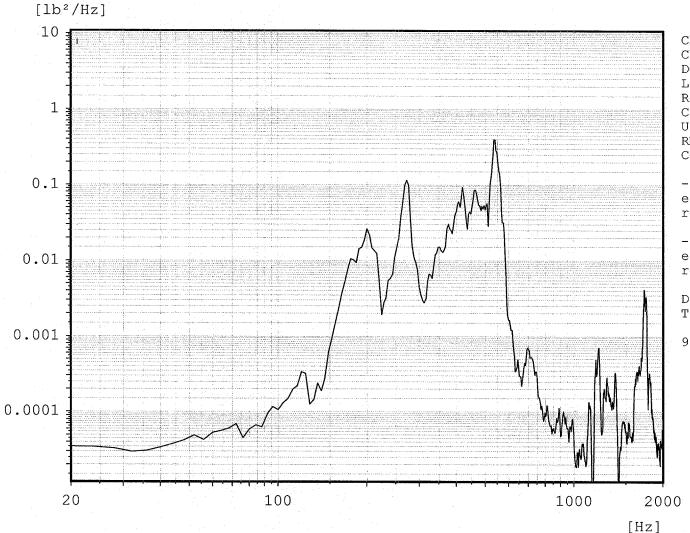
101713, Run # 4, X axis

SPIRE BDA

P/N 10209800-, S/N: 015

Force Sum Z 0dB, Cold





Chan.no: Chan.type: W DOF: 90 Level: 0.0 dB Resolution: 4 Hz Contr.strat.: Maximum Unit: lb²/Hz RMS (act.): 4.77 lb Contr.strat.: Closed loop

-- Time on act. level -elapsed: 000:02:00 remaining: 000:00:00

-- Time total --

elapsed: 000:03:06 remaining: 000:00:00

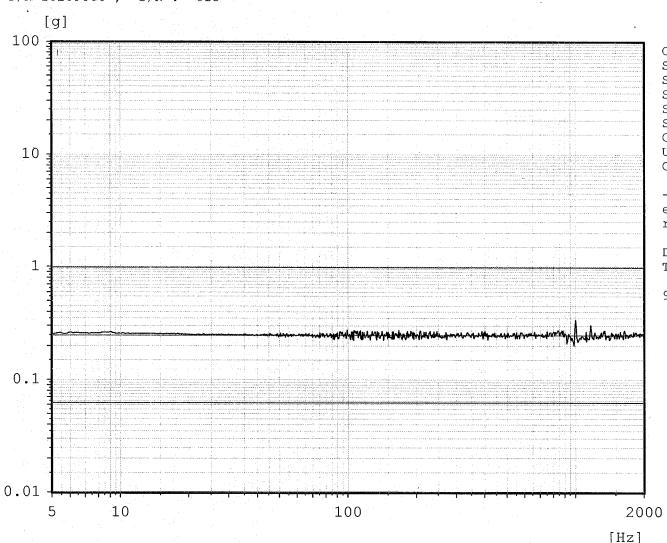
03-08-05 Date: 13:16:46 Time:

Sine 101713, Run # 6, X axis Spire BDA P/N 10209800-, S/N: 015

Control channel

After Shake, Cold





Chan.type: X

Sweep type: logarithmic

Sweeps done: 1 Sweeps req.: 1 Sweep direct.: up

Sweep rate: 4.00 Oct/min

Contr.strat.: Maximum

Unit: g

Contr.strat.: Closed loop

-- Testing time --

elapsed: 000:02:09 remaining: 000:00:00

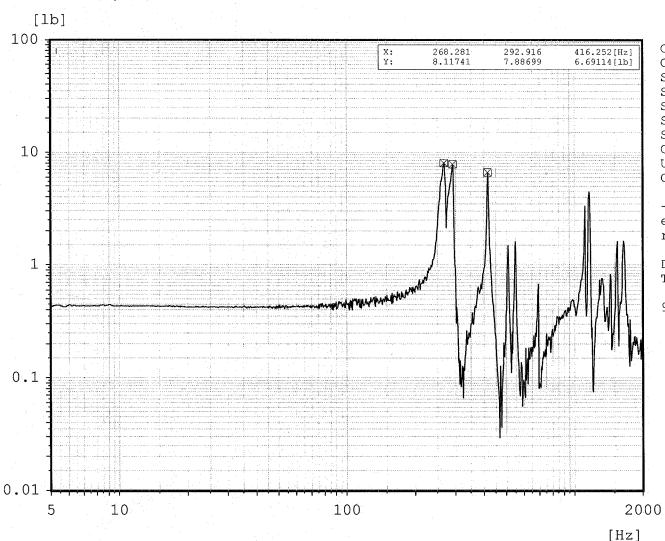
Date: 03-08-05 Time: 13:30:26

Sine 101713, Run # 6, X axis Spire BDA P/N 10209800-, S/N: 015 [lb] 100 10

Force Sum X

After Shake, Cold





Chan.no:

Chan.type: RMS Sweep type: logarithmic

Sweeps done: Sweeps req.: Sweep direct.: up

4.00 Oct/min Sweep rate:

Contr.strat.: Maximum

Unit: lb

Contr.strat.: Closed loop

-- Testing time --

elapsed: 000:02:09 remaining: 000:00:00

Date: 03-08-05 Time: 13:30:26

Sine 101713, Run # 6, X axis

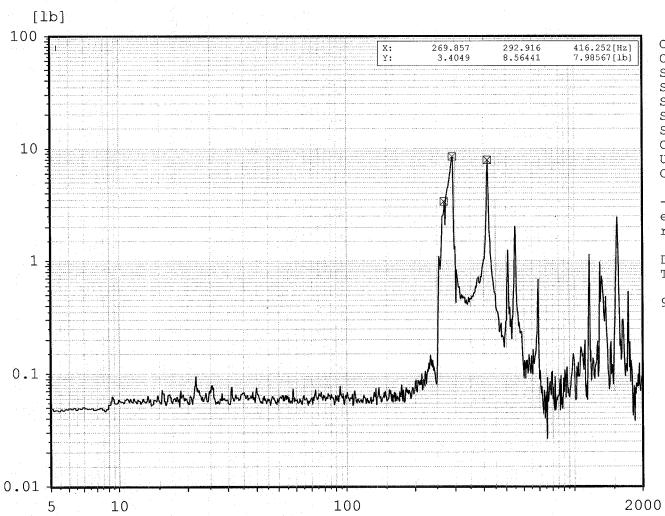
101/13, Run # 6, X axis Spire BDA

P/N 10209800-, S/N: 015

Force Sum Y

After Shake, Cold





Chan.no: 7

Chan.type: W RMS Sweep type: logarithmic

Sweeps done: 1
Sweeps req.: 1
Sweep direct.: up

Sweep rate: 4.00 Oct/min

Contr.strat.: Maximum

Unit: lb

Contr.strat.: Closed loop

-- Testing time --

elapsed: 000:02:09 remaining: 000:00:00

Date: 03-08-05 Time: 13:30:26

964#2/Amp #1/ M+P #2

[Hz]

101713, Run # 6, X axis

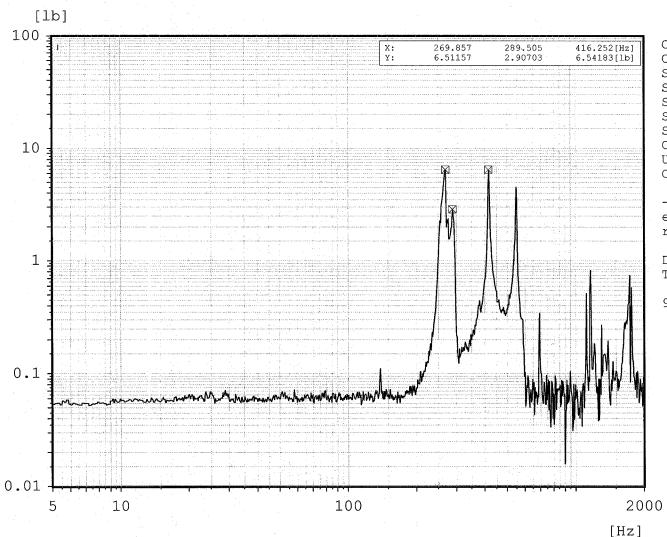
Spire BDA

P/N 10209800-, S/N: 015

Force Sum Z

After Shake, Cold





Chan.no: 8

Chan.type: W RMS Sweep type: logarithmic

Sweeps done: 1
Sweeps req.: 1
Sweep direct.: up

Sweep rate: 4.00 Oct/min

Contr.strat.: Maximum

Unit: lb

Contr.strat.: Closed loop

-- Testing time --

elapsed: 000:02:09 remaining: 000:00:00

Date: 03-08-05 Time: 13:30:26

PERFORMANCE VERIFICATION MATRIX - FS SLW BDA - 10209800-4 S/N 015

BDA Performance

Item	D. Value	Min Perf	Measured Median	Unit	Reference	Note
Number of bad optical pixels	= 2	= 5	1		BDA-PER-01	mod. noisy detector
(NEPphoton/NEPtotal) ² (derived)	> 0.60	> 0.50	0.645		BDA-PER-02	at 30 mVrms bias
Optical efficiency*	> 0.7		0.82		BDA-PER-05	
Detector time constant	< 4.2	< 14	4.0	ms	BDA-PER-07	at 20 mV bias
Vmax***	< 17***		11.0	mVrms	BDA-DRCU-22	
Calibration uniformity**	> 0.99	> 0.99	N/M		BDA-PER-08	
Cross-talk (n-n)**	< 0.01	< 0.05	N/M		BDA-PER-09	
Cross-talk (non n-n)**	< 0.001	< 0.001	N/M		BDA-PER-09	
1/f knee frequency	< 30	< 100	64	mHz	BDA-PER-10	at 21.2 mV bias
Average conducted heat load from 1.7 K	< 1.6	< 3.0	< 1.4	uW	BDA-TEC-06	

BDA Design Values (at 300 mK)

Item	Target	Measured Median	Unit	Reference	Note
R0	180.0	105.7	Ohms	BDA-SSSD	
Delta	41.8	42.8	K	BDA-SSSD	
R300	24.0	16.7	MOhms	BDA-SSSD	
G300	170.0	205.8	pW/K	BDA-SSSD	
Beta	1.50	1.49		BDA-SSSD	
C300	1.00	0.95	pJ/K	BDA-SSSD	
Rir	10.0	8.2	MOhms	BDA-SSSD	room temp
Dark Sdc	4.1	3.2	e8 V/W	BDA-SSSD	at 21.2 mV bias
Dark NEP (model), incl 9 nV/rtHz amp. noise		5.5	e-17 W/rtHz		at 21.2 mV bias
Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise	5.6		e-17 W/rtHz	derived	at 21.2 mV bias
Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise	5.6	6.8	e-17 W/rtHz	derived	at 21.2 mV bias
Vmax	10.3	9.5	mVrms	BDA-SSSD	SSSD value in error
BDA temperature rise from 1.7 K	< 10	10.2		BDA-HCO-1	
BDA thermal time constant	~ 100	130	S	BDA-HCO-2	

^{*}assumes vlower = 1.02 vcutoff

T1 saturates (> 17mVrms) at 46.4 mVrms bias

T1 saturates (> 17mVrms) at 44.0 mVrms bias

^{**}not tested

^{***}Thermistor values are not included

Problem Channels

		Р	ixel funct	ional at	
Pixel	Diagnosis	300 K	4 K	0.3 K	Notes
DK1	BDA Dead	No	No	No	Pixel Dead in Fabrication
DK2	not dark	Yes	Yes	Yes	Light leaks into dark channel
D4	Moderately BDA noisy	Yes	Yes	Yes	BoDAC channel was quiet from previous units

Pixel Performance										
Item	DV	MP								_
BDA connector			J05	J05	J05	J05	J05	J05	J05	J05
BDA pins			1,26	2,27	3,28	4,29	5,30	6,31	7,32	8,33
BoDAC Connector			4	4	4	4	4	4	4	4
Channel ID			1	2	3	4	5	6	7	8
Detector ID			R1	T1	C1	DK1	B1	D1	E1	A1
BDA Pixel Operability			Yes	Yes	Yes	No	Yes	Yes	Yes	Yes
BoDAC channel Operability	N/A	N/A	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes
Noisy BoDAC channel	N/A	N/A	No	No	No	No	No	No	No	No
(NEPphoton/NEPtotal)^2 (derived)	> 0.60	> 0.50	N/M	N/A	0.62	N/M	0.64	0.64	0.64	0.62
Optical efficiency*	> 0.7		N/M	N/A	0.83	N/M	0.84	0.85	0.81	0.82
Detector time constant	< 4.2	< 14	N/M	N/A	4.19	N/M	4.50	3.50	3.85	4.63
Calibration uniformity**	> 0.99	> 0.99	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A
Cross-talk (n-n)**	< 0.01	< 0.05	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A
Cross-talk (non n-n)**	< 0.001	< 0.001	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A
1/f knee frequency	< 30	< 100	< 30	73	< 100	N/A	64	55	82	82
Item		get								
R0		0.0	5.60E+06	89.60	00.40					
Delta	41.8				92.12	N/M	102.90	113.62	99.70	
			0.00	40.04	42.56	N/M	42.92	42.69	43.03	42.67
G300	17	70	N/A	40.04 N/A	42.56 211.26	N/M N/M	42.92 208.75	42.69 207.07	43.03 208.81	42.67 202.42
G300 Beta	17	70 .5	N/A N/A	40.04 N/A N/A	42.56 211.26 1.49	N/M N/M N/M	42.92 208.75 1.49	42.69 207.07 1.48	43.03 208.81 1.48	42.67 202.42 1.52
G300 Beta C300	17 1 1.	70 .5 00	N/A N/A N/A	40.04 N/A N/A N/A	42.56 211.26 1.49 1.03	N/M N/M N/M N/M	42.92 208.75 1.49 1.08	42.69 207.07 1.48 0.83	43.03 208.81 1.48 0.93	42.67 202.42 1.52 1.10
G300 Beta C300 Gamma	17 1 1. 1 (fi	70 .5 00 xed)	N/A N/A N/A 1.0	40.04 N/A N/A N/A 1.0	42.56 211.26 1.49 1.03 1.0	N/M N/M N/M N/M 1.0	42.92 208.75 1.49 1.08 1.0	42.69 207.07 1.48 0.83 1.0	43.03 208.81 1.48 0.93 1.0	42.67 202.42 1.52 1.10 1.0
G300 Beta C300 Gamma R300	17 1 1. 1 (fi	70 .5 00 xed)	N/A N/A N/A 1.0 5.7	40.04 N/A N/A N/A 1.0 9.3	42.56 211.26 1.49 1.03 1.0 13.7	N/M N/M N/M N/M 1.0	42.92 208.75 1.49 1.08 1.0 16.1	42.69 207.07 1.48 0.83 1.0 17.2	43.03 208.81 1.48 0.93 1.0 15.8	42.67 202.42 1.52 1.10 1.0 13.5
G300 Beta C300 Gamma R300 RIr+	17 1 1. 1 (fi 24 10	70 .5 00 xed) I.1	N/A N/A N/A 1.0 5.7 8.2	40.04 N/A N/A N/A 1.0 9.3 8.1	42.56 211.26 1.49 1.03 1.0 13.7 8.0	N/M N/M N/M N/M 1.0 N/M 8.1	42.92 208.75 1.49 1.08 1.0 16.1 8.2	42.69 207.07 1.48 0.83 1.0 17.2 8.2	43.03 208.81 1.48 0.93 1.0 15.8 8.2	42.67 202.42 1.52 1.10 1.0 13.5 8.1
G300 Beta C300 Gamma R300 RIr+ RIr-	11 1 1. 1 (fi 24 10	70 .5 .00 xed) i.1 0.0	N/A N/A N/A 1.0 5.7 8.2 8.1	40.04 N/A N/A N/A 1.0 9.3 8.1 8.0	42.56 211.26 1.49 1.03 1.0 13.7 8.0 8.1	N/M N/M N/M N/M 1.0 N/M 8.1 8.2	42.92 208.75 1.49 1.08 1.0 16.1 8.2 8.1	42.69 207.07 1.48 0.83 1.0 17.2 8.2 8.1	43.03 208.81 1.48 0.93 1.0 15.8 8.2 8.1	42.67 202.42 1.52 1.10 1.0 13.5 8.1 8.2
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc	17 1 1. 1 (fi 24 10	70 .5 .00 xed) i.1 0.0	N/A N/A N/A 1.0 5.7 8.2 8.1 N/A	40.04 N/A N/A N/A 1.0 9.3 8.1 8.0 N/A	42.56 211.26 1.49 1.03 1.0 13.7 8.0 8.1 3.0	N/M N/M N/M N/M 1.0 N/M 8.1 8.2 N/M	42.92 208.75 1.49 1.08 1.0 16.1 8.2 8.1 3.2	42.69 207.07 1.48 0.83 1.0 17.2 8.2 8.1 3.2	43.03 208.81 1.48 0.93 1.0 15.8 8.2 8.1 3.2	42.67 202.42 1.52 1.10 1.0 13.5 8.1 8.2 3.0
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise	11. 1 . 1 (fi. 24 10.	70 .5 .00 xed) I.1 0.0 0.0	N/A N/A N/A 1.0 5.7 8.2 8.1 N/A	40.04 N/A N/A N/A 1.0 9.3 8.1 8.0 N/A N/A	42.56 211.26 1.49 1.03 1.0 13.7 8.0 8.1 3.0 5.7	N/M N/M N/M N/M 1.0 N/M 8.1 8.2 N/M N/M	42.92 208.75 1.49 1.08 1.0 16.1 8.2 8.1 3.2 5.5	42.69 207.07 1.48 0.83 1.0 17.2 8.2 8.1 3.2 5.5	43.03 208.81 1.48 0.93 1.0 15.8 8.2 8.1 3.2 5.5	42.67 202.42 1.52 1.10 1.0 13.5 8.1 8.2 3.0 5.6
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise	11. 1 . 1 (fi. 24 10 10 2	70 .5 .00 xed) i.1 .0.0 .0.0 .2	N/A N/A N/A 1.0 5.7 8.2 8.1 N/A N/A	40.04 N/A N/A N/A 1.0 9.3 8.1 8.0 N/A N/A	42.56 211.26 1.49 1.03 1.0 13.7 8.0 8.1 3.0 5.7 5.79	N/M N/M N/M N/M 1.0 N/M 8.1 8.2 N/M N/M	42.92 208.75 1.49 1.08 1.0 16.1 8.2 8.1 3.2 5.5 5.84	42.69 207.07 1.48 0.83 1.0 17.2 8.2 8.1 3.2 5.5 6.21	43.03 208.81 1.48 0.93 1.0 15.8 8.2 8.1 3.2 5.5 5.39	42.67 202.42 1.52 1.10 1.0 13.5 8.1 8.2 3.0 5.6 5.56
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise	17. 1 1. 1 (fii 24 10 10 2	70 .5 .00 xed) i.1 .0.0 .0.0 .2	N/A N/A N/A 1.0 5.7 8.2 8.1 N/A N/A	40.04 N/A N/A 1.0 9.3 8.1 8.0 N/A N/A N/A	42.56 211.26 1.49 1.03 1.0 13.7 8.0 8.1 3.0 5.7 5.79 9.74	N/M N/M N/M N/M 1.0 N/M 8.1 8.2 N/M N/M N/M	42.92 208.75 1.49 1.08 1.0 16.1 8.2 8.1 3.2 5.5 5.84 7.31	42.69 207.07 1.48 0.83 1.0 17.2 8.2 8.1 3.2 5.5 6.21 7.99	43.03 208.81 1.48 0.93 1.0 15.8 8.2 8.1 3.2 5.5 5.39 6.49	202.42 1.52 1.10 1.0 13.5 8.1 8.2 3.0 5.6 5.56 7.31
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise	11. 1 . 1 (fi. 24 10 10 2	70 .5 .00 xed) i.1 .0.0 .0.0 .2	N/A N/A N/A 1.0 5.7 8.2 8.1 N/A N/A	40.04 N/A N/A N/A 1.0 9.3 8.1 8.0 N/A N/A	42.56 211.26 1.49 1.03 1.0 13.7 8.0 8.1 3.0 5.7 5.79	N/M N/M N/M N/M 1.0 N/M 8.1 8.2 N/M N/M	42.92 208.75 1.49 1.08 1.0 16.1 8.2 8.1 3.2 5.5 5.84	42.69 207.07 1.48 0.83 1.0 17.2 8.2 8.1 3.2 5.5 6.21	43.03 208.81 1.48 0.93 1.0 15.8 8.2 8.1 3.2 5.5 5.39	42.67 202.42 1.52 1.10 1.0 13.5 8.1 8.2 3.0 5.6 5.56
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise Vmax	17. 1 1. 1 (fii 24 10 10 2	70 .5 .00 xed) i.1 .0.0 .0.0 .2	N/A N/A N/A 1.0 5.7 8.2 8.1 N/A N/A	40.04 N/A N/A 1.0 9.3 8.1 8.0 N/A N/A N/A	42.56 211.26 1.49 1.03 1.0 13.7 8.0 8.1 3.0 5.7 5.79 9.74	N/M N/M N/M N/M 1.0 N/M 8.1 8.2 N/M N/M N/M	42.92 208.75 1.49 1.08 1.0 16.1 8.2 8.1 3.2 5.5 5.84 7.31	42.69 207.07 1.48 0.83 1.0 17.2 8.2 8.1 3.2 5.5 6.21 7.99	43.03 208.81 1.48 0.93 1.0 15.8 8.2 8.1 3.2 5.5 5.39 6.49	42.67 202.42 1.52 1.10 1.0 13.5 8.1 8.2 3.0 5.6 5.56 7.31
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise Vmax *assumes vlower = 1.02 vcutoff	17. 1 1. 1 (fii 24 10 10 2	70 .5 .00 xed) i.1 .0.0 .0.0 .2	N/A N/A N/A 1.0 5.7 8.2 8.1 N/A N/A	40.04 N/A N/A 1.0 9.3 8.1 8.0 N/A N/A N/A	42.56 211.26 1.49 1.03 1.0 13.7 8.0 8.1 3.0 5.7 5.79 9.74	N/M N/M N/M N/M 1.0 N/M 8.1 8.2 N/M N/M N/M	42.92 208.75 1.49 1.08 1.0 16.1 8.2 8.1 3.2 5.5 5.84 7.31	42.69 207.07 1.48 0.83 1.0 17.2 8.2 8.1 3.2 5.5 6.21 7.99	43.03 208.81 1.48 0.93 1.0 15.8 8.2 8.1 3.2 5.5 5.39 6.49	42.67 202.42 1.52 1.10 1.0 13.5 8.1 8.2 3.0 5.6 5.56 7.31
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise Vmax *assumes vlower = 1.02 vcutoff **not tested	17. 1 1. 1 (fii 24 10 10 2	70 .5 .00 xed) i.1 .0.0 .0.0 .2	N/A N/A N/A 1.0 5.7 8.2 8.1 N/A N/A	40.04 N/A N/A 1.0 9.3 8.1 8.0 N/A N/A N/A	42.56 211.26 1.49 1.03 1.0 13.7 8.0 8.1 3.0 5.7 5.79 9.74	N/M N/M N/M N/M 1.0 N/M 8.1 8.2 N/M N/M N/M	42.92 208.75 1.49 1.08 1.0 16.1 8.2 8.1 3.2 5.5 5.84 7.31	42.69 207.07 1.48 0.83 1.0 17.2 8.2 8.1 3.2 5.5 6.21 7.99	43.03 208.81 1.48 0.93 1.0 15.8 8.2 8.1 3.2 5.5 5.39 6.49	42.67 202.42 1.52 1.10 1.0 13.5 8.1 8.2 3.0 5.6 5.56 7.31
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise Vmax *assumes vlower = 1.02 vcutoff	17. 1 1. 1 (fii 24 10 10 2	70 .5 .00 xed) i.1 .0.0 .0.0 .2	N/A N/A N/A 1.0 5.7 8.2 8.1 N/A N/A	40.04 N/A N/A 1.0 9.3 8.1 8.0 N/A N/A N/A	42.56 211.26 1.49 1.03 1.0 13.7 8.0 8.1 3.0 5.7 5.79 9.74	N/M N/M N/M N/M 1.0 N/M 8.1 8.2 N/M N/M N/M	42.92 208.75 1.49 1.08 1.0 16.1 8.2 8.1 3.2 5.5 5.84 7.31	42.69 207.07 1.48 0.83 1.0 17.2 8.2 8.1 3.2 5.5 6.21 7.99	43.03 208.81 1.48 0.93 1.0 15.8 8.2 8.1 3.2 5.5 5.39 6.49	42.67 202.4; 1.52 1.10 1.0 13.5 8.1 8.2 3.0 5.6 5.56 7.31

Pixel Performance										
ltem										
BDA connector	J05									
BDA pins	9,34	10,35	11,36	12,37	13,38	14,39	15,40	16,41	17,42	18,43
BoDAC Connector	4	4	4	4	4	4	4	4	4	4
Channel ID	9	10	11	12	13	14	15	16	17	18
Detector ID	C2	D2	B2	E2	A2	C3	D3	В3	E3	C4
BDA Pixel Operability	Yes									
BoDAC channel Operability	Yes									
Noisy BoDAC channel	No	No	No	No	No	No	Yes	No	No	No
(NEPphoton/NEPtotal)^2 (derived)	0.63	0.65	0.63	0.62	0.65	0.66	0.65	0.65	0.65	0.67
Optical efficiency*	0.83	0.82	0.82	0.85	0.82	0.71	0.80	0.83	0.81	0.78
Detector time constant	3.95	3.75	4.00	3.79	4.50	3.82	3.70	4.22	3.83	5.15
Calibration uniformity**	N/A									
Cross-talk (n-n)**	N/A									
Cross-talk (non n-n)**	N/A									
1/f knee frequency	73	55	73	64	55	55	46	64	73	92
ltem										
R0	99.53	122.63	94.74	94.79	110.53	130.70	118.65	106.39	108.19	199.12
Delta	42.49	43.26	42.66	42.15	43.11	43.30	43.29	43.22	43.10	41.59
G300	207.96	208.06	212.78	204.96	207.25	208.72	205.95	205.62	203.51	164.95
Beta	1.49	1.48	1.48	1.48	1.50	1.50	1.49	1.50	1.48	1.71
C300	0.96	0.88	0.99	0.91	1.07	0.89	0.86	1.00	0.90	0.97
Gamma	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0
R300	14.7	20.1	14.3	13.3	17.8	21.6	19.6	17.4	17.4	25.8
Rir+	8.2	8.2	8.2	8.2	8.2	8.4	8.2	8.2	8.2	8.2
RIr-	8.1	8.2	8.2	8.2	8.2	8.2	8.2	8.2	8.2	8.2
Dark Sdc	3.1	3.4	3.0	3.0	N/M	3.5	3.4	3.3	3.3	4.1
Dark NEP (model), incl 9 nV/rtHz amp. noise	5.6	5.4	5.7	5.6	5.5	5.4	5.4	5.4	5.4	4.8
Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise	5.31	5.43	5.45	5.69	5.53	5.61	7.40	5.45	5.48	5.57
Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise	6.84	6.30	6.70	7.06	6.80	6.38	8.10	6.60	6.74	7.60
Vmax	8.86	10.30	8.83	8.40	9.68	10.69	10.11	9.53	9.48	11.03
400 45										
*assumes vlower = 1.02 vcutoff										
**not tested										
***T1 saturates (> 17mVrms) at 46.4 mVrms bias										
***T1 saturates (> 17mVrms) at 44.0 mVrms bias										

Pixel Performance	- 11							
item							Unit	Reference
BDA connector	J05	J05	J05	J05	J05	J05		
BDA pins	19,44	20,45	21,46	22,47	23,48	24,49		
BoDAC Connector	4	4	4	4	4	4		
Channel ID	19	20	21	22	23	24		
Detector ID	DK2	D4	C5	B4	A3	T2		
BDA Pixel Operability	Yes	M. Noisy	Yes	Yes	Yes	Yes		
BoDAC channel Operability	Yes	Yes	Yes	Yes	Yes	Yes		
Noisy BoDAC channel	No	No	No	No	No	No		
(NEPphoton/NEPtotal)^2 (derived)	0.67	0.63	0.64	0.66	0.65	N/A		BDA-PER-02
Optical efficiency*	N/M	0.84	0.83	0.85	0.79	N/A		BDA-PER-05
Detector time constant	3.28	3.65	4.26	4.07	5.28	N/A	ms	BDA-PER-07
Calibration uniformity**	N/A	N/A	N/A	N/A	N/A	N/A		BDA-PER-08
Cross-talk (n-n)**	N/A	N/A	N/A	N/A	N/A	N/A		BDA-PER-09
Cross-talk (non n-n)**	N/A	N/A	N/A	N/A	N/A	N/A		BDA-PER-09
1/f knee frequency	82	137	73	27	37	64	mHz	BDA-PER-10
Item							Unit	Reference
R0	189.99	96.29	97.52	122.59	111.12	104.95	Ohms	BDA-SSSD
Delta	41.56	42.74	42.99	43.37	43.41	39.72	K	BDA-SSSD
G300	172.37	203.05	202.37	203.62	202.24	N/A	pW/K	BDA-SSSD
Beta	1.66	1.50	1.51	1.50	1.50	N/A		BDA-SSSD
C300	0.64	0.87	1.00	0.94	1.22	N/A	pJ/K	BDA-SSSD
Gamma	1.0	1.0	1.0	1.0	1.0	1.0	·	
R300	24.6	14.7	15.4	20.4	18.6	10.4	MOhms	BDA-SSSD
Rir+	8.3	8.3	8.2	8.2	8.3	8.3	MOhms	BDA-SSSD
Rir-	8.2	8.2	8.2	8.3	8.3	8.2		BDA-SSSD
Dark Sdc	3.9	3.1	3.2	3.5	3.4	N/A	e8 V/W	BDA-SSSD
Dark NEP (model), incl 9 nV/rtHz amp. noise	4.9	5.5	5.5	5.3	5.4	N/A		
Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise	4.91	8.74	5.39	7.28	6.88	N/A	-17 W/rtH	.
				0.07	8.34	N/A	17 M//HU	
Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise	6.57	15.57	6.64	8.27				derived
Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise Vmax	6.57 10.65	15.57 8.75	6.64 8.93	10.27	9.77	***		
Vmax								derived
Vmax *assumes vlower = 1.02 vcutoff								derived
*assumes vlower = 1.02 vcutoff **not tested								derived
Vmax *assumes vlower = 1.02 vcutoff								derived

Pixel Performance	
Item	Note
BDA connector	
BDA pins	
BoDAC Connector	
Channel ID	
Detector ID	
BDA Pixel Operability	
BoDAC channel Operability	
Noisy BoDAC channel	
(NEPphoton/NEPtotal)^2 (derived)	at 30 mV bias
Optical efficiency*	
Detector time constant	at 28 mV bias
Calibration uniformity**	
Cross-talk (n-n)**	
Cross-talk (non n-n)**	
1/f knee frequency	at 21.2 mV bias
Pixel Design Values	
ltem	Note
R0	
Delta	
Della	
G300	
G300 Beta	
G300	
G300 Beta	
G300 Beta C300	
G300 Beta C300 Gamma	room temp
G300 Beta C300 Gamma R300 RIr+ RIr-	room temp
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc	
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise	room temp at 21.2 mV bias
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise	room temp at 21.2 mV bias at 21.2 mV bias
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise	room temp at 21.2 mV bias
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise	room temp at 21.2 mV bias at 21.2 mV bias
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise Vmax	room temp at 21.2 mV bias at 21.2 mV bias
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise Vmax *assumes vlower = 1.02 vcutoff	room temp at 21.2 mV bias at 21.2 mV bias
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise Vmax *assumes vlower = 1.02 vcutoff **not tested	room temp at 21.2 mV bias at 21.2 mV bias
G300 Beta C300 Gamma R300 RIr+ RIr- Dark Sdc Dark NEP (model), incl 9 nV/rtHz amp. noise Dark NEP (1 Hz), incl 9 nV/rtHz amp. noise Dark NEP (0.1 Hz), incl 9 nV/rtHz amp. noise Vmax *assumes vlower = 1.02 vcutoff	room temp at 21.2 mV bias at 21.2 mV bias

Symbol	Units	Value	Value	Value	Value	Value	Value	Value	Value	Value	Value	Value	Value	Value
T0	K		Base Tempera				Note: Correct		,					
Vn	nV/rtHz		Amplifier Voltage				corrected for							
Q	pW		Absorbed Power C				assumes only				, and LR pro	pagates		
NEP _{photon}	1e-17 W/rtHz		Noise in Absorbed				added 2 more							
Vbias Gain	mV	81000	Bias Across Bolom	ieter & Load Resist	ors		added variab							
Gairi		81000					INEFS CHECKE	su with Stant	iaiu spieaus	ПССІ				
Detector ID		Target	R1	T1	C1	DK1	B1	D1	E1	A1	C2	D2	B2	E2
Pthermal	pW	5.440	N/A	#VALUE!	6.234	#VALUE!	6.433	6.508	6.393	6.100	6.242	6.628	6.205	6.031
Pelec+Q	pW	5.440	N/A	#VALUE!	6.234	#VALUE!	6.433	6.508	6.393	6.100	6.242	6.628	6.205	6.031
Tbolo	K	0.32975	N/A	#VALUE!	0.32759	#VALUE!	0.32874	0.32929	0.32857	0.32810	0.32803	0.32965	0.32729	0.32753
T/T0		1.099	N/A	#VALUE!	1.092	#VALUE!	1.096	1.098	1.095	1.094	1.093	1.099	1.091	1.092
Rbolo	Ω	1.40E+07	5.07E+06	#VALUE!	8.21E+06	#VALUE!	9.44E+06	1.00E+07	9.30E+06	8.00E+06	8.73E+06	1.16E+07	8.60E+06	8.01E+06
Vbolo	mV	8.72	5.03	#VALUE!	7.15	#VALUE!	7.79	8.07	7.71	6.99	7.38	8.76	7.31	6.95
Ibolo	nA	0.62	0.99	#VALUE!	0.87	#VALUE!	0.83	0.81	0.83	0.87	0.85	0.76	0.85	0.87
A		-5.63	N/A	#VALUE!	-5.70	#VALUE!	-5.71	-5.69	-5.72	-5.70	-5.69	-5.73	-5.71	-5.67
С	pJ/K	1.10	N/A	#VALUE!	1.13	#VALUE!	1.19	0.91	1.02	1.21	1.04	0.97	1.08	0.99
G	pW/K	195.9	N/A	#VALUE!	240.8	#VALUE!	239.2	237.6	239.0	231.9	237.6	239.3	242.1	233.4
Z/R		0.357	1.000	#VALUE!	0.379	#VALUE!	0.363	0.357	0.364	0.373	0.374	0.350	0.382	0.382
τ	ms	5.175		#VALUE!	4.090	#VALUE!	4.420	3.444	3.780	4.499	3.862	3.732	3.912	3.691
Sdc	V/W	4.12E+08	N/A	#VALUE!	2.99E+08	#VALUE!	3.19E+08	3.27E+08	3.17E+08	3.04E+08	3.09E+08	3.44E+08	3.03E+08	3.00E+08
NEP _{johnson}	1e-17 W/rtHz	2.276	N/A	#VALUE!	2.703	#VALUE!	2.598	2.557	2.605	2.658	2.655	2.472	2.698	2.693
NEP _{phonon}	1e-17 W/rtHz	3.174		#VALUE!	3.515		3.506	3.496	3.504	3.448	3.492	3.509	3.524	3.460
	1e-17 W/rtHz			#VALUE!			1.892		1.882		1.856	1.979		
NEP _{load}		1.814			1.846			1.913		1.782			1.873	1.800
NEP _{amp}	1e-17 W/rtHz	2.182		#VALUE!	3.013		2.825	2.755	2.837	2.963	2.916	2.613	2.972	2.996
NEP _{det}	1e-17 W/rtHz	4.828		#VALUE!	5.669		5.532	5.478	5.537	5.560	5.585	5.401	5.660	5.607
DQE		0.000	N/A	#VALUE!	0.000	#VALUE!	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000
Vn(det)	nV/rtHz	19.9	12.13	#VALUE!	16.9	#VALUE!	17.6	17.9	17.6	16.9	17.2	18.6	17.1	16.8
Vn(total)	nV/rtHz	19.9		#VALUE!	16.9		17.6	17.9	17.6	16.9	17.2	18.6	17.1	16.8
VII(total)	110/1012	10.0	12.1	#V/LOL:	10.0	WV/ LOL:	17.0	17.0	17.0	10.0	17.2	10.0	17.1	10.0
Vn(measured	d) at 1Hz (no T/C)		12.6	15.6	17.3	N/M	18.6	20.3	17.1	16.9	16.4	18.7	16.5	17.1
NEP(measure	ed) at 1Hz (no T/0	C)	N/A	N/M	5.79	N/M		6.21	5.39	5.56	5.31	5.43	5.45	5.69
	d) at 0.1Hz (no T/0		13.7	19.5	29.1	N/M		26.1	20.6	22.2	21.1	21.7	20.3	21.2
NEP(measure	ed) at 0.1Hz (No	T/C)	N/A	N/M	9.74	N/M	7.31	7.99	6.49	7.31	6.84	6.30	6.70	7.06
Vn(measured	d) at 1Hz (T/C)		12.6	17.2	18.3	N/M	21.8	22.1	18	18.1	17.4	18.8	17.6	18.5
	red) at 1Hz (T/C)		N/A	N/M	6.13	N/M		6.76	5.67	5.96	5.64	5.46	5.81	6.16
Vn(measured	d) at 0.1Hz (T/C)		13.7	22.1	29.9	N/M	87.8	27.9	28	26.9	22.7	22.5	26.9	27.8
NEP(measure	ed) at 0.1Hz (T/C)	N/A	N/M	10.01	N/M	27.56	8.54	8.83	8.86	7.36	6.53	8.88	9.26

Symbol	Value	Value										
T0												
Vn												
Q												
NEP _{photon}												
Vbias												
Gain												
Detector ID	A2	C3	D3	В3	E3	C4	DK2	D4	C5	В4	А3	T2
Pthermal	6.487	6.628	6.596	6.442	6.426	6.784	6.730	6.142	6.285	6.599	6.461	#VALUE!
Pelec+Q	6.487	6.628	6.596	6.442	6.426	6.784	6.730	6.142	6.285	6.599	6.461	#VALUE!
Tbolo	0.32915	0.32954	0.32979	0.32917	0.32941	0.33710	0.33548	0.32822	0.32892	0.33011	0.32970	#VALUE!
T/T0	1.097	1.098	1.099	1.097	1.098	1.124	1.118	1.094	1.096	1.100	1.099	#VALUE!
Rbolo	1.03E+07	1.24E+07	1.12E+07	1.01E+07	1.00E+07	1.33E+07	1.30E+07	8.70E+06	9.00E+06	1.17E+07	1.07E+07	#VALUE!
Vbolo	8.18	9.07	8.60	8.06	8.03	9.49	9.34	7.31	7.52	8.77	8.31	#VALUE!
Ibolo	0.79	0.73	0.77	0.80	0.80	0.72	0.72	0.84	0.84	0.75	0.78	#VALUE!
A	-5.72	-5.73	-5.73	-5.73	-5.72	-5.55	-5.57	-5.71	-5.72	-5.73	-5.74	#VALUE!
С	1.17	0.98	0.95	1.10	0.98	1.09	0.72	0.95	1.10	1.03	1.34	#VALUE!
G	238.1	240.3	237.1	236.2	233.8	201.3	207.4	232.4	232.4	235.0	233.1	#VALUE!
Z/R	0.357	0.352	0.348	0.356	0.354	0.286	0.300	0.370	0.361	0.344	0.349	#VALUE!
τ	4.437	3.808	3.674	4.162	3.771	5.097	3.248	3.567	4.164	4.047	5.216	#VALUE!
Sdc	3.31E+08	3.51E+08	3.43E+08	3.30E+08	3.32E+08	4.05E+08	3.93E+08	3.13E+08	3.19E+08	3.50E+08	3.42E+08	#VALUE!
NEP _{johnson}	2.540	2.447	2.474	2.539	2.527	2.141	2.207	2.624	2.584	2.438	2.482	#VALUE!
NEP _{phonon}	3.498	3.515	3.493	3.485	3.468	3.220	3.269	3.454	3.455	3.477	3.462	#VALUE!
NEP _{load}	1.922	2.020	1.950	1.898	1.883	1.818	1.852	1.820	1.830	1.952	1.901	#VALUE!
NEP _{amp}	2.718	2.562	2.622	2.724	2.709	2.220	2.291	2.871	2.819	2.568	2.634	#VALUE!
NEP _{det}	5.456	5.384	5.385	5.441	5.413	4.815	4.923	5.511	5.469	5.333	5.357	#VALUE!
DQE	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	#VALUE!
DQL	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	#VALUL:
Vn(det)	18.1	18.9	18.5	18.0	18.0	19.5	19.3	17.3	17.5	18.7	18.3	#VALUE!
Vn(total)	18.1	18.9	18.5	18.0	18.0	19.5	19.3	17.3	17.5	18.7	18.3	#VALUE!
VII(total)	10.1	10.5	10.5	10.0	10.0	10.0	10.0	17.5	17.5	10.7	10.0	#VALUE:
Vn(measured	18.3	19.8	25.9	18	18.2	22.6	19.9	27.4	17.2	25.5	25.5	16.4
NEP(measure	5.53	5.64	7.55	5.45	5.48	5.57	5.07	8.74	5.39	7.28	7.46	N/M
Vn(measured	22.9	22.4	27.8	21.8	22.4	32.2	29.9	48.8	21.2	29	29	19.6
NEP(measure	6.92	6.38	8.10	6.60	6.74	7.94	7.61	15.57	6.64	8.27	8.49	N/M
Vn(measured	19	19.7	25.4	18.4	19	22.8	19.3	27.6	18.7	26.5	23.5	17.4
NEP(measure	5.74	5.61	7.40	5.57	5.72	5.62	4.91	8.81	5.86	7.56	6.88	N/M
Vn(measured	22.5	24.9	35	22.7	28.4	30.8	25.8	71.8	46.8	32.8	28.5	21.4
NEP(measure	6.80	7.09	10.20	6.87	8.55	7.60	6.57	22.91	14.66	9.36	8.34	N/M

Symbol	Value	Value	Value	Value	Value	Value	Value
T0							
Vn							
Q							
NEP _{photon}							
Vbias							
Gain							
Detector ID							
Pthermal	Power as function of Temperature	P _{thermal} = [G	300/(1+β)][T	/0.3] ^β T evalua	ated from To	to Tb	
Pelec+Q	Electrical + Absorbed Power	P _e + Q = [V	_{bias} /(2R _L + R _E	3)] ² R _B + Q			
Tbolo	Bolometer Temperature	Solve for Tb u	ising Newtonian	recursion such	that P _{thermal} =	P _e + Q	
T/T0		T/To = Tbo					
Rbolo	Bolometer Resistance	Rbolo = (Ro	o)exp[(Δ/Tb) ¹	^{/2}]			
Vbolo	Voltage across Bolometer		oias/(2R _L + R				
Ibolo	Current through Bolometer	Ibolo = Vbia	as/(2R _L + R _B)				
A		A = (T/R)(d	R/dT) = -(1/2)	2)[(Δ/Tb) ^{1/2}]			
С	Dynamic Heat Capacity	C = C300[(
G	Dynamic Thermal Conductance	G = G300[(T/0.3) ^β]				
Z/R		Z/R = (I/V)(dV/dI) = [-1 -	- GTb/(P _e A)]	/ [1 – GTb/(F	P _e A)]	
τ	Electrical Time Constant	τ = [C/2G][(2R _L /R _B)] / [Z/	'R + 2R _L /R _B]		
Sdc	Electrical Responsivity at 0 Hz	Sdc = (1/2)	$[R_B/P_e]^{1/2}[1-$	- Z/R] / [1 + (2	Z/R)(R _B /2R _L)		
NEP _{johnson}	Johnson Noise Prior to Demodulation	NEP _{johnson} =	= [(4k(Tb) ³ G ²)/(P _e A ²)] ^{1/2}			
NEP _{phonon}	Phonon Noise Prior to Demodulation			$(2\beta + 3)^{2\beta + 3} - 1)]/[(2\beta + 3)]$			
NEP _{load}	Johnson Noise from R _L Prior to Demod.	NEP _{load} = [4	4kTo/2R _L] ^{1/2}	2(Z/R)R _B Ibol	o/[(Z/R) – 1]		
NEP _{amp}	Amplifier Noise Prior to Demodulation	NEP _{amp} = V	/n / Sdc				
NEP _{det}	Detector Noise after Demodulation	NEP _{det} = [2	NEP _{john} ² +NE	P _{phon} ² +2NEP	oad ² +2NEP _{an}	np ²] ^{1/2}	
DQE	BLIP Figure-of-Merit for Detector	DQE = NEF	P _{photon} ² / (NEF	P _{photon} ² + NEF	det ²)		
Vn(det)	Voltage Noise of Detector After Demod.	Vn(det) = N	IED. Sdc				
` '	0			$=$ $P_{\text{photon}}^2]^{1/2}$ Sc	1-		
Vn(total)	Total Noise after Demodulation	vn(total) =	INEP _{det} + N	=P _{photon}] Sc	ic		
Vn(measure							
NEP(measu							-
Vn(measure							
NEP(measu	ri 						
Vn(measure	d						
NEP(measu							
Vn(measure							
NEP(measu	rı						

Symbol	Units	Value	Value	Value	Value	Value	Value	Value	Value	Value	Value
T0	K		Base Temperat				ected for sqrt(
Vn	nV/rtHz		Amplifier Volta				r ETF in Johr				
Q	pW	_	Absorbed Power C				ly first harmo		i, and LR pro	pagates	
NEP _{photon}	1e-17 W/rtHz		Noise in Absorbed	•			re iterations				
Vbias	mV		Bias Across Bolom	neter & Load Resis	stors		ble gain to so				
Gain		81000				NEPs check	ced with stand	dard spreads	sheet		
Detector ID		Target	R1	T1	C1	DK1	B1	D1	E1	A1	C2
Pthermal	pW	18.188	N/A	#VALUE!	19.025		19.557	19.788	19.457	18.693	19.106
Pelec+Q	pW	18.188	N/A	#VALUE!	19.025		19.557	19.788	19.457	18.693	19.106
Tbolo	K	0.38713	N/A	#VALUE!	0.37541	#VALUE!	0.37798	0.37940	0.37766	0.37677	0.37668
T/T0		1.290	N/A	#VALUE!	1.251	#VALUE!	1.260	1.265	1.259	1.256	1.256
Rbolo	Ω	5.86E+06	5.07E+06	#VALUE!	3.88E+06		4.37E+06	4.59E+06	4.31E+06	3.74E+06	4.08E+06
Vbolo	mV	6.80	7.12	#VALUE!	5.82	#VALUE!	6.36	6.60	6.28	5.60	5.99
Ibolo	nA	1.16	1.41	#VALUE!	1.50	#VALUE!	1.46	1.44	1.46	1.50	1.47
Α		-5.20	N/A	#VALUE!	-5.32	#VALUE!	-5.33	-5.30	-5.34	-5.32	-5.31
С	pJ/K	1.29	N/A	#VALUE!	1.29		1.37	1.05	1.17	1.39	1.20
G	pW/K	249.2	N/A	#VALUE!	294.8	#VALUE!	294.5	293.0	293.9	286.2	291.9
Z/R		0.404	1.000	#VALUE!	0.409	#VALUE!	0.386	0.377	0.389	0.414	0.403
τ	ms	4.202	N/A	#VALUE!	3.491	#VALUE!	3.696	2.858	3.171	3.842	3.273
Sdc	V/W	2.30E+08	N/A	#VALUE!	1.79E+08	#VALUE!	1.91E+08	1.96E+08	1.90E+08	1.78E+08	1.85E+08
NEP _{johnson}	1e-17 W/rtHz	3.766	N/A	#VALUE!	4.028	#VALUE!	3.937	3.903	3.941	4.018	3.994
NEP _{phonon}	1e-17 W/rtHz	3.778	N/A	#VALUE!	4.060	#VALUE!	4.069	4.066	4.064	4.001	4.045
NEP _{load}	1e-17 W/rtHz	1.795	N/A	#VALUE!	1.766	#VALUE!	1.819	1.843	1.807	1.718	1.781
NEP _{amp}	1e-17 W/rtHz	4.351	N/A	#VALUE!	5.575	#VALUE!	5.233	5.102	5.259	5.604	5.419
NEP _{det}	1e-17 W/rtHz	7.114	N/A	#VALUE!	8.179	#VALUE!	7.921	7.823	7.935	8.156	8.054
DQE		0.685	N/A	#VALUE!	0.622	#VALUE!	0.637	0.643	0.636	0.624	0.630
-		3.230			0.022		5.551	3.3.10	2.200	0.02	
Vn(det)	nV/rtHz	16.4	12.89	#VALUE!	14.7	#VALUE!	15.1	15.3	15.1	14.6	14.9
Vn(total)	nV/rtHz	29.2	12.9	#VALUE!	23.9	#VALUE!	25.1	25.7	25.0	23.7	24.4

Symbol	Value											
T0												
Vn												
Q												
NEP _{photon}												
Vbias												
Gain												
Detector ID	D2	B2	E2	A2	C3	D3	В3	E3	C4	DK2	D4	C5
Pthermal	20.310	19.058	18.608	19.804	20.496	20.160	19.658	19.601	20.695	20.579	18.882	19.162
Pelec+Q	20.310	19.058	18.608	19.805	20.496	20.160	19.658	19.601	20.695	20.579	18.882	19.162
Tbolo	0.38081	0.37507	0.37600	0.37923	0.38104	0.38094	0.37927	0.37989	0.39682	0.39360	0.37736	0.37855
T/T0	1.269	1.250	1.253	1.264	1.270	1.270	1.264	1.266	1.323	1.312	1.258	1.262
Rbolo	5.22E+06	4.06E+06	3.76E+06	4.72E+06	5.57E+06	5.06E+06	4.61E+06	4.57E+06	5.56E+06	5.52E+06	4.03E+06	4.14E+06
Vbolo	7.23	5.96	5.59	6.70	7.53	7.06	6.56	6.52	7.60	7.53	5.88	6.06
Ibolo	1.39	1.47	1.49	1.42	1.35	1.40	1.43	1.43	1.37	1.37	1.46	1.46
Α	-5.33	-5.33	-5.29	-5.33	-5.33	-5.33	-5.34	-5.33	-5.12	-5.14	-5.32	-5.33
С	1.12	1.24	1.14	1.35	1.13	1.10	1.26	1.13	1.28	0.84	1.09	1.27
G	296.3	296.4	286.2	294.3	298.9	293.9	292.0	288.8	265.8	270.3	286.7	287.2
Z/R	0.358	0.408	0.420	0.376	0.354	0.361	0.378	0.378	0.329	0.336	0.406	0.394
τ	3.030	3.328	3.174	3.662	3.058	2.992	3.447	3.129	3.850	2.495	3.024	3.502
Sdc	2.08E+08	1.83E+08	1.78E+08	1.99E+08	2.13E+08	2.06E+08	1.97E+08	1.97E+08	2.21E+08	2.18E+08	1.85E+08	1.88E+08
NEP _{johnson}	3.820	4.018	4.037	3.888	3.798	3.830	3.891	3.883	3.736	3.754	3.980	3.944
NEP _{phonon}	4.095	4.070	4.004	4.072	4.111	4.078	4.056	4.038	3.913	3.939	4.010	4.018
NEP _{load}	1.910	1.789	1.725	1.854	1.952	1.886	1.831	1.818	1.893	1.897	1.753	1.767
NEP _{amp}	4.806	5.471	5.617	5.036	4.687	4.856	5.072	5.067	4.534	4.578	5.403	5.311
NEP _{det}	7.623	8.114	8.176	7.778	7.556	7.644	7.789	7.769	7.308	7.360	8.011	7.939
DQE	0.655	0.626	0.623	0.646	0.659	0.654	0.645	0.646	0.674	0.671	0.632	0.636
Vn(det)	15.9	14.8	14.6	15.4	16.1	15.7	15.4	15.3	16.1	16.1	14.8	14.9
Vn(total)	27.0	24.3	23.7	25.9	27.6	26.7	25.8	25.8	28.2	28.0	24.4	24.8

Symbol	Value	Value	Value	Value	Value	Value	Value	Value	Value
T0									
Vn									
Q									
NEP _{photon}									
Vbias									
Gain									
Detector ID	B4	А3	T2						
Pthermal	20.230	19.774	#VALUE!	Power as function of Temperature	P _{thermal} = [G	300/(1+β)][T	/0.3] ^β T evalu	ated from To	to Tb
Pelec+Q	20.230	19.774	#VALUE!	Electrical + Absorbed Power	P _e + Q = [V	$_{\rm bias}/(2R_{\rm L}+R_{\rm E})$	₃)] ² R _B + Q		
Tbolo	0.38189	0.38074	#VALUE!	Bolometer Temperature	Solve for Tb u	sing Newtonian	recursion such	that P _{thermal} =	P _e + Q
T/T0	1.273	1.269	#VALUE!		T/To = Tbo	lo/To			
Rbolo	5.21E+06	4.82E+06	#VALUE!	Bolometer Resistance	Rbolo = (Ro	o)exp[(∆/Tb) ¹	^{1/2}]		
Vbolo	7.19	6.76	#VALUE!	Voltage across Bolometer	Vbolo = [Vb	ias/(2R _L + R	_B)]R _B		
Ibolo	1.38	1.40	#VALUE!	Current through Bolometer	Ibolo = Vbia	$as/(2R_L + R_B)$			
Α	-5.33	-5.34	#VALUE!		A = (T/R)(d	R/dT) = -(1/2)	$2)[(\Delta/Tb)^{1/2}]$		
С	1.19	1.55	#VALUE!	Dynamic Heat Capacity	C = C300[(Γ/0.3) ^γ]			
G	292.2	289.3	#VALUE!	Dynamic Thermal Conductance	G = G300[(
Z/R	0.357	0.371	#VALUE!		Z/R = (I/V)(dV/dI) = [-1	- GTb/(P _e A)]	/ [1 – GTb/(P _e A)]
τ	3.273	4.278	#VALUE!	Electrical Time Constant		Z/R + 1)(1 +			
Sdc	2.09E+08	2.03E+08	#VALUE!	Electrical Responsivity at 0 Hz	Sdc = (1/2)	$[R_B/P_e]^{1/2}[1-$	- Z/R] / [1 + (Z/R)(R _B /2R _L)
						2 2	2 1/2		
NEP _{johnson}	3.804	3.848	#VALUE!	Johnson Noise Prior to Demodulation	NEP _{johnson} =	(4k(Tb) ³ G ²)/(P _e A ²)] ^{1/2}		
NEP _{phonon}	4.069	4.043	#VALUE!	Phonon Noise Prior to Demodulation	$=\{[(4kTo^2G)]$	s)(β+1)((T/To	$(2\beta^{-3}-1)]/[(2\beta^{-1})]$	+3)(T/To) ^β (($\Gamma/\text{To})^{\beta+1}-1)]\}^{1/2}$
NEP _{load}	1.894	1.842	#VALUE!	Johnson Noise from R _L Prior to Demod.	$NEP_{load} = [4]$	kTo/2R _L] ^{1/2}	2(Z/R)R _B Ibo	lo/[(Z/R) – 1]	
NEP _{amp}	4.775	4.935	#VALUE!	Amplifier Noise Prior to Demodulation	NEP _{amp} = V				
NEP _{det}	7.577	7.675	#VALUE!	Detector Noise after Demodulation	NEP _{det} = [2	NEP _{john} ² +NE	P _{phon} ² +2NEP	load 2+2NEPar	² _{np} ²] ^{1/2}
DQE	0.658	0.652	#VALUE!	BLIP Figure-of-Merit for Detector	DQE = NEF	P _{photon} ² / (NEF	P _{photon} ² + NEF	O _{det} ²)	
Vn(det)	15.9	15.6	#VALUE!	Voltage Noise of Detector After Demod.	Vn(det) = N	EP _{det} Sdc			
Vn(total)	27.1			Total Noise after Demodulation		NEP _{det} ² + NI	EP _{photon} ²] ^{1/2} So	dc	

Version	Issue Date	Sheet	Changes from Previous Version
SLW-FS 1	5/26/2005		Update to Current Format (from old format)
		Pixel	Update the Heat Capacity
		Mather Dark	Update the noise (noise from v.0 was not enter correctly)
SLW-FS 4	5/27/2005		
		BDA	BDA ID and Serial No.
			Added thermistor saturation voltages
			Declared D4 bad and removed it from medians
		Problem Channels	Add C1 and D4 on the list of noisy channel
		Pixel	Update the DQE
			Fixed QE requirements
			Update the 1/f knee (at sqrt(2) x flat noise)
			Fixed A3 DQE reference
			NEP derived from best of two noise data sets
		Mather Dark	Made final Vn and NEP depend on adjustable gain
		Mathan Ontical	
		Mather Optical	Corrected the optical loading and photon NEP values, reoptimized the bias
			Fixed A3 column references

Version notes 1/1 FS_SLW_EIDP_v4.xls

EIDP Coverpage For QM PLW BDA Unit Identfication QM PLW BDA Name Part # 10209800 -8 S/N #007 **Environmemtal Testing** Duration Axes or Number Tested Temperature of Cycles Pass/Fail Requirement Source Waiver # X, Y, Z at 90 K SSSD 2 min HR-SP-JPL 100 K RFW-006 Random Vibration Test X, Y, Z per axis 1 min per axis Sec # 3.4 SSSD HR-SP-JPL High Level Sine Vibe Test None NA NA NA X, Y, Z at 90 K Sec # 3.4 RFW-005 5 days as None (other than part of the as part of the assembly assembly Bakeout NA 80 C procedures procedure) D-20549 Min15 from RmT RoomT to Thermal Cycles NA ~ < 10 K 27 Ρ to < 77 K D-20549 Other Testing Minimum Frequency (Hz) Performance Source Waiver # Note SSSD Lowest Resonant > 200 Hz Cold (Goal: >250 Hz) Sec # 3.1.3 Frequency (X-axis) 283 Hz NA > 200 Hz Lowest Resonant SSSD 281 Hz Cold (Goal: >250 Hz) Frequency (Y-axis) Sec # 3.1.3 NA Lowest Resonant > 200 Hz SSSD Frequency (Z-axis) 276 Hz Cold (Goal: >250 Hz) Sec # 3.1.3 Metrology Measurements were performed before and after the Vibration Test and the Thermal Cycles Motion in Meets Performance Motion in Z Goal? X/Y Goal Source Waiver # Maximum motion due to Random Vibration Test 125 μm in X/Y SSSD and 500 µm in Z 1st axis (X) 21 μm 40 μm Υ Sec # 3.1.1 NA Maximum motion due to Random Vibration Test 125 μm in X/Y SSSD 2nd axis (Y) 22 μm 8.6 µm Υ and 500 µm in Z Sec # 3.1.1 NA Maximum motion due to Random Vibration Test 125 μm in X/Y SSSD and 500 µm in Z 3rd axis (Z) 9.5 μm 11 μm Υ Sec # 3.1.1 NA Cumulative Maximum 125 μm in X/Y SSSD Υ and 500 µm in Z motion 34 μm 56 μm Sec # 3.1.1 NA Cold Continuity Measurements: In Process Pass/Fail Requirement Waiver # Source Cold Continuity Test (1st Thermal Cycle) None NA NΑ Cold Continuity Test (2nd Thermal Cycle) None NA NA



ENVIRONMENTAL TEST AUTHORIZATION AND SUMMARY (ETAS)

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ENVIRONMENTAL TEST AUTHORIZATION AND SUMMARY (ETAS)

OTHER AUTHORIZATION PROVIS	SIONS AND EXPLANATIONS
This is a cold vibration test (<110 K) done on the Qual BDA. accelerometers will be mounted onto the suspended mass and fixture in order to provide redundant response measurements. before, in between, and after each axis.	force transducers will be mounted under the interface



ENVIRONMENTAL TEST ITHORIZATION AND SUMMARY (ETAS) ENVIRONMENTAL TEST SUMMARY

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HARDWARE	S/N	ETAS	TEST ENVIRONMENT LEVELS & DURATION	DATE TEST PERFORMED	TEST AGENCY	PASS/ FAIL	COMMENTS
HARDWARE Qual BDA (10209800-8)	S/N 7	HSO13	LATERAL 2 minute Random Vibe +3dB/octave 20-100Hz 0.06 g^2/Hz 100-138.5 Hz +36dB/octave 138.5-170 Hz 0.7 g^2/Hz 170-200 Hz -48dB/octave 200-220 Hz .1 g^2/Hz 220-300 Hz -9 dB/octave 300-2000 Hz Total Input: 8.0 Grms Spectrum to be notched in order to get 15 g's response RMS LONGITUDINAL 2 minute Random Vibe +3dB/octave 20-100Hz 0.08g^2/Hz 100-400Hz -12dB/octave 400-2000Hz Total Input: 6.2 Grms Spectrum to be notched in order to get 15 g's response RMS Each axis1/4 g sine sweep 20-2000 Hz each axisT ~ 100 K	PERFORMED	AGENCY	FAIL	COMMENTS



ENVIRONMENTAL TEST AUTHORIZATION AND SUMMARY (ETAS)

Particular Companies and Control of the Control of Cont	AUITURI	ZATION SECTION		
PROJECT			LOG NO.	
Herschel			HS017	<u> </u>
↑ TEMASSEMBLY TITLE S Qual BDA SN007				DATE ISSUED 9/2/2003
REFERENCE DESIGNATION NUMBER	PART NO. (IF MULTIPLE, AT 10209800	TACH LIST)	REV.	SERIAL NO.
HARDWARE TYPE			PRE-ENVIRONMENTAL INSPECTI	ON REPORT NUMBER (ATTACH IR)
	FLIGHT SPARE	OTHER		
WIRING HARNESS EM QUAL FLIGHT	∏EM ∭SE	PART NO.	REV.	SERIAL NO.
TEST DESCRIPTION (CHECK ALL APPLICABLE)			TYPE OF TEST	<u> </u>
☐ SINE VIBRATION ☐ PYROSHOCK ☐	ACOUSTIC EMC	OTHER	QUALIFICATION	FLIGHT ACCEPTANCE
☐ RANDOM VIBRATION ☐ THERMAL VAC. ☐	THERMAL ATMOSPHERE		PROTO FLIGHT	RETEST
WILL ALL TESTS/LEVES/DURATIONS REQUIRED BY TH	IE PROJECT DOCUMENTS BE			
YES NO (IF NO, ATTACH EX		ENTER PROJ. DOC. NO.	AND REV	
HAS THE UNIT PASSED ALL PRE-ENVIRONMENTAL FU				
YES NO (IF NO, ATTACH E		BRIEF EXPLANATION		
HAVE ALL DESIGN ANALYSES BEEN COMPLETED AND ☐ NO (IF NO, ATTACH EX		IMPLEMENTED? BRIEF EXPLANATION		
IS THE TEST ARTICLE IDENTICAL TO OTHER FLIGHT U	NITS?			- Marian et al.
YES NO (IF NO, ATTACH E)	XCEPTIONS LIST)	BRIEF EXPLANATION		
ARE ALL PFRS AGAINST THIS UNIT CLOSED?		PRICE EVEL ANATION		
YES NO (IF NO, ATTACH E)		BRIEF EXPLANATION		
HAVE ALL WAIVERS AND ECRS BEEN APPROVED AND		BRIEF EXPLANATION		
YES NO (IF NO, ATTACH E)				
OOONIZANIZ ENGINEED .~ DA	and the second of the second o	NUTHORIZED BY	DATE ENVIRONMENTAL REQ	UIREMENTS ENG. DATE
7.11	TECHNICAL MGR./INST	KINKGJPI PREP REP	DATE ENVIRONMENTAL REC	
Fille 10/9/	03 Moutin Ch	10-16	03 Hm (Hal	10/9/03
		ARY SECTION		
TEST AGENCY (IF MULTIPLE, ATTACH SUMMARY AND			ATED OPERATING HOURS PRIOR	TO FIRST ENVIRONMENTAL TEST
JPL Building 183	9/2/03			
				<u> </u>
SERIAL NUMBERS ACTUALLY TESTED	TEST TERMIN		NG HOURS DURING ENVIRONMENT	TAL EXPOSURE
SERIAL NUMBERS ACTUALLY TESTED	While	03	NG HOURS DURING ENVIRONMENT	AL EXPOSURE
	\(/\(\/\)	DESCRIPTION		
VIBRATION ACOUSTIC	TEST PYROSHOCK SHOCK	DESCRIPTION THERMAL VA	CUUM TEMPERATURE AT	
VIBRATION ACOUSTIC AXES: X Y Z	\(/\(\/\)	DESCRIPTION Z PRESSURE: <1E-5	CUUM TEMPERATURE AT	
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y	DESCRIPTION THERMAL VA	CUUM TEMPERATURE AT	
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	TEST PYROSHOCK SHOCK	DESCRIPTION Z PRESSURE: <1E-5	CUUM TEMPERATURE AT mbar, NO OF CYCLES:	MOSPHERE OTHER
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y	DESCRIPTION Z PRESSURE: <1E-5 290K to 7K	CUUM TEMPERATURE AT mbar, NO OF CYCLES:	MOSPHERE OTHER ATED DURATION (HRS.)
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS.	DESCRIPTION Z PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27	CUUM TEMPERATURE AT mbar, NO OF CYCLES:	MOSPHERE OTHER ATED DURATION (HRS.) h COLD:°c,h
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS.	DESCRIPTION Z PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL	MOSPHERE OTHER ATED DURATION (HRS.)
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. DIMENTAL TESTS?	DESCRIPTION Z PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT:°c,	MOSPHERE OTHER ATED DURATION (HRS.) h COLD:°c,h
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. DIMMENTAL TESTS? XCEPTIONS LIST)	DESCRIPTION Z PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS LIST PFR NOS. / Bi	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT: °c, HOT: °c, RIEF EXPLANATION	MOSPHERE OTHER ATED DURATION (HRS.) h COLD:°c,h
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. DIMENTAL TESTS? XCEPTIONS LIST) DINS COMPLETE? A COPY OF THE INSPECTION	DESCRIPTION Z PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS LIST PFR NOS. / Bi	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT:°c,	MOSPHERE OTHER ATED DURATION (HRS.) h COLD:°c,h
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. DIMMENTAL TESTS? KCEPTIONS LIST) ONS COMPLETE? A COPY OF THE INSPECTION D, ATTACH EXPLANATION)	DESCRIPTION Z THERMAL VAI PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS LIST PFR NOS. / BF	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT: °c, HOT: °c, RIEF EXPLANATION	MOSPHERE OTHER ATED DURATION (HRS.) h COLD:°c,h
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. DINMENTAL TESTS? XCEPTIONS LIST) DINS COMPLETE? A COPY OF THE INSPECTION D, ATTACH EXPLANATION) IEVED?	DESCRIPTION Z THERMAL VAI PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS LIST PFR NOS. / BF	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT: °c, HOT: °c, RIEF EXPLANATION	MOSPHERE OTHER ATED DURATION (HRS.) h COLD:°c,h
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VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. PRAD. EMIS. COMMENTAL TESTS? XCEPTIONS LIST) COMPLETE? A COPY OF THE INSPECTION COND. ATTACH EXPLANATION) IEVED? XCEPTIONS LIST)	DESCRIPTION Z THERMAL VAI PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS LIST PFR NOS. / BFI LIST PFR NOS. / BFI LIST PFR NOS. / BFI JIMMARY FOR ACTIONS TH	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT: °c, HOT: °c, RIEF EXPLANATION RIEF EXPLANATION	MOSPHERE OTHER ATED DURATION (HRS.) h COLD: °c, h h COLD: °c, h
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VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. DIMMENTAL TESTS? ACCEPTIONS LIST) ONS COMPLETE? A COPY OF THE INSPECTION D, ATTACH EXPLANATION) IEVED? ACCEPTIONS LIST) TED. SEE THE ATTACHED SU	DESCRIPTION Z THERMAL VAI PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS LIST PFR NOS. / BFI LIST PFR NOS. / BFI LIST PFR NOS. / BFI JIMMARY FOR ACTIONS TH	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT: °c, HOT: °c, RIEF EXPLANATION RIEF EXPLANATION RIEF EXPLANATION HAT NEED TO BE TAKEN.	MOSPHERE OTHER ATED DURATION (HRS.) h COLD: °c, h h COLD: °c, h
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. DIMENTAL TESTS? ACCEPTIONS LIST) ON ATTACH EXPLANATION) IEVED? ACCEPTIONS LIST) TECHNICAL MGR./INST	DESCRIPTION Z PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS LIST PFR NOS. / BI LIST PFR NOS. / BI LIST PFR NOS. / BI JIMMARY FOR ACTIONS THR MRG./PI PREP REP	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT: °c, HOT: °c, RIEF EXPLANATION RIEF EXPLANATION HAT NEED TO BE TAKEN. DATE ENVIRONMENTAL REQ	MOSPHERE OTHER ATED DURATION (HRS.) h COLD: °c, h h COLD: °c, h DATE
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. DIMENTAL TESTS? ACCEPTIONS LIST) ON ATTACH EXPLANATION) IEVED? ACCEPTIONS LIST) TECHNICAL MGR./INST	DESCRIPTION Z THERMAL VAI PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS LIST PFR NOS. / BE LIST PFR NOS. / BE JIMMARY FOR ACTIONS THE R MRG./PI PREP REP	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT: °c, HOT: °c, RIEF EXPLANATION RIEF EXPLANATION HAT NEED TO BE TAKEN. DATE ENVIRONMENTAL REQ	MOSPHERE OTHER ATED DURATION (HRS.) h COLD: °C, h h COLD: °C, h DUIREMENTS ENG. DATE
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. DIMMENTAL TESTS? ACCEPTIONS LIST) DIS COMPLETE? ACCOPY OF THE INSPECTION D, ATTACH EXPLANATION) IEVED? EXCEPTIONS LIST) TECHNICAL MGR./INST HE ENVIRONMENTAL TESTS L TECHNICAL MGR./INST	DESCRIPTION Z THERMAL VAI PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS LIST PFR NOS. / BE LIST PFR NOS. / BE JIMMARY FOR ACTIONS THE R MRG./PI PREP REP	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT: °c, C,	MOSPHERE OTHER ATED DURATION (HRS.) h COLD: °C, h h COLD: °C, h DUIREMENTS ENG. DATE
VIBRATION ACOUSTIC AXES: X Y Z SINE VIBRATION	PYROSHOCK SHOCK AXES: X Y SHOCKS/AXIS: COND. EMIS. RAD. EMIS. DIMMENTAL TESTS? ACCEPTIONS LIST) DIS COMPLETE? ACCOPY OF THE INSPECTION D, ATTACH EXPLANATION) IEVED? EXCEPTIONS LIST) TECHNICAL MGR./INST HE ENVIRONMENTAL TESTS L TECHNICAL MGR./INST	DESCRIPTION Z THERMAL VAI PRESSURE: <1E-5 290K to 7K NO OF CYCLES: 27 ISOLATION MAGNETICS LIST PFR NOS. / BE LIST PFR NOS. / BE JIMMARY FOR ACTIONS THE R MRG./PI PREP REP	CUUM TEMPERATURE AT mbar, NO OF CYCLES: TEMP. LEVEL (°c) AND ACCUMUL HOT: °c, C,	MOSPHERE OTHER ATED DURATION (HRS.) h COLD: °C, h h COLD: °C, h DATE TAKEN, INCLUDING RETEST. TUREMENTS ENG. DATE



ENVIRONMENTAL TEST AUTHORIZATION AND SUMMARY (ETAS)

OTHER AUT	THORIZATION PROVISIONS AND EXPLANA	TIONS
mal cycles will be performed on the	e BDA SN7 in order to fully qualify the de-	sign for flight.
mar cycles will be performed on the	BETTERN IN ORDER to LUMBY AND AND AND	



ENVIRONMENTAL TEST SUMMARY (ETAS) ENVIRONMENTAL TEST SUMMARY

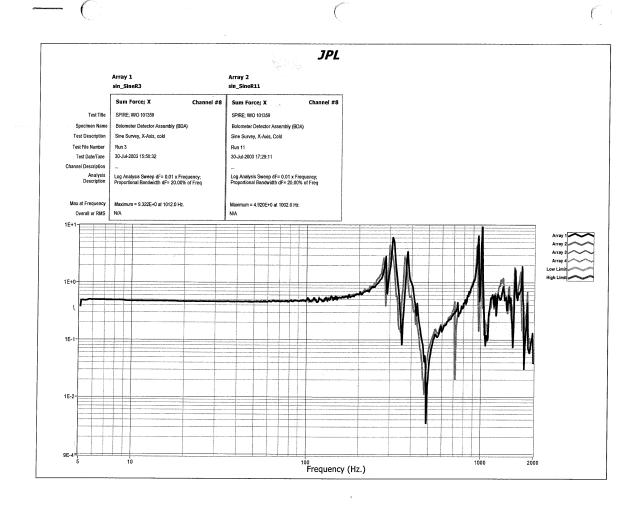
				TAL TEST SOM			
HARDWARE	S/N	ETAS	TEST ENVIRONMENT LEVELS & DURATION	DATE TEST PERFORMED	TEST AGENCY	PASS/ FAIL	COMMENTS
Qual BDA (10209800)	7	HSO17					
	-		27 Thermal cycles from 290K to 7K				
							-
						A Laboratory of	
		.1					
			÷.	:			

PAGE 3 JPL 2683 R 1/98 FF

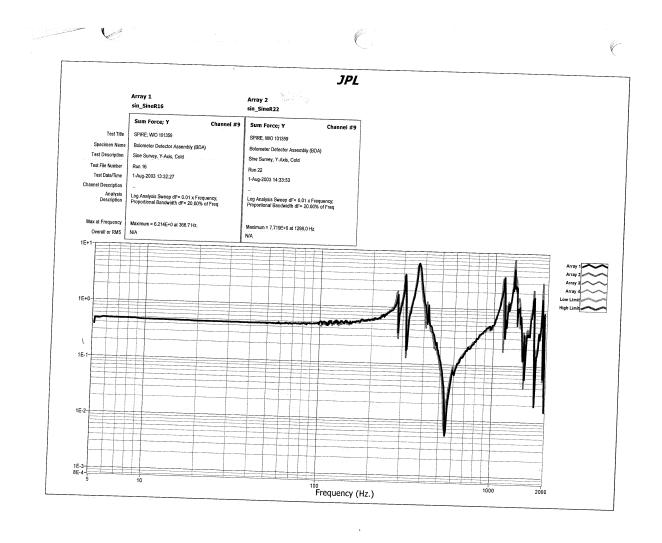
QM BDA Random Vibration Test

P/N 10209800-8 S/N 007

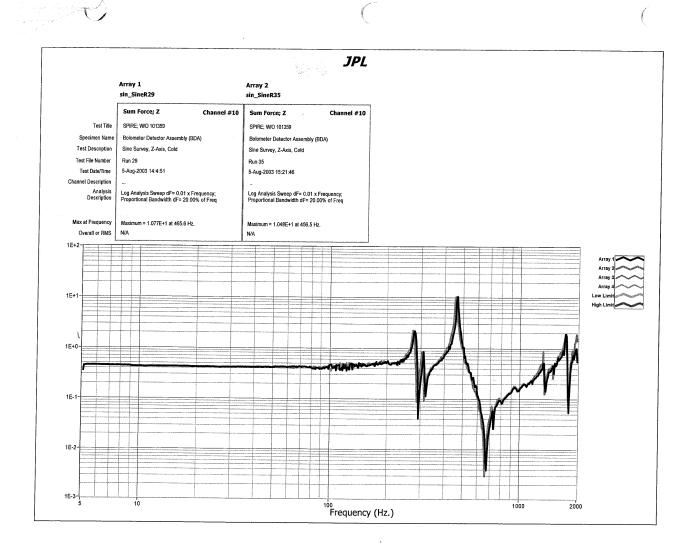
X-axis Shake, Cold, Sine Surveys (Before and After 0 dB Random Vibe)



Y-axis Shake, Cold, Sine Surveys (Before and After 0 dB Random Vibe)



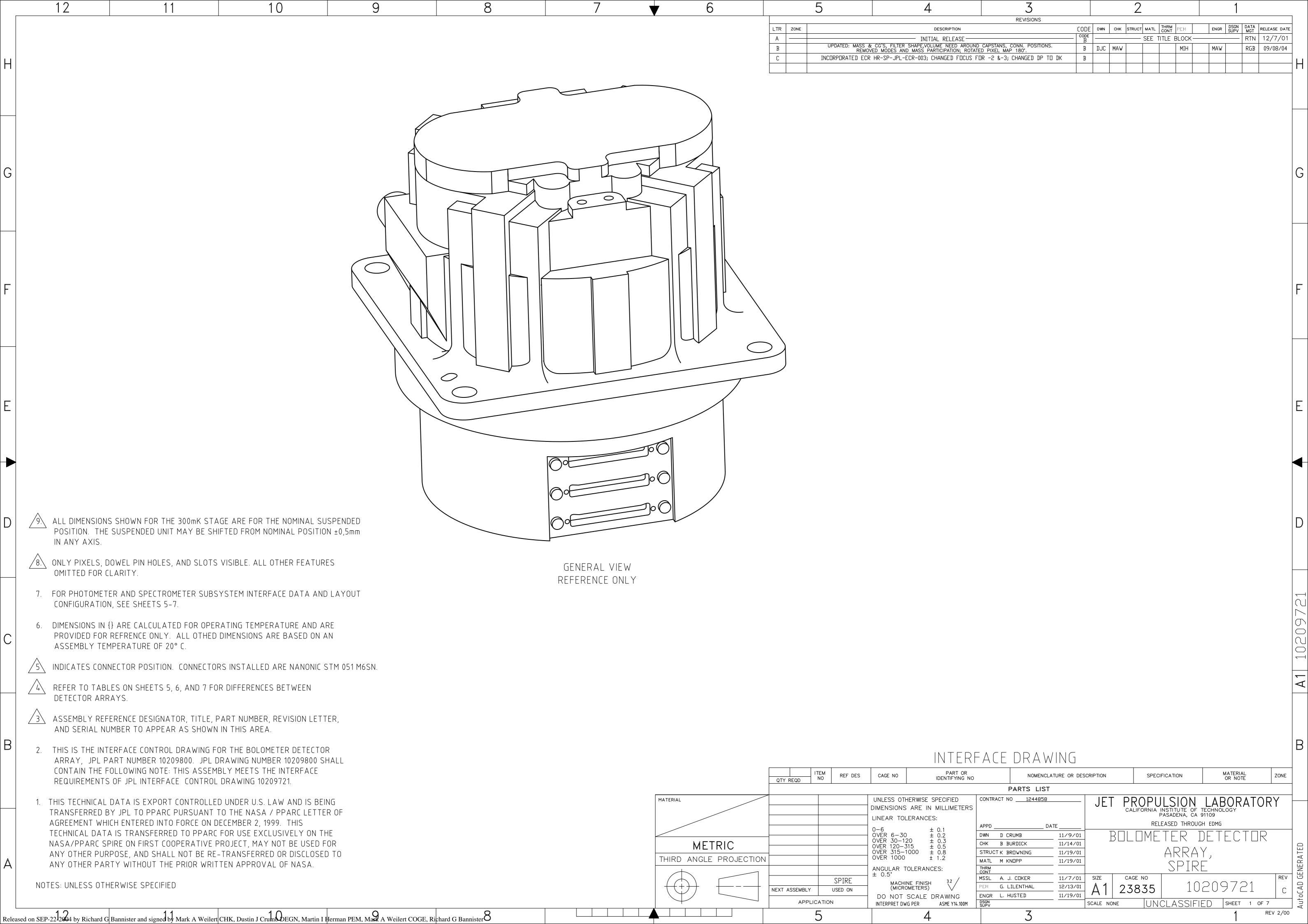
Z-axis Shake, Cold, Sine Surveys (Before and After 0 dB Random Vibe)

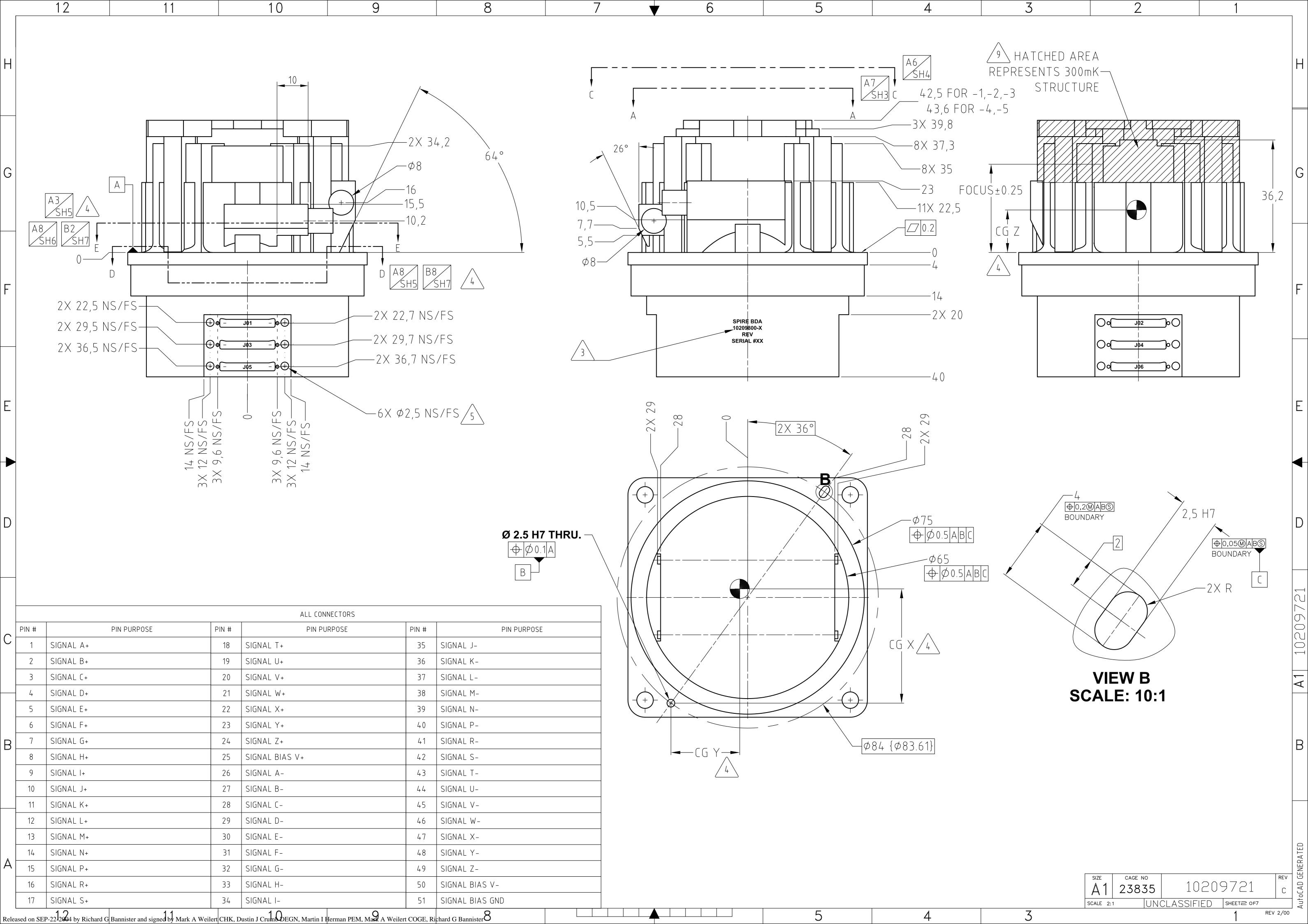


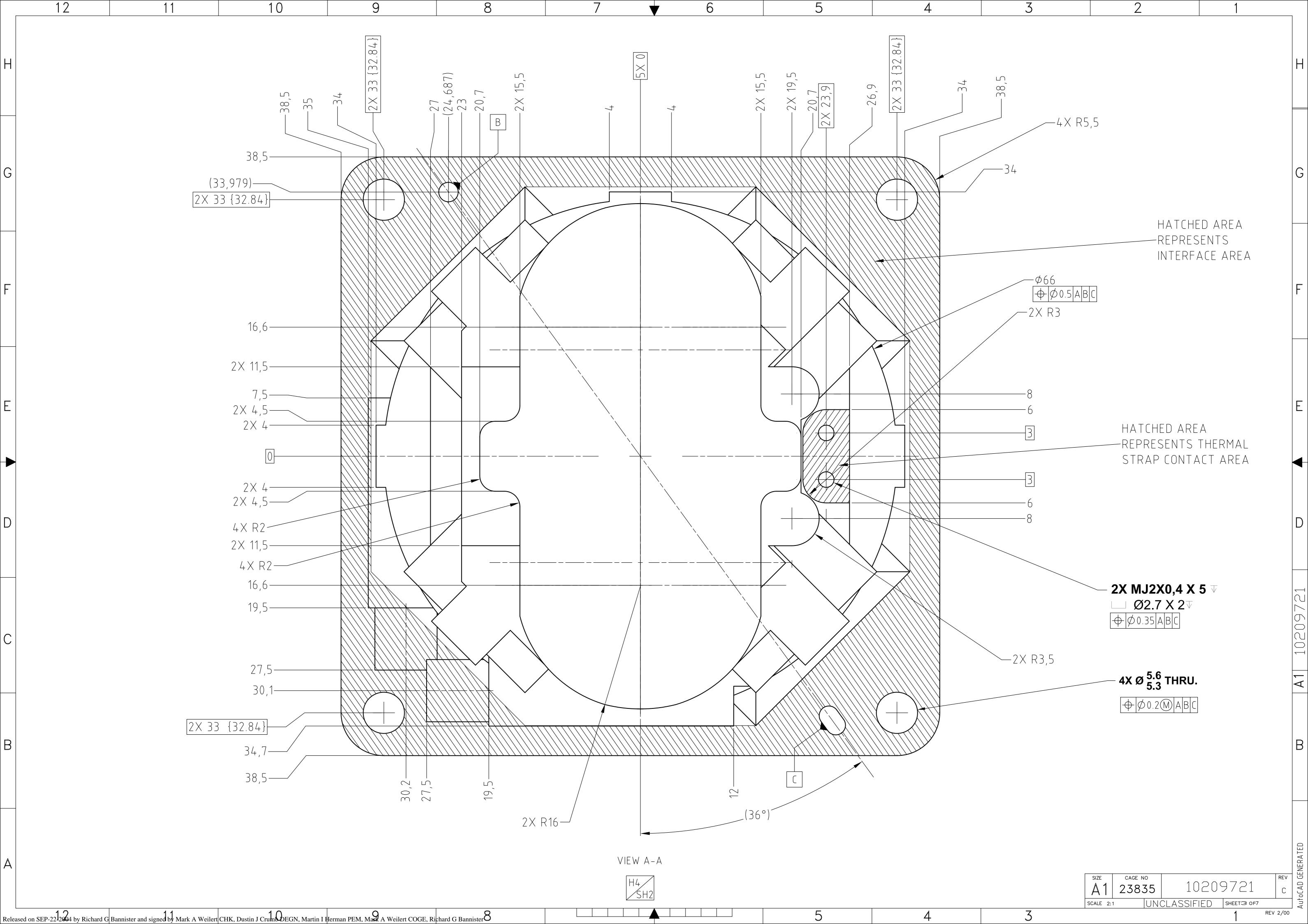
Date	Time	AIDS	Power	Mate	Demate	Transport	Notes
							Assembly Process Connector Mates
30-Sep-2004		243275		J05	J05		kapton cable sub-assembly test
9-Feb-2005		244743		J05	J05		kapton cable post-installation test
15-Feb-2005		244743		J05	J05		load resistor test
22-Feb-2005		244743		J05	J05		detector test
25-Feb-2005		244743		J05	J05		detector test, after feedhorn installation
							Assembly Complete
2-Mar-2005		244960		J05	J05		assembly complete electical test (pre-bakeout)
3-Mar-2005		244960				Х	103 -> MDL -> 103, for optical metrology
3-Mar-2005		244960					Filter installation
4-Mar-2005		244960				х	103 -> bld 158 for Vacuum Bakeout (80C, 24 hrs, 10^-5 torr)
7-Mar-2005		244960				х	bld 158 -> 170 -> 103 for metrology
7-Mar-2005		244960		J05	J05		post-bakeout, pre-vibe electrical test
7-Mar-2005		244960				х	103 -> 183 delivery to environmental test
7-Mar-2005		245002					Install into Shake facility
8-Mar-2005		245002				х	183->144 shake lab
8-Mar-2005		245002					pump out, go cold, complete 2 min 90K shake
8-Mar-2005		245002					warm overnight
9-Mar-2005		245002					complete warm low-level shake
9-Mar-2005		245002				х	144->183 for removal from shake facility
9-Mar-2005		245002				Х	183->170->103 for metrology
9-Mar-2005		245010		J05	J05		post-shake electrical test
10-Mar-2005		245010				х	103 -> 183 for performance test
10-Mar-2005		245015		J05			Installation in BODAC
10-Mar-2005		245015					pumpout
11-Mar-2005		245015					cooldown
interim			х				performance testing
29-Mar-2005		245015					finish warmup, vent
29-Mar-2005		245015					pump, cooldown

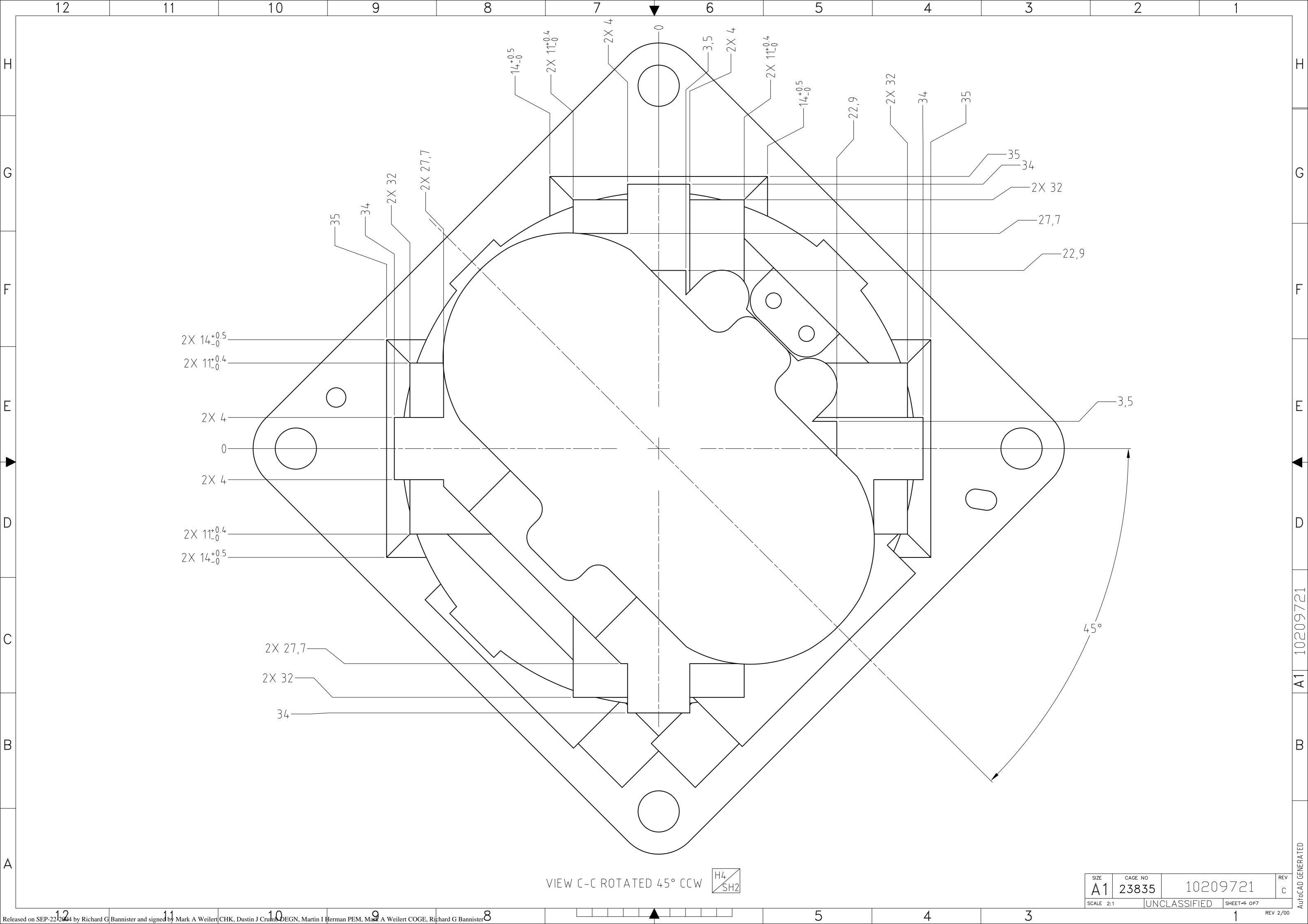
Hardware ID FS SLW BDA, 10209800-4 S/N 015

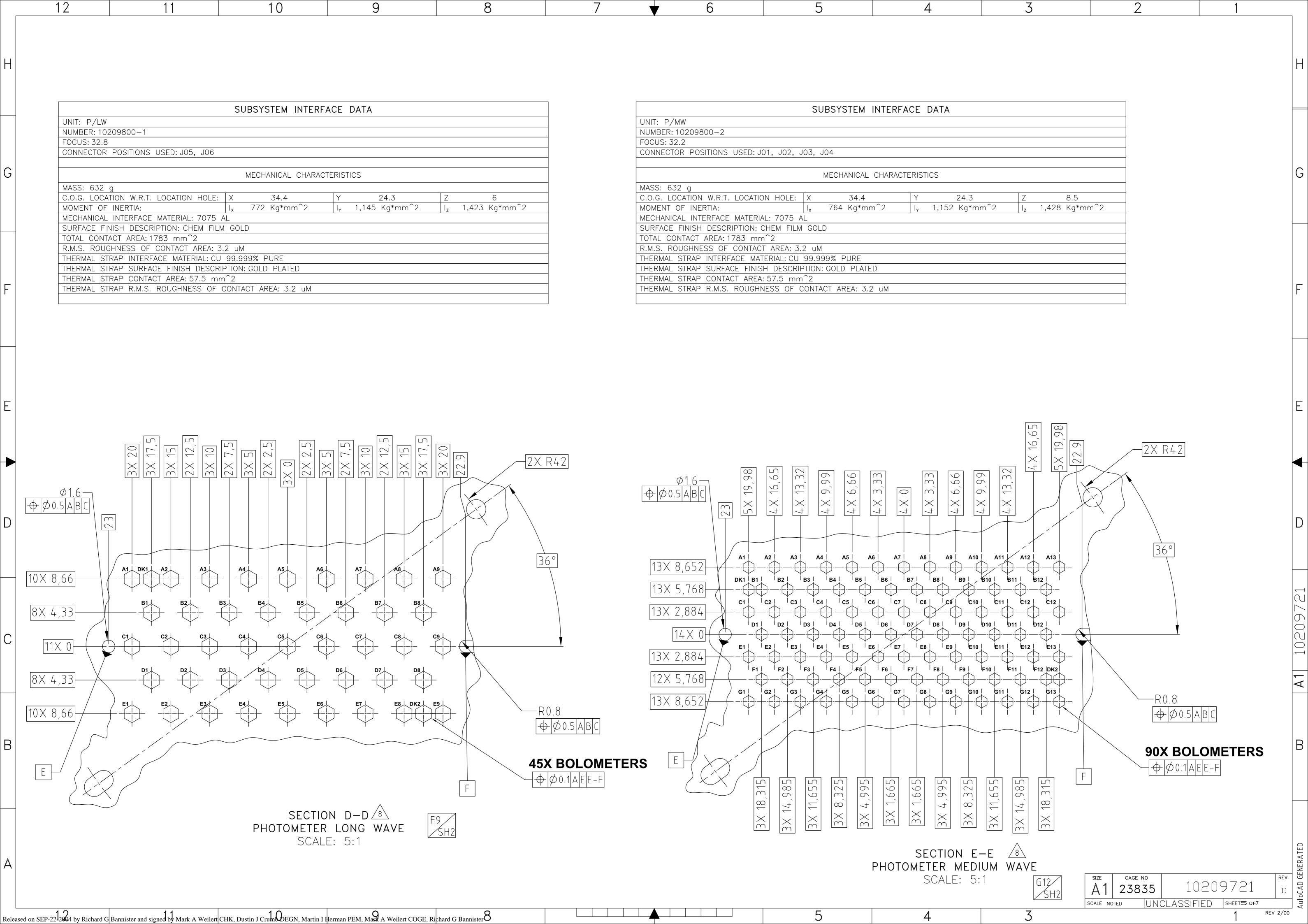
Date	Time	AIDS	Power	Mate	Demate	Transport	Notes
interim	_	_	х			•	performance testing
12-Apr-2005		245051					finish warmup
12-Apr-2005		245051					vent
12-Apr-2005		245051			J05		Removal from BODAC
18-Apr-2005		245284				Х	183 -> 103 for installation of temporary optical targets
19-Apr-2005		245141				Х	103->170->183 for post-BODAC metrology
19-Apr-2005		245141		J05			Install into Cold Alignment Facility for TS1, J05
19-Apr-2005		245141	х				Take continuity data.
19-Apr-2005		245141					pump out
20-Apr-2005		245141					Cooler on
21-Apr-2005		245141	х				Take continuity data.
21-Apr-2005		245141					Cooler off
25-Apr-2005		245141	х				Take continuity data.
25-Apr-2005		245141			J05		Remove from Cold Alignment Facility
25-Apr-2005		245141				Х	183->170->183 for metrology
25-Apr-2005		245145		J05			Install into Cold Alignment Facility for TS2, J05
25-Apr-2005		245145	х				Take continuity data.
25-Apr-2005		245145					pump out
26-Apr-2005		245145					Cooler on
27-Apr-2005		245145	х				Take continuity data.
27-Apr-2005		245145					Cooler off
28-Apr-2005		245145	х				Take continuity data.
28-Apr-2005		245145			J05		Remove from Cold Alignment Facility
28-Apr-2005		245145				Х	183->170->103 for metrolgy and storage
Aug-2005		245858		J05	J05		Pre-Ship electrical test (planned)

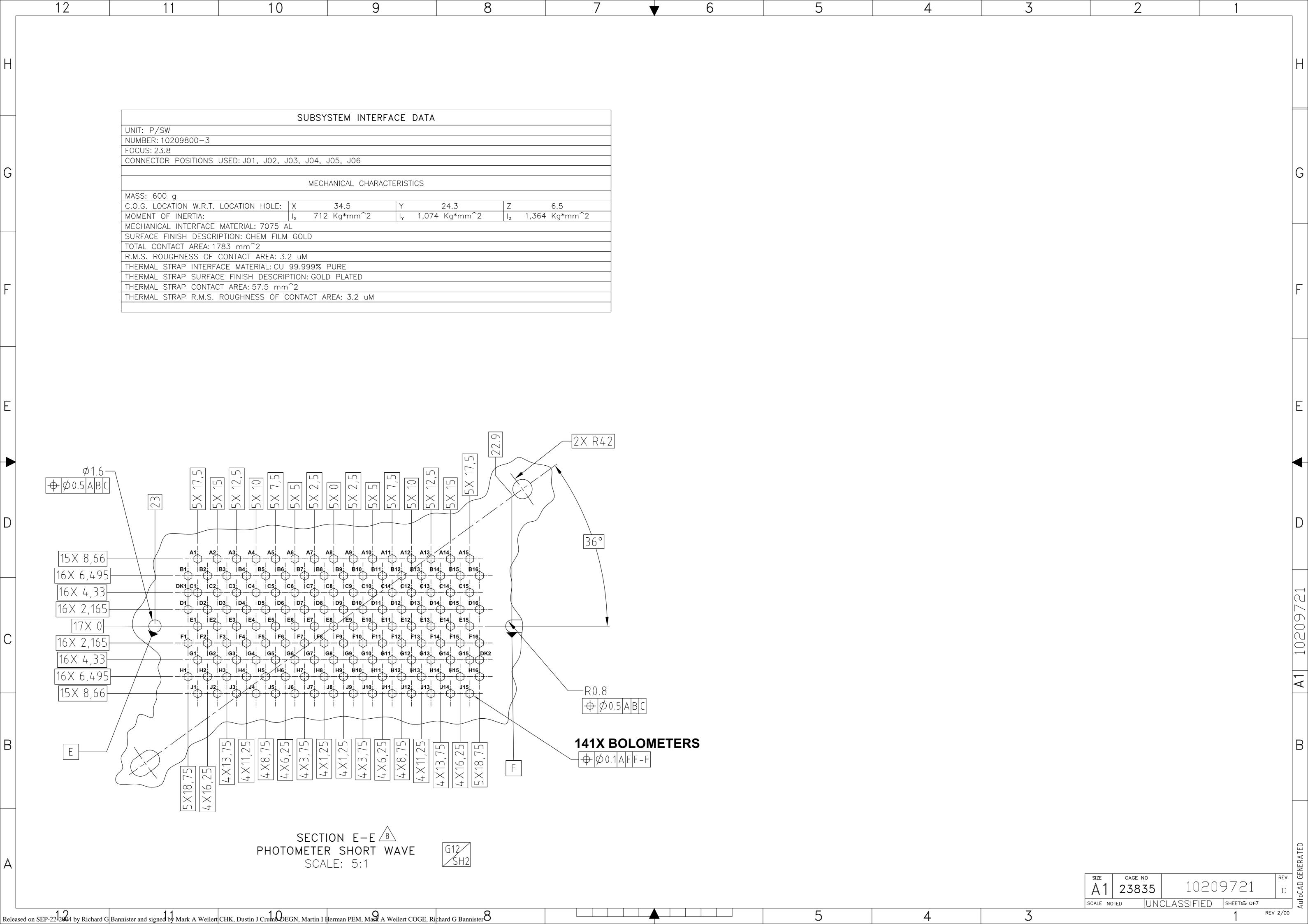


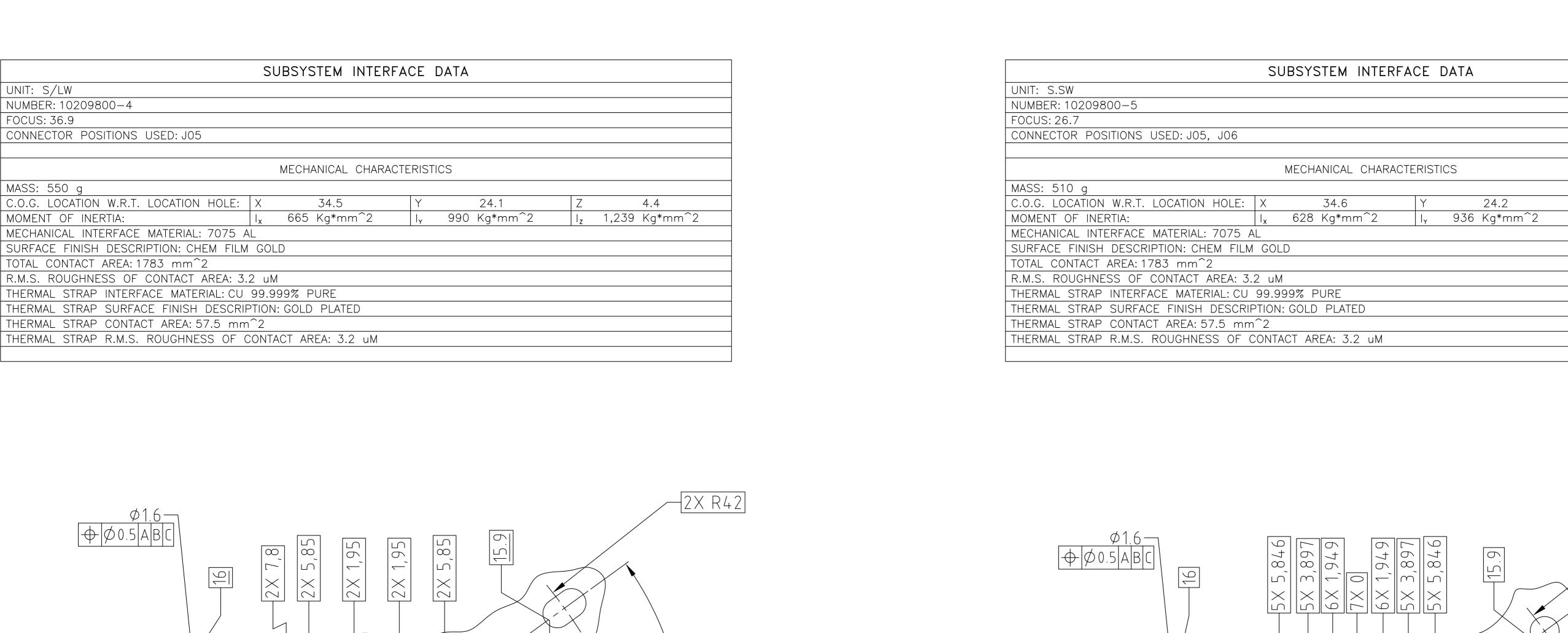








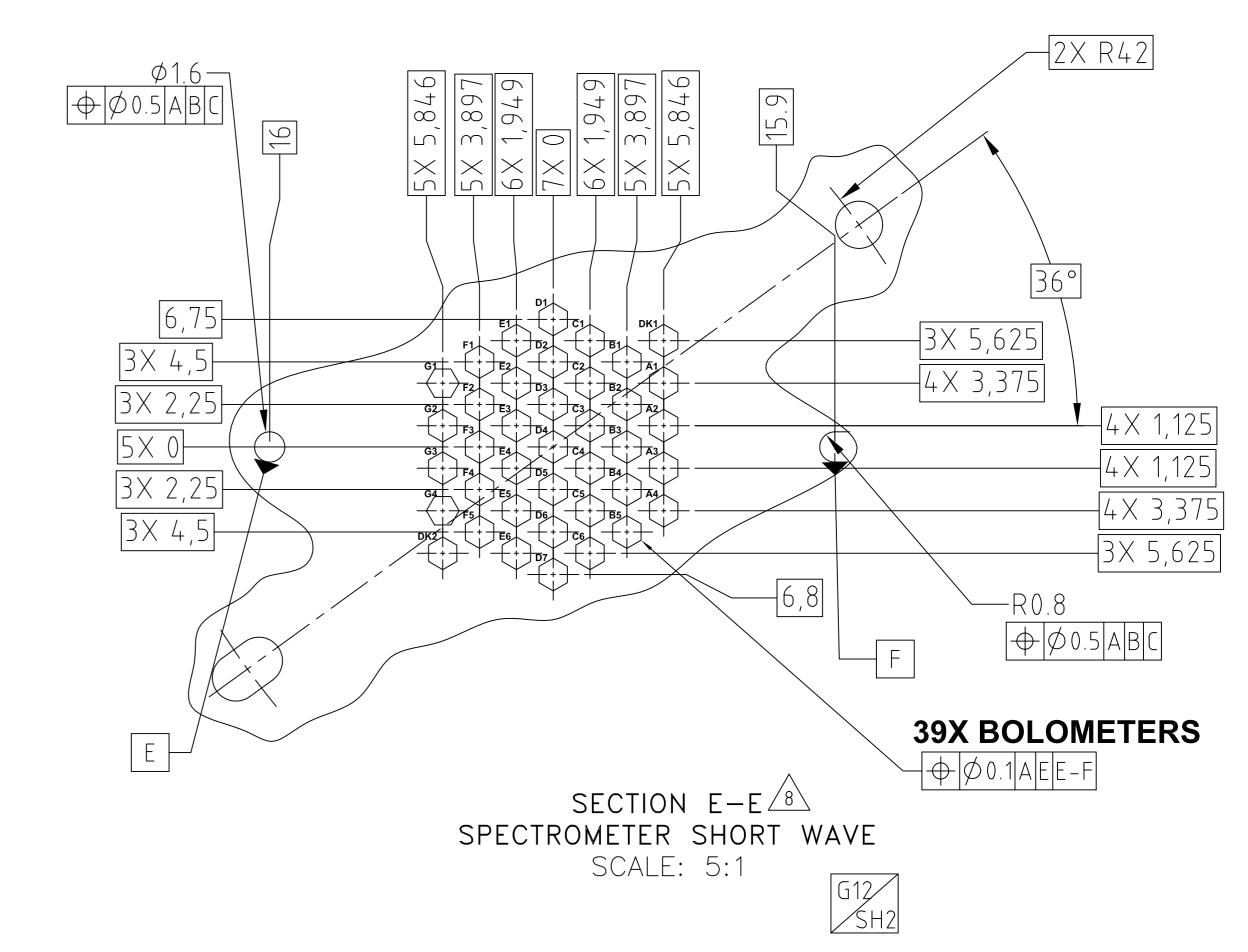


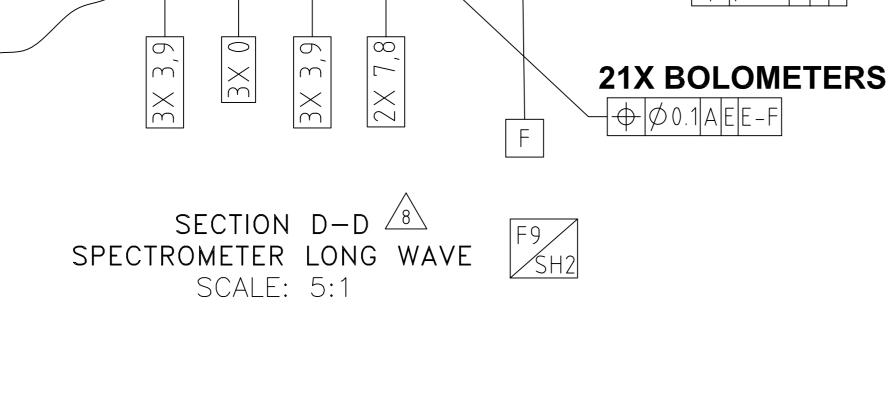


36°

-R0.8

6





SIZE CAGE NO 10209721 REV C

REV 2/00

Released on SEP-22 2004 by Richard G Bannister and signed by Mark A Weilert CHK, Dustin J Crum DEGN, Martin I Herman PEM, Mask A Weilert COGE, Richard G Bannister 8

4X 6,755

4 X 3,377

4X 3,377

4X 6,755

10

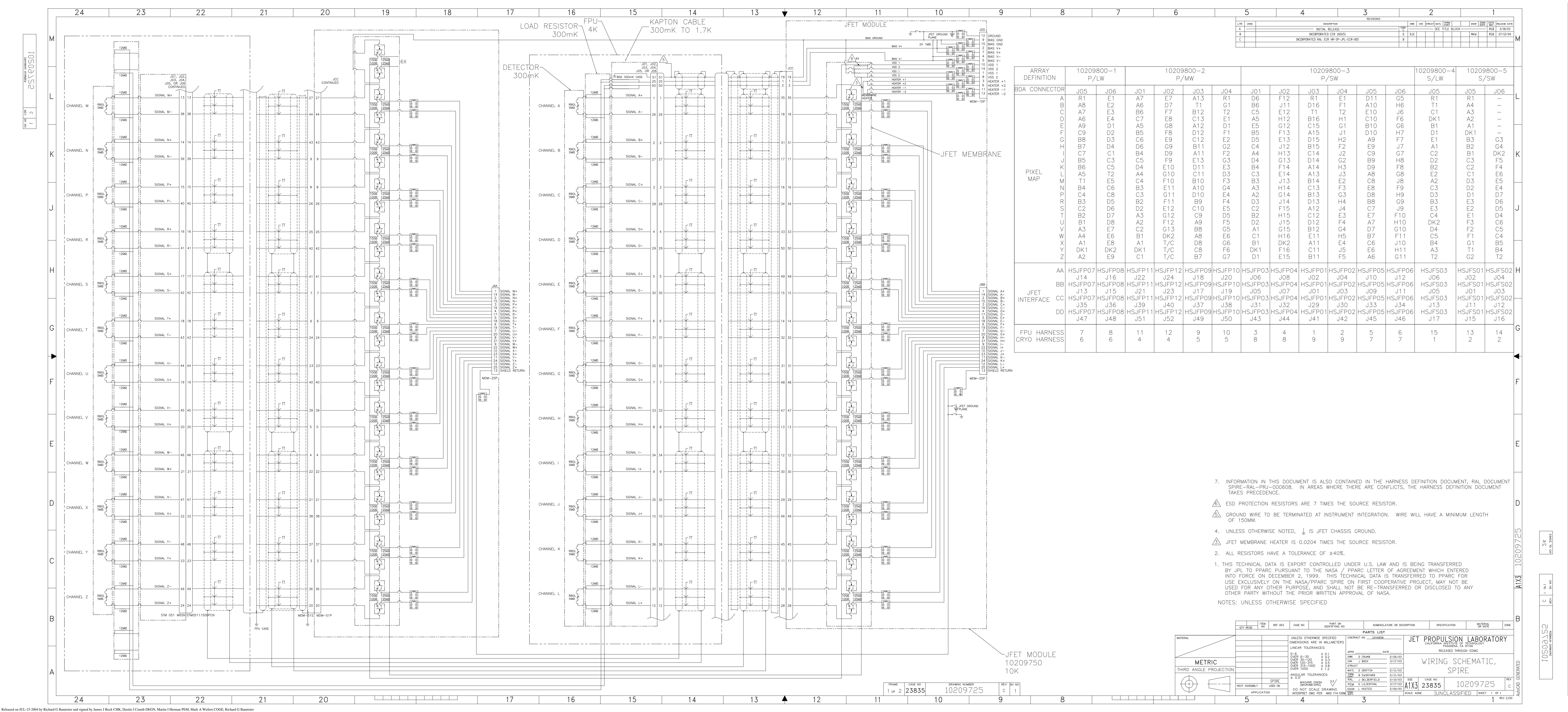
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3

SCALE 5:1 UNCLASSIFIED SHEET OF T

1,189 Kg*mm^2



SPIRE MIUL Cover Page

MIUL = Material Identification & Utilization List
Declared Materials List's and Processes List are not included in this HRCR

Materials and Processes List
Materials and Processes List
SPIRE
JPL D-25725
REV B
1/05/04
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10^{-1}
MIII
Reviewed by:
M. Knopp M&P Engineer

SPIRE Assembly Array/Backshort Assembly Travellei Revised by A Turner Dec 17,2004

nage 5

244558

AIDS:

Height measurements of Backshort to Detector to NTD chip

Device #	SLW 4.1	SLW BS 3.1
Date	16-Feb-05	
Collected by	A.Turner	
AIDS	244558	

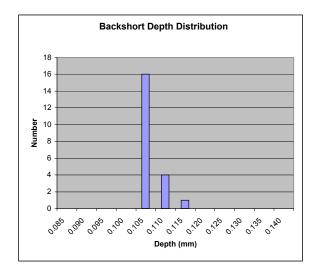
AIDS	244558	
Device	Thickness Measur	rements
Zero at	Measure at	Meas (mm)
1	1	0.0000
1	2	-1.0220
1	3	-1.0230
1	4	-1.0225
1	5	0.0000
1	6	-1.0230
1	7	-1.0260
1	8	-1.0255
1	9	-1.0265
1	10	-1.0275
1	11	-1.0250
1	12	-1.0275
1	13	-1.0295
1	14	-1.0335
1	15	-1.0360
1	16	-0.0010
1	17	-1.0295
1	18	-1.0335
1	19	-1.0380
1	20	-0.0020

Targets	mm	tol (mm)
Stack thick	1.0283	0.0465
NTD chip	0.0250	0.0100
BS dist	0.113	0.011

Stack Thi	ckness (mm)
	1.0280
Average	
max	1.0380
min	1.0220
p-p	0.0160
Backshort ⁻	Thickness(mm)
Average	0.9203
max	0.9200
min	0.9205
p-p	0.0005
Backshort	Distance (mm)
Average	0.1091
max	0.1160
min	0.1060
р-р	0.0100
NTD Chip	Thickness(mm)
Average	0.0314
max	0.0355
min	0.0260
p-p	0.0095

a= BS height
b= to web
c= NTD heig

		c= NTD heig	int					
Pillar Height Measurements								
Zero at	Pixel#	a (mm)	b(mm)	c(mm)	NTD chip (mm)	BS dist (mm)		
1	DK1	-0.9200	-1.0260	-1.0590	0.0330	0.1060		
1	A1	-0.9200	-1.0265	-1.0620	0.0355	0.1065		
1	A2	-0.9200	-1.0275	-1.0560	0.0285	0.1075		
1	A3	-0.9200	-1.0270	-1.0560	0.0290	0.1070		
1	T1		-1.0265	-1.0635	0.0370			
1	B1	-0.9200	-1.0285	-1.0575	0.0290	0.1085		
1	B2	-0.9200	-1.0275	-1.0615	0.0340	0.1075		
1	B3	-0.9200	-1.0270	-1.0585	0.0315	0.1070		
1	B4	-0.9205	-1.0280	-1.0570	0.0290	0.1075		
1	T2		-1.0280	-1.0600	0.0320			
1	C1	-0.9205	-1.0280	-1.0600	0.0320	0.1075		
1	C2	-0.9205	-1.0285	-1.0600	0.0315	0.1080		
1	C3	-0.9200	-1.0285	-1.0545	0.0260	0.1085		
1	C4	-0.9200	-1.0290	-1.0605	0.0315	0.1090		
1	C5	-0.9200	-1.0310	-1.0655	0.0345	0.1110		
1	D1	-0.9205	-1.0290	-1.0590	0.0300	0.1085		
1	D2	-0.9205	-1.0290	-1.0590	0.0300	0.1085		
1	D3	-0.9205	-1.0295	-1.0600	0.0305	0.1090		
1	D4	-0.9205	-1.0330	-1.0665	0.0335	0.1125		
1	E1	-0.9205	-1.0305	-1.0620	0.0315	0.1100		
1	E2	-0.9205	-1.0320	-1.0665	0.0345	0.1115		
1	E3	-0.9205	-1.0335	-1.0655	0.0320	0.1130		
1	DK2	-0.9205	-1.0365	-1.0695	0.0330	0.1160		



SPIRE Assembly Array/Backshort Assembly Traveller Revised by A Turner Dec 17,2004

				Keviseu by	A Tuillei L	Jec 17,20	U 4				0
Backshor	t Distance	after Asse	embly (in n	nm)						page of	6 7
Device		41101 71000	.	,	SLW	<i>l</i> 4.1				- Ci	
Date					02/1	6/05					
Ву					A.Tu						
AIDS					244	558					
	DK1 0.106		A1 0.1065]	A2 0.1075		A3 0.107				
T1		B1 0.1085		B2 0.1075]	B3 0.107		B4 0.1075		T2	
	C1 0.1075		C2 0.108]	C3 0.1085		C4 0.109		C5 0.111]	
		D1 0.1085		D2 0.1085]	D3 0.109		D4 0.1125			
			E1 0.11]	E2 0.1115		E3 0.113		DK2 0.116]	
BS Ran Low High	ge (mm) 0.102 0.124			BS Dist to Average Max Min p-p	0.1091 0.1160 0.1060 0.0100		Stack Thic Average Max Min p-p	1.0280 1.0380 1.0220 0.0160		BS Thickr Average Max Min p-p	ness (mm) 0.9203 0.9200 0.9205 0.0005

Detector Front Short Gap

	FH-SLW 10209843-1 SN02 Hex									
	xaxis									
yaxis	0.000	-6.250	-12.500	-18.750	-25.000	-31.250	-37.500			
0.000	0.000	0.004	0.007	0.009	0.012	0.012	0.011			
-4.467	0.001	0.007	-1.805	-1.805	-1.799	0.016	0.016			
-8.933	0.003	0.007	-1.808	-1.804	-1.800	0.016	0.020			
-13.400	0.003	0.005	-1.809	-1.805	-1.801	0.014	0.020			
-17.867	0.002	0.005	-1.809	-1.806	-1.800	0.015	0.018			
-22.333	0.001	0.005	-1.809	-1.805	-1.801	0.014	0.014			
-26.800	0.002	0.005	0.006	0.009	0.013	0.012	0.012			

ope C	orre	cte	d
-------	------	-----	---

	xaxis						
yaxis	0.000	-6.250	-12.500	-18.750	-25.000	-31.250	-37.500
0.000	0.000	0.002	0.004	0.004	0.005	0.003	0.000
-4.467	0.000	0.005	-1.808	-1.810	-1.806	0.007	0.005
-8.933	0.003	0.004	-1.812	-1.810	-1.807	0.006	0.009
-13.400	0.002	0.003	-1.813	-1.811	-1.808	0.004	0.009
-17.867	0.001	0.003	-1.813	-1.811	-1.807	0.006	0.006
-22.333	0.000	0.002	-1.813	-1.811	-1.808	0.004	0.002
-26.800	0.001	0.002	0.002	0.002	0.005	0.002	0.000

ave = max = min = p-p = -1.810 -1.806 -1.813 0.007

	cp16-SN010-SLW 4.1-SLWBS3.1 clipped in							
	xaxis							
yaxis	0.000	-6.250	-12.500	-18.750	-25.000	-31.250	-37.500	
0.000	0.000	2.992	2.994	2.994	2.993	2.990	-0.003	
4.467	n/a	1.968	1.965	1.965	1.966	1.969	n/a	
8.933	n/a	n/a	1.964	1.963	1.963	n/a	n/a	
13.400	n/a	n/a	1.962	1.959	1.959	n/a	n/a	
17.867	n/a	n/a	1.961	1.956	1.955	n/a	n/a	
22.333	n/a	1.963	1.957	1.953	1.950	1.950	n/a	
26.800	-0.003	2.551	2.554	2.555	2.555	2.553	-0.009	

Slope Corrected

	xaxis						
yaxis	0.000	-6.250	-12.500	-18.750	-25.000	-31.250	-37.500
0	0.000	2.992	2.994	2.995	2.995	2.992	0.000
-4.467	#VALUE!	1.969	1.966	1.967	1.968	1.972	#VALUE!
-8.933	#VALUE!	#VALUE!	1.965	1.965	1.966	#VALUE!	#VALUE!
-13.400	#VALUE!	#VALUE!	1.964	1.962	1.961	#VALUE!	#VALUE!
	#VALUE!	#VALUE!	1.963	1.959	1.958	#VALUE!	#VALUE!
-22.333	#VALUE!	1.965	1.959	1.956	1.953	1.954	#VALUE!
-26.800	0.000	2.554	2.557	2.559	2.559	2.557	-0.004

1.963 ave = max = 1.972 min = p-p = 1.953 0.018

Coverplate SN	cp-16 SN010
Feedhorn SN	SLW SN02
Detector SN	SLW 4.1
Backshort SN	SLW BS 3.1
SLW FS	0.158
SLW FS tol	0.054
SLW BS	0.113
SLW BS tol	0.011

Front short Estimation GAP

OA!							
yaxis	0.000	-6.250	-12.500	-18.750	-25.000	-31.250	-37.500
0.000	0.000						0.000
-4.467			0.158	0.157	0.162		
-8.933			0.153	0.156	0.159		
-13.400			0.151	0.151	0.153		
-17.867			0.150	0.148	0.151		
-22.333			0.147	0.145	0.145		
-26.800	0.001						-0.004

ave =	0.152
max =	0.162
min =	0.145
p-p=	0.017

Alignment Measurement Summary

for FS SLW BDA 10209800-4 SN015

WARM ALIGNMENT MEASUREMENTS:

Position:

Center of feed horn entrance plane with respect to the alignment pin hole, mounting face and alignment slot as defined in the ICD drawing 10209721 sht. 3 (see Figure 1 below)

$$(x,y,z) = (24.756, -33.673, 36.852)$$
 (all distances in mm)

Nominal x,y position:

$$(x_{nom}, y_{nom}) = (24.687, -33.979)$$

x-y shift from nominal:

$$(dx,dy) = (0.069, 0.306)$$

The z position of the suspended part referenced to the 34.2 mm nominal dimension on ICD pg 2, zone G9:

Measured z dimension:

34.300 mm

Z shift from nominal

0.100 mm

Rotation:

Feed horn rotation in xy plane (top view, as in ICD, sht. 3)

0.081° counterclockwise

Normal vector to feedhorn entrance plane:

(-0.00389, 0.01095, 0.99993)

which is 0.666° from the z direction.

COLD ALIGNMENT MEASUREMENTS:

(BDA cooled from RmT to approximately 7-8 K)

Shifts on Cooling:

XY Shift of center of 300 mK stage on cooling (with respect to flange alignment pin hole):

$$(dx, dy) = (-0.13, 0.13)$$

300 mK stage rotation in xy plane on cooling (top view):

$$|\theta|$$
 < 0.04° (not repeatable, values scattered below this limit)

The suspended portion of the BDA shifted approximately 0.06 mm down in the z axis on cooling, moving closer to the mounting flange. The rotation about the x-axis on cooling was measured as -0.09° (+y end moving down toward mounting plate), but this did not recover on warming, so the repeatability is in question. We have no information about rotation in the y axis on cooling.

These shifts are not accurate to better than ± 40 microns, and the repeatability over multiple cooldowns is not well known.

Net Result:

xy cold position of the feedhorn center relative to alignment pin hole:

$$(x, y) = (24.63, -33.54)$$

Rotation of feedhorn relative to xy axes (top view) is nominally 0.08° ccw, \pm roughly 0.04° .

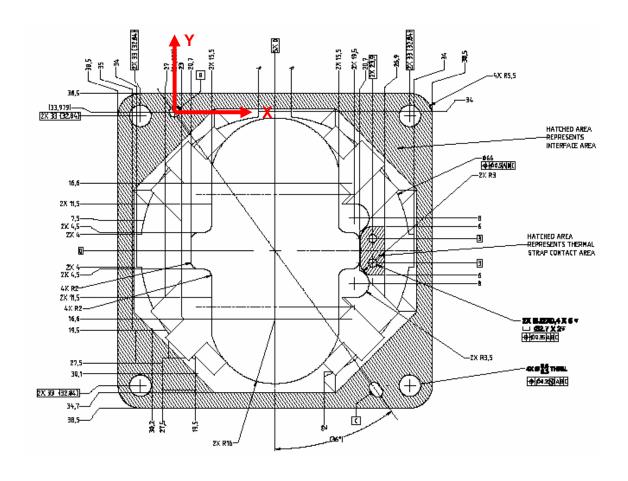


Figure 1 (excerpt from ICD dwg 10209721, with coordinate axes shown)



Custom Microwave Inc. 940 Boston Avenue Longmont, CO 80501

CERTIFICATE OF COMPLIANCE

JPL	1248788				
CUSTOMER	PURCHASE ORDER NUMBER				
3609	10209843				
INVOICE NUMBER	PART NUMBER(S)				
P8647	1 EA.				
LOT NUMBER(S)/SERIAL	QUANTITY				

Custom Microwave, Inc. certifies that all materials and processes used in the manufacturing of supplied parts conforms in all respects to the above mentioned purchase order, specification and/or drawing requirements and that documents are on file to substantiate this and are available for examination. Custom Microwave, Inc. further certifies that no parts supplied against this purchase order contain mercury or have come in contact with mercury or mercury compounds nor do they contain beryllium or beryllium compounds except beryllium copper.

Authorized Signature
Quality Assurance Manager

07/22/03

Date

CMI CAGE CODE: 5Y549

MATERIALS:

COPPER C101 HOUSING: RM#954

BRASS WIRE RM# 1200 SN96 SOLDER: RM#1183

PROCESSES:

COPPER ELECTROFORM CMI COPPER # 3
GOLD PLATE PER MIL-G-45204, TYPE 3, CLASS 1, GRADE A

NCR # 12265 attached

Order No.

Hem

1以 日

Spec. Value

規格値

ample No.

III HNo.

Quench Test

Manufacturring No.

製造番号

91V1897

TMX DIVISION/MILWAUKEE

DIMENSION AND PHYSICAL PROPERTY 寸法と物理的性質

Out. Dia.

外 径

(IN)

+0. 0025

-0. 0025 PASSED

H2 Embrittlement Test (水素ぜい化試験)

MICROSCOPIC BLISTER MACRODEFECT

Dimension 寸法

(はく離試験)

REPEATED BENDING Min (10) 12.0

Article

(UNS C10100)

Yield Strength

. 2 ¥Offset

耐力

ks I ※

37. 0

41. 9

VISUAL INSPECTION (かイカン ケンサ) GOOD

Max. Max. Max.

HITACHI CABLE, LTD.

Pb Zn Bi Cd O

Min.

Max.

C10118D-H

Elongation

伸び

(x)

16

23

Bend Test

Max. Max.

AT-279 (TOC-279) *TMXP/ONO. 745977/136776-2 検査成績 装

Tension Test 引張試験

Min.

Max.

Tensile Strength

引張り強さ

k s l ※

Min.

Max.

PASSED

Specification

Length

長さ

(N)

12FT

PASSED

SP73-14-1104E

ASTM-F-68-93

2' -12FT

Hardness

Test

硬さ試験

77. 0

81.0

REMARK: MATERIAL IS FREE FROM MERCURY

Max.

15

Max. Max.

Max

TSUCHIURA WORKS

HRF

Min.

Max.

(曲げ試験)

Size

Size

结晶粒度

Min.

Max.

Electric

Conductivity

建加率

at 20°C

(X)

101. 0

101.8

Expanding Test

Max.

Electric

電気抵抗

at 20°C

 Ω mmi/m

Max.

Eddy Current Test (渦流探傷試験)

Flattening Test (偏平試験)

Max. Max.

5

Resistivity Pressure Test

(押し拡げ試験)

Max. Max.

0.5 10

Se Te Sb As Fe Mn Ni Ag Sn

10

*B-5003

00/01/28

Quantity Delivered

納入数量

3, 688. 4 LBS

(01)

%1ks1=1000Lb/In2

Manager Quality Assuranca Dept.

Max.

25

Date 日付

Quantity Ordered

注文数量

4, 000. 0 LBS

水圧試験

Mpa

Min.

CHEMICAL	COMPOSI	TION
	化学成分((X)
Element 成分	Cu +	
Specified Value	Min.	
規格額	99. 99	~
Measured Value		
測定鏡	99. 99	
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130		
17	SHI	PER
	BY	
1		775

CUSTOMER P.O

sum of Test Report Customer PO proby certify that this represents materials

on the above order

" Crass Sales, Inc.

EIS Phoenin 1524 West 14th Street Suite 106 TEMPE AZ 85281 USA

Sold TOCUSTON MICRONAVE, INC 940 BOSTON AVE LONGKONT CO 80501 USA·

Facking List # 264304 Cust. Phone: 3036510707 | Page: 27

Ship Totuston Micronave, INC 940 BOSTON AVE LONGKONT CO 80501 USA

Date: 04/22/02 00:46:23

CUSTOMER ORDER NO	<u> 4 </u>	zeri di nganananan				PCS.	WT.	BILL OF LADING	
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FRT PPD & CHG			. Ph	one #:3(04/22/0	SALESMAN	99944	PICKED BY	DATE
					r	V 2:	99944) કર્ણામળામુકિર્દ	
CATALOG	COLOR: PU	DESCRIPTION JT UP:		M	QUANTITY ORDERED	QUANTITY SHIPPED	QUANTITÝ BACK ORDEF		
1965W.031				LB	2.00	7	0.0		
2306B \	SOLDER, SO	DLID WIRE,	. SN96 . 3AG	3.2.1		(
					4.74.7	トンン	· •	1750000	
***		***	****	* * * * *	* * * * * * * * * *	* * * * * * *	· * * * * * * * *		
* PRODUCT	*****	CERTIFT	CATE OF	* * * * * CÓNFO:	********* RMANCE	DIRECTLY	ABMUE	* 7	
* PRODUCT	SHIPPED	********* CERTIFT ON THIS E	CATE OF CO. NOME:	* **** CONFO: ER', I	* * * * * * * * * *	DIRECTLY R S SPECI	ABOVE FICATIONS	*	
- AERE MA	SHIPPED UFACTURES	CERTIFT CERTIFT ON THIS F O IN CONF	******** CATE OF CO. NUMBI DEMANCE W	* * * * * * CONFO: ER , I: I' TH M	********** RMANCE DENTIFIED I ANUFACTURE	R S SPECI		* * * * * * * * * * * * * * * * * * * *	
- AERE MA	SHIPPED UFACTURES	CERTIFT CERTIFT ON THIS F O IN CONF	******** CATE OF CO. NUMBI DEMANCE W	* * * * * * CONFO: ER , I: I' TH M	********* RMANCE DENTIFIED 1	R S SPECI		* * * * * * * * * * * * * * * * * * * *	
- AERE MA	's SHIPPED HUFACTURES	CERTIFT ON THIS F O IN CONFC	CATE OF CATE O	***** CONFO ER, I ITH M	********** RMANCE DENTIFIED 1 ANUFACTURES ENTS ANA	S SPECI	FICATIONS	* * * * * * * * * * * * * * * * * * * *	
* WERE MA * Sign	's SHIPPED HUFACTURES (ature / Ti	******** CERTIFI ON THIS F O IN CONFO itle: ot/Batch N	CATE OF CATE O	***** CÓNFO ER, I I'TH M	RMANCE DENTIFIED DANUFACTURED LEWIS ANA	S SPECI		* * * * * * * * * * * * * * * * * * * *	
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100 May 100 Ma EDM Supplies, Inc. 9806 Everest Street

Downey, CA 90242-3199 Phone: 562-803-6563

Fax: 562-803-4281

SHIPPER

Sales Order Number Shipper Number Ship Date Page

250913 06/28/02

S 103884 O CUSTOM MICROWAVE L 940 BOSTON AVE D LONGMONT CO 80501

103884 CUSTOM MICROWAVE 940 BOSTON AVE LONGMONT CO 80501

	DOWNEY		Terms: NET 3	0		Freight: PRE	PAID ANI	D ADD
Custor	mer's PO:	1255	37		R	esale No:		
.1#	Order/Qty	UM	Part/Description		Units/Pkg	Ship Qty	Lc	t Number
1	10	EA	C22-023 .023 DIA. X 12 PBR	Rm 1200		5		C
2	10	EA	C22-024 .024 DIA. X 12 PBR	Rm [20]		10		. 0
5	10		C22-027 .027 DIA. X 12 PBR *****CERTIFICATION WE HEREBY CERTIFY MATERIAL TO BE PRE BRASS ROD ALLOY 26	S***** THIS CISTON		4		C
,			SIGNED: 7 WWW JON ORDERED BY DAN JON	Wreau				
		0.0000000000000000000000000000000000000						

SHIP TO: CUSTOM MICROWAVE 940 BOSTON AVE LONGMONT CO 80501

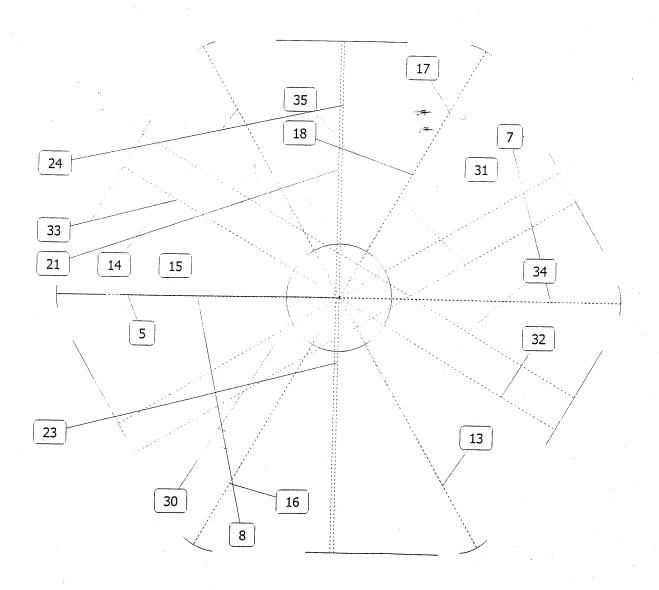
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Proj#		11	Description	Fee	edho	rn Bloc	k, 1020	9843, I	Final Asso	embly	Part#	102	2098	43	·	Rev.	X11
Custor	ner	JPL			Total Quant	tity		Serial N	lumbers				MII C=	STD -105	LEVEL II M= 1.5 A	SINGLE AQL A= 4	4.0 AQL
Item #			acteristic			Seq#	Dwg Zone	AQL	Insp Gage Number	Actua	II/Range		Qty	Qty Acc	Qty Rej	Cert Oper Stamp	Insp Stamp Date
		JPL dwg	# 1020984	13											 	Date	
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		JPL dwg	# 1020984	3	2073-7				,		ME POPCE.			•			7-7-13
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70	4X R	9				140	D10	С		8.95 - 8.99)			,	0.		03
	26,06	6 MAX (see	e note 4)			140	D11	С		25.6				1	1		25.03
80	5,94	MIN (see	note 4)			140	D10	С		6.49							
82	38,5		-			140	C11	С		38.56						-	
	6,5			***************************************		140	C10	С	_	6.471							
85	// (D,05 A				140	F10	С	_	.0168			1				

	CMI Qua	ality Ass	urand	ce	Che	cked By:	•	PC-	Stamp			MAP			Rev.	7
	Insp	ection P	lan		Date	э :		(5)				MP127	00		1	
Proj#	3.1	Description		norn Bloc	ck, 1020	9843, F	Final Ass	embly	Part #	102	098	43		Rev.	X1	
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Item #		aracteristic		Seq#	Dwg Zone	AQL	Insp Gage Number		al/Range		Qty Insp	Qty Acc	Qty Rej	Cert Oper Stamp	Insp Star Date	np
90	46,247±0,2 (4	corners)		140	E11	С		46.2277	46.224	7		1	Ø	Date	(Ogn	De.
95	// 0,003 /	A		140	D10	С				,	}	,	-		7-21	35
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105	Ø21 (see note	e 4)		140	H10	С		20.73								
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115				140	E7	С		2.983	·							\vdash
120	1,81+0,02/-0 9 boss points,	9 land point	s	140	E7	Ċ	AYG =	1.8128 PLANE TO								
125	2X 9 MAX			140	E8	С	,	8,99 -		POINI						-
				140	D7	C		0026 (10	POINTS			J	1			\dashv
	19X Ø3,8/3,79	 -	,	140	G10	С		3.823 - 3 .015 MA .40193966 .0374		5 (Ca)		1	Ox.	(rl
	19X Ø0,398/0,			140	D3	С		.015 7/1N .4020 -37 .40193966	MAY NCK!	2265	,	1 XX	0 7-31	7-30-03	7-22	33
143	19X 0,2 surfac	e finish		140	E6	С		ACCEPT))	0	7-30-03	17:22	50· 020
	4X Ø2,25/2 T⊦ ⊕ Ø0,05 (-	140	D12	С	-	2.0338 - 2.	1109		1	/	1		72	3
150	2X Ø3,2/3,12 ┐ ✓ Ø3,85/3,6 M3,5 X 0,35-6l	THRU X 90°		140	H12	С		3.1496 3.6068 X ACCEPT							1	

CMI Quality Assurance Inspection Plan Date: DCSamp MP12700 MP12700 Proj # Description Feedhorn Block, 10209843, Final Assembly Part # 10209843 Customer JPL Total Quantity Serial Numbers MIL STD -105 LEVEL IN C=100% M= 1.5 / C=100% M= 1	Rev.	X11
Description Feedhorn Block, 10209843, Final Assembly Part # 10209843	I SINGI F	
Total Quantity Serial Numbers MIL STD -105 LEVEL I C=100% M= 1.5 / C=100	I SINGLE AQL A= 4	10101
Item # Characteristic Seq # No. Dwg Zone AQL AQL Gage Number Actual/Range Qty Insp Qty Rej	70L 77-	
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	Stamp Date	
155 Ø1,61/1,6 THRU 140 C10 C .0602 MAX / / / O		(Cu) 18
160 1,6+0,01/-0 140 F1 C (405 = 405)		7-20-3
⊕0,1 A B C		
⊕0,1 A B C 140 E2 C .4911		
170 2X R 140 E2 C ACCEPT		
Weight parts and record results 140 C //7.59	-	
180 Inspect plating per SP1019, section 6.2		+-
185 Final Inspect as per SP1019 140 C Accept		

Feedhorn outer housing dimensions (not significant)



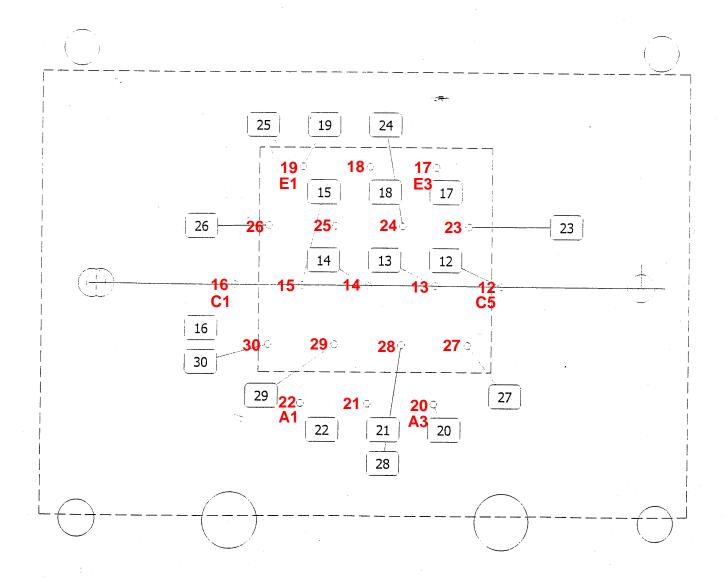
Program: Untitled Units: mm, dec deg

Date: Mon Jul 07 2003 Time: 09:05:02

Feature	Actual	Nominal	Plus (+)	Minus (-)	Dev/Nom	Out/Tol
Distance 5 Distance XY	[MCS] 10.3292	10.5000	0.0000	2.5000	-0.1708	
Distance 7 Distance XY	[MCS] 10.3261	10.5000	0.0000	2.5,000	-0.1739	
Distance 8 Distance XY	[MCS] 20.6552	21.0000	0.0000	5.0000	-0.3448	
Distance 13 Distance XY	[MCS] 10.3695	10.5000	0.0000	2.5000	-0.1305	
Distance 14 Distance XY	[MCS] 10.3354	10.5000	0.0000	2.5000	-0.1646	
Distance 15 Distance XYZ	[MCS] 20.7047	21.0000	0.0000	5.0000	-0.2953	
Distance 16 Distance XY	[MCS] 10.3416	10.5000	0.0000	5.0000	-0.1584	
Distance 17 Distance XY	[MCS] 10.3536	10.5000	0.0000	2.5000	-0.1464	
Distance 18 Distance XYZ	[MCS] 20.6951	21.0000	0.0000	5.0000	-0.3049	
Distance 23 Distance XY	[MCS] 9.2256	10.5000	0.0000	2.5000	-1.2744	
Distance 24 Distance XY	[MCS] 9.2305	10.5000	0.0000	2.5000	-1.2695	
Distance 30 Distance XY	[MCS] 9.2130	10.5000	0.0000	2.5000	-1.2870	
Distance 31 Distance XY	[MCS] 9.2474	10.5000	0.0000	2.5000	-1.2526	
Distance 32 Distance XY	[MCS] 9.2535	10.5000	0.0000	2.5000	-1.2465	
Distance 33 Distance XY	[MCS] 9.2128	10.5000	0.0000	2.5000	-1.2872	
Distance 34 Distance XY	[MCS] 18.4662	21.0000	0.0000	5.0000	-2.5338	
Distance 35 Distance XY	[MCS] 18.4609	21.0000	0.0000	5.0000	-2.5391	

Feedhorn waveguide diameters:

red numbers are circle numbers for data on following pages.
Positions are relative to feedhorn alignment pin hole
Corresponding Pixel ID's are given at corners.
Note this is a bottom view of the feedhorn, so the pixel map is
mirrored with respect to the ICD.



FINAL

Program: 10209843 jpl feedhorn 19 small hole with datums.iwpDate: Tue Jul 22 2003

Units: mm, dec deg

Feature Actual. Nominal Plus (+) Minus (-) Dev/Nom Out/Tol Circle 3 [MCS] Center X 276.2954 182.8375 93.4579 Center Y 99.7132 134.7152 -35.0019 Diameter 1.6035 1.6000 0.0100 0.0000 0.0035 Circularity 0.0091 Circle 12 [System 11] Center X -8.2307 -8.2238 -0.0069 Center Y 0.0008 0.0000 0.0008 Diameter 0.3995 0.3930 0.0050 0.0000 0.0065 0.0015 Circularity 0.0038 TP RFS 0.0138 0.0400 Circle 13 [System 11] Center X -12.1354 -12.1351 -0..0003 Center Y 0.0091 0.0000 0.0091 Diameter 0.3986 0.3930 0.0050 0.0000 0.0056 0.0006 Circularity 0.0053 TP RFS 0.0182 0.0400 Circle 14 [System 11] Center X -16.0547 -16.0464 -0.0083 Center Y -0.0052 0.0000 -0.0052 Diameter 0.3975 0.3930 0.0050 0.0000 0.0045 Circularity 0.0046 TP RFS 0.0196 0.0400 Circle 15 [System 11] Center X -19.9502 -19.95770.0075 Center Y 0.0025 -0.0000 0.0025 Diameter 0.3986 0.3930 0.0050 0.0000 0.0056 0.0006 Circularity 0.0059 TP RFS 0.0158 0.0400 Circle 16 [System 11] Center X -23.8525 -23.8690 0.0165 Center Y 0.0011 -0.0000 0.0011 Diameter 0.3997 0.3930 0.0050 0.0000 0.0067 0.0017 Circularity 0.0042 TP RFS 0.0330 0.0400 Circle 17 [System 11] Center X -12.1332-12.13510.0019 Center Y 6.7701 6.7746 -0.0045 Diameter 0.3930 0.3989 0.0050 0.0000 0.0059 0.0009 Circularity 0.0040 TP RFS 0.0098 0.0400 Circle 18 [System 11] Center X -16.0300 -16.0464 0.0164 Center Y 6.7836 6.7746 0.0090 Diameter 0.4019 0.3930 0.0050 0.0000 0.0089 0.0039 Circularity 0.0045 TP RFS 0.0374 0.0400 Circle 19 [System 11] Center X -19.9413-19.9577 0.0164 6.7746 Center Y 6.7717 -0.0029 Diameter 0.3930 0.3988 0.0050 0.0000 0.0058 0.0008 Circularity 0.0071 TP RFS 0.0332 0.0400 Circle 20 [System 11] Center X -12.1351-12.1391 -0.0040 Center Y -6.7674 -6.77460.0072 Diameter 0.3976 0.3930 0.0050 0.0000 0.0046 Circularity 0.0045 TP RFS 0.0164 0.0400

Time: 14:59:07

Program: 10209843 jpl feedhorn 19 small hole with datums.iwpDate: Tue Jul 22 2003 Units: mm, dec deg Time: 14:59:07

Actual	Nominal	Plus (+)	Minus (-)	20	
f 🗢			minus (-)	Dev/Nom	Out/Tol
[System 11] -16.0432 -6.7640 0.3982	-16.0464 -6.7746 0.3930	0.0050	0.'0000	0.0032	
0.0067		0.0400		0.0032	0.0002
[System 11] -19.9482 -6.7679 0.3999 0.0039 0.0232	-19.9577 -6.7746 0.3930	0.0050	0.0000	0.0095 0.0067 0.0069	0.0019
[System 11] -10.1737 3.3798 0.3997 0.0044 0.0187	-10.1794 3.3873 0.3930	0.0050	0.0000	0.0057 -0.0075 0.0067	0.0017
[System 11] -14.0818 3.3813 0.3966 0.0065 0.0215	-14.0907 3.3873 0.3930	0.0050	0.0000	0.0089 -0.0060 0.0036	
[System 11] -17.9940 3.3830 0.3979 0.0055 0.0182	-18.0020 3.3873 0.3930	0.0050	0.0000	0.0080 -0.0043 0.0049	
[System 11]					
-21.9038 3.3867 0.3985 0.0054 0.0191	-21.9133 3.3873 0.3930	0.0050	0.0000	0.0095 · -0.0006 0.0055	0.0005
[System 11] -10.1860 -3.3838 0.4005 0.0033 0.0148	-10.1794 -3.3873 0.3930	0.0050	0.0000	-0.0066 0.0035 0.0075	0.0025
[System 11] -14.0890 -3.3896 0.4019 0.0059 0.0057	-14.0907 -3.3873 0.3930	0.0050	0.0000	0.0017 -0.0023 0.0089	0.0039
[System 11] -17.9924 -3.3746 0.3997 0.0059	-18.0020 -3.3873 0.3930	0.0050	0.0000	0.0096 0.0127 0.0067	0.0017
	-6.7640 0.3982 0.0067 0.0221 [System 11] -19.9482 -6.7679 0.3999 0.0039 0.0232 [System 11] -10.1737 3.3798 0.3997 0.0044 0.0187 [System 11] -14.0818 3.3813 0.3966 0.0065 0.0215 [System 11] -17.9940 3.3830 0.3979 0.0055 0.0182 [System 11] -21.9038 3.3867 0.3985 0.0054 0.0191 [System 11] -10.1860 -3.3838 0.4005 0.00191 [System 11] -10.1860 -3.3838 0.4005 0.0033 0.0148 [System 11] -10.1860 -3.3838 0.4005 0.0054 0.0191 [System 11] -10.1860 -3.3838 0.4005 0.0054 0.0191 [System 11] -14.0890 -3.3896 0.4019 0.0059 0.0057 [System 11] -17.9924 -3.3746 0.3997	-6.7640	-6.7640	-6.7640	-6.7640 -6.7746 0.3922 0.3930 0.0050 0.0000 0.0052 0.0106 0.3922 0.0067 0.0221 0.00400 0.0052 0.0067 0.0021 0.0067 0.0022 0.00400 0.0052 0.0067 0.0022 0.0069 0.0050 0.0000 0.0069 0.0069 0.3999 0.3930 0.0050 0.0000 0.0069 0.0069 0.0039 0.3930 0.0050 0.0000 0.0069 0.0069 0.0039 0.3930 0.0050 0.0050 0.0000 0.0069 0.0069 0.0039 0.3930 0.0050 0.0050 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0067 0.0069 0.0065 0.0065 0.3930 0.0050 0.0060 0.0065 0.0065 0.3930 0.0050 0.0060 0.0065 0.0065 0.0065 0.3930 0.0050 0.0060 0.0065 0.0065 0.0065 0.0060 0.0065 0.0060 0.0065 0.0060 0.0065 0.0060 0.0065 0.0060 0.0065 0.0060 0.0065 0.0060 0.0060 0.0060 0.0060 0.0055 0.0082 0.0060 0.0050 0.0000 0.0000 0.0055 0.0082 0.0060 0.0050 0.0000 0.0055 0.0082 0.0060 0.0055 0.0082 0.0060 0.0050 0.0060 0.0055 0.0082 0.0060 0.0050 0.0000 0.0055 0.0082 0.0060 0.0055 0.0082 0.0060 0.0055 0.0082 0.0060 0.0055 0.0082 0.0060 0.0055 0.0060 0.0060 0.0055 0.0060 0.0060 0.0055 0.0060 0.0060 0.0055 0.0060 0.0060 0.0055 0.0060 0.0060 0.0055 0.0060 0.0060 0.0055 0.0060 0.0060 0.0055 0.0060 0.0060 0.0055 0.0060 0.0060 0.0060 0.0065 0.0060 0.0060 0.0060 0.0065 0.0060 0.006

Program: 10209843 jpl feedhorn 19 small hole with datums.iwpDate: Tue Jul 22 2003 Units: mm, dec deg

Feature	Actual	Nominal	Plus (+)	Minus (-)	Dev/Nom	Out/Tol
Circle 30 Center X Center Y Diameter Circularity	[System 11] -21.8996 -3.3853 0.3990 0.0053	-21.9133 -3.3873 0.3930	0.0050	0:0000	0.0137 0.0020 0.0060	0.0010
TP RFS	0.0278		0.0400	•		
Circle 31 Center X Center Y Diameter	[System 11] -32.2289 0.0000 1.6054	-32.2363 0.0000 1.6000	0.0100	0.0000	0.0074 -0.0000 0.0054	,
Circle 32 Center X Center Y Diameter	[System 11] -31.7378 0.0056 1.6005	-31.7386 0.0005 1.6000	0.0100	0.0000	0.0009 0.0051 0.0005	
Point 33 Location X Location Y TP RFS	[System 11] -31.9833 0.0028 0.0338	-32.0000 0.0000	0.1000		0.0167 0.0028	
Circle 34 Center X Center Y Diameter TP MMC	[System 11] 1.0130 13.4899 2.0514 0.0329	1.0000 13.5000 2.0000	0.2500 0.0500	0.0000	0.0130 -0.0101 0.0514 -0.0185	
Circle 36 Center X Center Y Diameter TP MMC	[System 11] -32.9813 13.4758 2.0338 0.0612	-33.0000 13.5000 2.0000	0.2500 0.0500	0.0000	0.0187 -0.0242 0.0338 0.0274	
Circle 37 Center X Center Y Diameter TP MMC	[System 11] 1.0082 -13.4937 2.0756 0.0208	1.0000 -13.5000 2.0000	0.2500	0.0000	0.0082 0.0063 0.0756 -0.0548	
Circle 38 Center X Center Y Diameter TP MMC	[System 11] -32.9446 -13.4826 2.1109 0.1161	-33.0000 -13.5000 2.0000	0.2500 0.0500	0.0000	0.0554 0.0174 0.1109 0.0053	
Circle 39	[System 11] PN 646 F -23.9814 -13.5130 3./496 3.2342 0.0453	-24.0000 -13.5000 3.1200	0.3500		0.0186 -0.0130 0.0842	
Circle 40 Center X Center Y Diameter TP RFS	[System 11] -8.0293 -13.4930 3.1938 0.0602	-8.0000 -13.5000 3.1200	0.3500		-0.0293 0.0070 0.0738	

Time: 14:59:07

Program: 10209843 jpl feedhorn 19 large hole 1.iwp

Units: mm, dec deg

Feature Actual Nominal Plus (+) Minus (-) Dev/Nom Out/Tol Circle 6 [System 51 Diameter 3.8211 3.7950 0.0050 0.0000 0.0261 0.0211 Circle 7 [System 5] Diameter 3.8090 3.7950 0.0050 0.0000 0.0140 0.0090 Circle 8 [System 5] Diameter 3.8230 3.7950 0.0050 0.0000 0.0280 0.0230 Circle 9 [System 5] Diameter 3.8125 3.7950 0.0050 0.0000 0.0175 0.0125 Circle 10 [System 5] Diameter 3.8111 3.7950 0.0050 0.0000 0.0161 0.0111 Circle 11 [System 5] Diameter 3.8113 3.7950 0.0050 0.0000 0.0163 0.0113 Circle 12 [System 5] Diameter 3.8189 3.7950 0.0050 0.0000 0.0239 0.0189 Circle 13 [System 5] Diameter 3.8140 3.7950 0.0050 0.0000 0.0190 0.0140 Circle 14 [System 5] Diameter 3.8090 3.7950 0.0050 0.0000 0.0140 0.0090 Circle 15 [System 5] Diameter 3.8142 3.7950 0.0050 0.0000 0.0192 0.0142 Circle 16 [System 5] Diameter 3.8176 3.7950 0.0050 0.0000 0.0226 0.0176 Circle 17 [System 5] Diameter 3.8154 3.7950 0.0050 0.0000 0.0204 0.0154 Circle 18 [System 5] Diameter 3.8148 3.7950 0.0050 0.0000 0.0198 0.0148 Circle 19 [System 5] Diameter 3.8104 3.7950 0.0050 0.0000 0.0154 0.0104 Circle 20 [System 5] Diameter 3.8130 3.7950 0.0050 0.0000 0.0180 0.0130 Circle 21 [System 5] Diameter 3.8106 3.7950 0.0050 0.0000 0.0156 0.0106 Circle 22 [System 51 Diameter 3.8150 3.7950 0.0050 0.0000 0.0200 0.0150 Circle 23 [System 5] Diameter 3.8083 3.7950 0.0050 0.0000 0.0133 0.0083 Circle 24 [System 5] Diameter 3.8211 3.7950 0.0050 0.0000 0.0261 0.0211

Date: Tue Jul 22 2003

Time: 15:15:51



Custom Microwave Inc. 940 Boston Avenue Longmont, CO 80501

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16

Clency Lee-Yow

From: Mark Weilert [Mark.A.Weilert@jpl.nasa.gov] Sent: Wednesday, July 30, 2003 10:06 AM To: Clency Lee-Yow Cc: Martin.I.Herman@jpl.nasa.gov; Scott.P.Hughes@jpl.nasa.gov Subject: Fwd: RE: SLW feedhorn non-conformances Hi Clency, Jason and Jamie (by phone) have agreed that the non-conformances are acceptable as-is. see below. So, you are clear to ship. Mark >Date: Tue, 29 Jul 2003 16:10:34 -0600 >From: Jason Glenn <Jason.Glenn@Colorado.edu> >Subject: RE: SLW feedhorn non-conformances >To: 'Mark Weilert' <Mark.A.Weilert@jpl.nasa.gov>, jjb@astro.caltech.edu >Cc: Jason Glenn <jglenn@origins.colorado.edu> >Reply-to: Jason.Glenn@Colorado.edu >Organization: CASA >X-Mailer: Microsoft Outlook, Build 10.0.2627 >Importance: Normal >Original-recipient: rfc822; Mark.A. Weilert@jpl.nasa.gov >Hi Mark and Jamie, see below. >Jason Glenn ->Assistant Professor of Astrophysics, University of Colorado CASA >389-UCB Boulder, CO 80309 >ARL Office: (303) 735-5904 ARL Room 175B >Main Campus: (303) 492-6073 Room 913 Gamov Tower >Fax: (303) 492-5941 >Lab: (303) 492-5972 ARL Room 125 >----Original Message---->From: Mark Weilert [mailto:Mark.A.Weilert@jpl.nasa.gov] >Sent: Monday, July 28, 2003 12:48 PM >To: James.J.Bock@jpl.nasa.gov; Jason.Glenn@colorado.edu >Subject: SLW feedhorn non-conformances >Hi Jamie and Jason, >attached is the non-conformance report from Custom Microwave for the >SLW > >feedhorn that they >recently finished. The short version is that there are two problems: >1) The feedhorn openings are all slightly too large, >3.8083 to 3.823mm instead of the specified 3.795 to 3.800. (the center >horn seems is one of the larger ones) >**The impact of this will be that at 350 um, the design wavelength of >the horns, the beamsizes will decrease by as much as 0.25% FWHM

>compared to a 3.800 um opening. This is acceptable. The upper limit >of 3.800 was chosen because CM felt that a larger radius would lead to

>wall thicknesses that were too thin to machine.

>2) Most (15 out of 19) of the waveguide ends of the feedhorns are also >too large, 0.3982-0.4019, instead of the specified 0.393-0.398 (which >is over-specified, according to Jasons previous email)
>In this case, the center horn is one of the ones that is in spec.
> **This impact of this will be to increase the cutoff wavelengths by as >much as 1% compared to 0.398 openings. This is acceptable also.
> I have also included the drawing for reference, and also another CMM >report which shows the positions of the various large end openings >(which isn't in >the original report).
> I need to hear whether or not this feedhorn is acceptable as is, so I >can tell CMI if they can ship.
> Thanks >Mark

Mark Weilert M/S 79-24 Jet Propulsion Laboratory 4800 Oak Grove Dr. Pasadena Ca 91109-8099

Mark.A.Weilert@jpl.nasa.gov office: (818) 354-5060 fax: (818) 393-4878

Any opinions expressed are mine, and do not represent official positions or policies of \mathtt{JPL}

2

ATTU: Mark

Data for large Dia. End

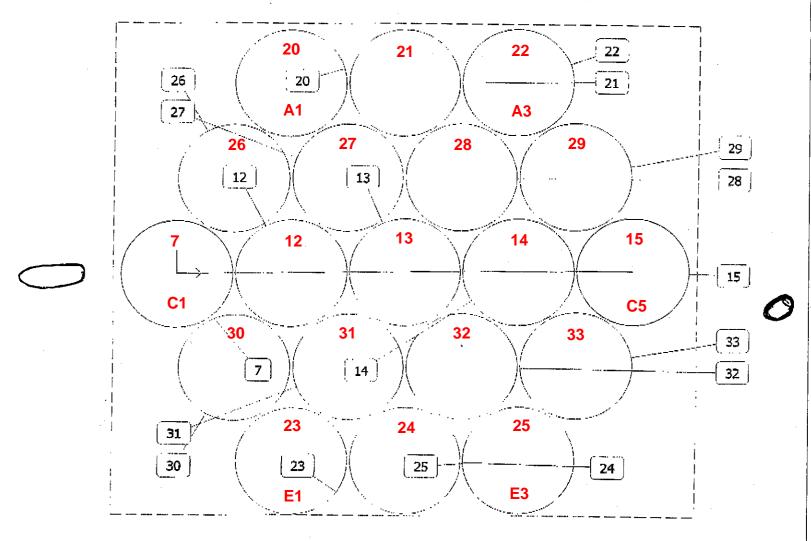
From DAV Jongsma at custom microwave

Feedhorn entrance diameters:

red numbers are circle numbers for data on following pages.

Positions are relative to circle 7

Corresponding Pixel ID's are given at corners.



Date: Wed Jul 23 2003 Time: 15:58:29

Feature	Actual	Nominal	flus (+)	Minus (-)	Dev/Nom	Qut/Tol
Circle 7 Center X Center Y Diameter TP RFS	[System 6] 0.0039 0.0019 3.8116 0.0087	0.0000 0.0000 3.7950	0.0050 0.0400	0.0000	0.0039 0.0019 0.0166	0.0116
Circle 12 Center X Center Y Diameter TP RFS	[System 6] 3.9128 -0.0015 3.8158 0.0042	3.9113 -0.0000 3.7950	0.0050 0.0400	0,0000	0.0015 -0.0015 0.0208	0.0158
Circle 13 Center X Center Y Diameter TP RFS	[System 6] 7.8160 0.0050 3.8212 0.0165	7.8226 0.0000 3.7950	0.0050 0.0400	0.0000	-0.0066 0.0050 0.0262	0.0212
Circle 14 Center X Center Y Diameter TP RFS	[System 6] 11.7229 -0.0004 3.8169 0.0220	11.7339 0.0000 3.7950	0.0050	0.0000	-0.0110 -0.0004 0.0219	0.0169
Circle 15 Center X Center Y Diameter TP RFS	[System 6] 15.6277 0.0043 3.8220 0.0361	15.6452 0.0000 3.7950	0.0050 0.0400	0.0000	~0.0175 0.0043 0.0270	0.0220
Circle 20 Center X Center Y Diameter TP RFS	[System 6] 3.9048 6.7670 3.8146 0.0200	3.9113 6.7746 3.7950	0.0050 0.0400	0.0000	-0.0065 -0.0076 0.0196	0.0146
Circle 21 Center X Center Y Diameter TP RFS	[System 6] 7.8144 6.7639 3.8163 0.0270	7.8226 6.7746 3.7950	0.0050 0.0400	0.0000	-0.0082 -0.0107 0.0213	0.0163
Circle 22 Center X Center Y Diameter TF RFS	(System 6) 11.7170 6.7665 3.8195 0.0375	11.7339 6.7746 3.7950	0.0050 0.0400	0.0000	-0.0169 -0.0081 0.0245	0.0195
Circle 23 Center X Center Y Diameter TP RFS	[System 6] 3.9220 -6.7591 3.8135 0.0376	3.9113 -6.7746 3.7950	0.0050 0.0400	0.0000	0.0107 0.0155 0.0185	0.0135
Circle 24 Center X Center Y Diameter TP RFS	[System 6] 7.8269 -6.7649 3.8174 0.0213	7.8226 -6.7746 3.7950	0.0050 0.0400	0.0000	0.0043 0.0097 0.0224	0.0174
Circle 25 Center X Center Y Diameter TP RFS	(System 6] 11.7242 -6.7638 3.8146 0.0290	11.7339 -6.7746 3.7950	0.0050 0.0400	0.0000	-0.0097 0.0108 0.0196	0.0146

Date: Wed Jul 23 2003

Time: 15:58:29

Feature	Actual	Nominal	Plus (+)	Minus (-)	Dev/Nom	Out/Tol
Circle 26	[System 6]	•				
Center X	1.9576	1.9556				
Center Y	3.3872	3.3873			0.0020	
Diameter	3.8164	3,7950	0 0050		-0.0001	
TP RFS	0.0039	3,7950	0.0050 0.0400	0.0000	0.0214	0.0164
Circle 27	[System 6]					
Center X	5.8653	5.8669				
Center Y	3.3837	3.3873			-0.0016	
Diameter	3.8093	3.7950	0.0050	0.0000	-0.0036	
TP RFS	0.0079	2.,,,,,	0.0400	0.0000	0.0143	0.0093
Circle 28	[System 6]					
Center X	9.7651	9.7782				
Center Y	3.3830	3.3873			-0.0131	
Diameter	3.8094	3.7950	0.0050		-0.0043	
TP RFS	0.0275	3,7,50	0.0400	0.0000	0.0144	0.0094
Circle 29	(System 6)				•	
Center X	13.6777	13.6895				
Center Y	3.3888	3.3873			-0.0118	
Diamoter	3.8165	3.7950	0.0050	0 0000	0.0015	
TP RF\$	0.0237	2.7500	0.0400	0.0000	0.0215	0.0165
Circle 30	[System 6]					
Center X	1.9580	1.9556				
Center Y	-3.3788	-3.3873			0,0024	
Diameter	3.8132	3.7950	0.0050	0.0000	0.0085	
TP RFS	0.0177	5.7550	0.0400	0.0000	0.0182	0.0132
Circle 31	[System 6]					
Center X	5.8695	5.8669			0 0000	
Center Y	-3.3806	~3.3873			0.0026	
Diameter	3.9115	3.7950	0.0050	0.0000	0.0067	
TP RFS	0.0143		0.0400	0.0000	0.0165	0.0115
Circle 32	[System 6]				-	
Center X	9.7762	9.7782			0.000	
Center Y	-3.3853	-3.3873			-0.0020	
Diameter	3.8126	3.7950	0.0050	0.0000	0.0020	
TP RFS	0.0056	*****	0.0400	0.0000	0.0176	0.0126
ircle 33	[System 6]					
Center X	13.6810	13.6895			0.000=	
Center Y	-3.3737	-3.3873			-0.0085	
Diameter	3.8223	3.7950	0.0050	0.0000	0.0136	
TP RFS	0.0321	01.700	0.0400	0.0000	0.0273	0.0223





Ref.:SPIRE Issue: 1.1

Date:17 December 2004

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SPIRE - 300mK SLW-FS filter stack

End Item Data Package (EIDP)

SPIRE - 300mK SLW-FS filter stack

SPIRE Ref.: SPIRE-UCF-

Cardiff Ref.: HSO-CDF-EIDP-089 Issue 1.1

17 December 2004

Prepared by: Peter Hargrave SPIRE Technical Manager

Approved by: Carole Tucker Cardiff Filter Manager

Ian Walker Cardiff SPIRE/HFI Programme Manager

Distribution list

JPL	James Bock	RAL	Eric Sawyer
	Hien Nguyen		Eric Clark
	Martin Herman		Judy Long
	Mark Weilert		Bruce Swinyard
Cardiff	Carole Tucker		
	Peter Ade		
	Matt Griffin		
	lan Walker		

Astronomy Instrumentation Group, Department of Physics & Astronomy, University of Wales, Cardiff, 5 The Parade, Cardiff CF24 3YB

+44 (0)2920 876682

 $H: \c Cardiff_work packages \c Deliverables_configured \c Shipped \c Filters \c FS-300mK-filters \c FS-SLW-stack \c 300mK_SLW_FS_HSO-CDF-EIDP-089.doc$

Change Record

Issue	Section	Date	Changes
1.0		15/12/04	First Issue after DRB approval
1.1		17/12/04	Flight issue post DRB approval

Table of contents

Section	Contents	Req.	Comments
1	Shipping Documents	X	
2	Transportation, Packing, Handling & Integration Procedures	X	
3	Certificate of Conformance / Delivery Review Board MoM Ai-Lists	X	
4	Qualification Status List / Test Matrix	X	
5	Top Level Drawings (inc. Family Tree)	X	
6	Interface Drawings	X	
7	Functional, Block & Mechanical Drawings	X	
8	Electrical Circuit Drawings		
9	As Built Parts List	X	
10	Serialised Components List		
11	List of Waivers	X	
12	Copies of Waivers	X	
13	Operational Manual		
14	Historical Record	X	
15	Logbook / Diary of Events	X	
16	Operating Time / Cycle Record		
17	Connector Mating Record		
18	Age Sensitive Items Record	X	
19	Pressure Vessel History / Test Record		
20	Calibration Data Record	X	
21	Temporary Installation Record	X	
22	Open Work / Deferred Work / Open Tests	X	
23	List of Non-Conformance Reports	Х	
24	Copies of Non-Conformance Reports	Х	
25	Test Reports	Х	
26	Proof Load Certificates		
27	Reference List of EIDP's	Х	

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SPIRE - 300mK SLW-FS filter stack End Item Data Package (EIDP) Page 3 of 39

	(Lower Level / Associated)		
28	Mass Records / Power Budget	X	
29	Cleanliness Statement	X	
30	Other Useful Information	X	

SECTION 01 - Shipping Documents

Labelling on box:-

Instructions to FedEx – Important!

At LAX, please handover to:-

PackAir Airfreight INC., 5510 West 104 St., Los Angeles CA90045 USA

Power of Attorney - Roger Bachar Telephone (310) 342 6051



Figure 1 SLW FS filter stack prior to shipping to JPL.

DRB Minutes of meeting

Minutes of SPIRE PFM 300mK FS SLW filter stack DRB Cardiff, December 16th 2004

Present: Ian Walker (chair), Pete Hargrave, Peter Ade, Carole Tucker, Melanie Whitehead

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H:\Cardiff_workpackages\Deliverables_configured\Shipped\Filters\FS-300mK-filters\FS-SLW-stack\300mK SLW FS HSO-CDF-EIDP-089.doc	SPIRE - 300mK SLW-FS filter stack End Item Data Package (EIDP)	Page 7 of 39	

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DRB scope and objectives

• Review 300mK FS SLW filter stack (FILT-FS-210)

List of relevant documents and status

- HSO-CDF-EIDP-089 (15 December 2004)
- HSO-CDF-ICD-012 (Issue 3.0)
- HSO-CDF-SP-002 (Issue 2.2)
- DML/DPL
 - o Overall document to be issued for all SPIRE deliverables
 - o DML: HSO-CDF-L1-074 Issue 1.0
 - o DMPL: HSO-CDF-L1-075 Issue 1.0
 - o DPL: HSO-CDF-L1-076 Issue 1.0

Review of comments received on EIDP

- Comments from Ian Walker & Melanie Whitehead
 - p6 photos to be added
 - p7 insert minutes for this DRB
 - p9 insert checklist for this DRB
 - p10 change PMW to PSW

- p26 last two dates in historical record to be added
- p33 location of UWC Filter production PA V2.0.doc?
- p37 location of UWC Filter Fabrication Procedures.doc?
- p38 photos to be added
- Above comments accepted and Actions agreed during EIDP run-through (see below).
- Agreed that the Carole would archive dated PDF versions of UWC_Filter_production_PA_V2.0.doc and UWC Filter Fabrication Procedures.doc

EIDP run-through

- Section 1, Shipping Documents Action: PCH to add photographs, update EIDP number, DRB checklist and Conclusions, and include DRB minutes in final version of EIDP.
- Section 2, Transportation, Packing, Handling & Integration Procedures PCH amended "PMW BDA (PFM or FS)" to "SLW BDA (FS)".
- Section 4, Qualification Status List PCH amended filter reference for 'Inspection for surface defects'.
- Section 9, As Built Configuration Items Status List PCH corrected an error relating to a filter number.
- Section 14, Historical Record Action: PCH to update the last two placeholder dates (in red) and provide appropriate reference to these DRB minutes. PCH to also add reference to post-thermal shock spectral test.
- Section 25, Test Reports Action: PCH to add note explaining differences between uniformity and calibration data. It was agreed that the performance data meets requirements.
- Section 28, Mass record Action: PCH to update placeholder mass value (in red) with appropriate value.
- Section 30, Other Useful Information Action: PCH to add photographs of assembly prior to shipping.

Conclusions and summary of outstanding work

- This unit is deemed acceptable as flight-standard hardware, and may be shipped to JPL for incorporation in the SPIRE PFM FS BDAs.
- The amendments/additions noted above must be made to the EIDP before the unit is shipped.

DRB Check-list

If all listed points are satisfactory then the item may be accepted. If not, the item may be accepted with the caveat that the requirement in question will be met within an agreed time scale.

No.	Record applicable answers and provide explanations in comment column	Yes/No/NA	Comments
1	Are all documents, drawings, etc. complete, approved, and under configuration control?	Yes	
2	Do the released items above reflect all approved changes?	Yes	
3	Is the hardware identical to other hardware delivered. If not provide difference list?	Yes	
4	Does the hardware fulfil its functional requirements, specifications, RFWs, ICDs etc.?	Yes	
5	Does the As-built Configured Items List reflect hardware as delivered?	Yes	
6	Have all required environmental tests and analyses been completed?	Yes	
7	Are all the required test and qualification procedures and reports completed and available to review.	Yes	
8	Have all the Declared Lists, i.e. DML, DMPL, DPL and components (EEE Parts) list been released? (Need not necessarily be included in EIDP, but must be available)	Yes	
9	Have PADS been raised and approved where required?	N/A	
10	Are relevant Test Readiness Review (TRR) minutes and the Post Test Reviews (PTR) complete and available?	N/A	
11	EIDP check: Are all agreed sections of the EIDP complete? Record any anomalies.	Yes	PCH to provide minor amendments to sections as indicated above

		Signature	Date
Ian Walker	Cardiff SPIRE PA manager and DRB chair		
Peter Hargrave	Cardiff SPIRE Technical Manager		
Carole Tucker	Cardiff Filter Manager		

H:\Cardiff_workpackages\Deliverables_configured\Shipped\Filters\FS-300mK-filters\FS-SLW-stack\300mK_SLW_FS_HSO-CDF-EIDP-089.doc	SPIRE - 300mK SLW-FS filter stack End Item Data Package (EIDP)	Page 10 of 39

SECTION 02 - Transportation, Packing, Handling & Integration Procedures

This package contains flight hardware.

To be opened only by authorised SPIRE personnel in clean room conditions.

Do not touch filter surface.

Handle only by Aluminium frame.

To be integrated to SPIRE SLW BDA (FS) according to JPL procedure.

Hand over to JPL Cognisant Engineer – Mark Weilert

Mark Weilert
M/S 79-24
Jet Propulsion Laboratory
4800 Oak Grove Dr.
Pasadena Ca 91109-8099

Mark.A.Weilert@jpl.nasa.gov

office: (818) 354-5060 fax: (818) 393-4878

SECTION 03 - Certificate of Conformance

Cardiff University Astronomy Instru	mentation Group I	nereby certifies that the	following equipment,	
Space	ecraft / Project:	Herschel		
	Instrument:	SPIRE		
	Model:	FS		
	Subsystem:	300mK SLW filter	stack	
	Serial No:	FILT-FS-210		
As described in this End Item Data	Package: HSO-CDI	-EIDP-089		
Complies with the requirements set	out in: SPIRE-RAL	PRJ-000034 (Instrume	nt requirements document)	
Responsible Authority			Signature	
	Prof P.A.	R.Ade		
Cardiff Filter Management	Dr C.E.1	ucker		
Cardiff Product Assurance Dr I.Walke		alker		
Cardiff SPIRE Management	Dr P.Ha	rgrave		

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stack\300mK_SLW_FS_HSO-CDF-EIDP-089.doc

SECTION 04 - Qualification Status List

Test	Status	Applicable document / Test	Test Institute
	FS-SLW - FILT-FS-210	reference	
Spectral behaviour - In and near-band transmission	Tested at component and assembly level. Compliant with approved waiver (HSO-CDF-RFW-063).	HSO-CDF-SP-002-2.2 See historical record for test references	UWC
Spectral behaviour - out-of-band blocking, at $\lambda{<}15\mu m$	Open test. Off-cuts of the filter material are securely stored, and may be measured to 15µm using the Bomen spectrometer if required.	HSO-CDF-SP-002-2.2 See historical record for test references	UWC
Dimension and tolerances to specification	Compliant	HSO-CDF-ICD-012-3.0	UWC
Filter flatness	Not applicable for this assembly	HSO-CDF-ICD-012-3.0	UWC
Inspection for surface defects	Passed	UWC Filters database "hundred_acre_wood.mdb" reference B675, B683.	UWC
Mass	Compliant	HSO-CDF-ICD-012-3.0	
Thermal cycling (5 cycles 300K-77K-300K)	Passed	See historical record for test references	UWC
Cold vibration	Not tested at unit level, but qualified in SPIRE CQM cold vibration campaign	MSSL-Technote-SPIRE-26 SPIRE-RAL-REP-002007	MSSL/RAL – Cold vibration RAL – Post vibration inspection
Environmental condition - Vacuum 3x10 ⁻¹ mBar	Passed	See historical record for test references	UWC
Differential pressure (a pumping-out rate of 10mB/sec)	Passed	See historical record for test references	UWC
Pre-bake out (not exceeding 80°C)	Passed	UWC PCH SPIRE Filters log- book	UWC
Outgassing	Test not performed. All materials used within ESA / NASA specifications		
Cleanliness checks, by visual inspection.	Passed	UWC Filters database "hundred_acre_wood.mdb" reference B675, B683.	UWC
Degradation due to high energy radiation.	Not tested. Heritage from previous space missions (ISO, Cassini)		

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stack\300mK_SLW_FS_HSO-CDF-EIDP-089.doc			

SECTION 05 – Top Level Drawings (Inc. Family Tree)

Although all drawings in this section have numbers of the form FILT-CQM/PFM-XXX-xx-xx, these are also the correct drawings for the flight spare model.

TOP LEVEL DRAWING LIST

Drawing No.	Title
FILT-CQM/PFM-200-03.001	300mK Filter Assembly

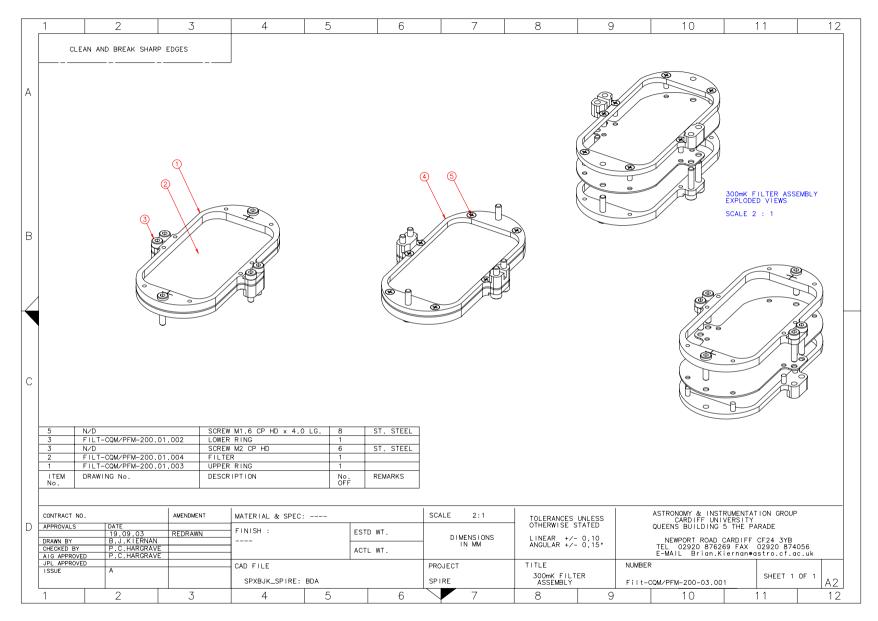


Figure 2 300mK filter stack assembly

SECTION 06 - Interface Drawings

INTERFACE DRAWING LIST

Drawing No.	Title
FILT-CQM/PFM-200	300mK Filter ICD

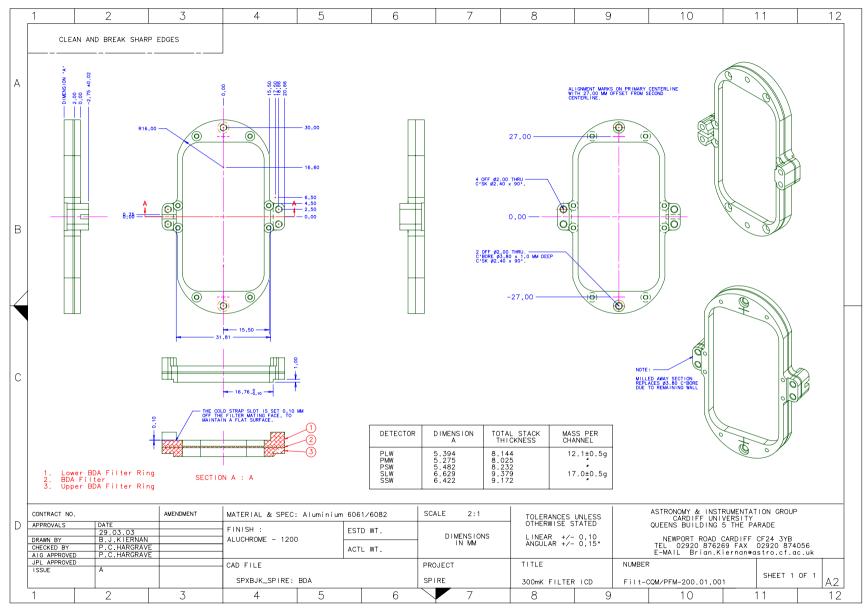


Figure 3 Interface drawing for 300mK filters

SECTION 07 - Functional, Block & Mechanical Drawings

Component drawings are given in this section.

FUNCTIONAL & BLOCK DRAWING LIST

Drawing No.	Title

MECHANICAL COMPONENT DRAWING LIST

Drawing No.	Title
FILT-CQM/PFM-200-01-004	300mK Filter
FILT-CQM/PFM-200-01-003	300mK Filter Upper Ring
FILT-CQM/PFM-200-01-002	300mK Filter Lower Ring
FILT-CQM/PFM-200-02-001	300mK Spectrometer Lens

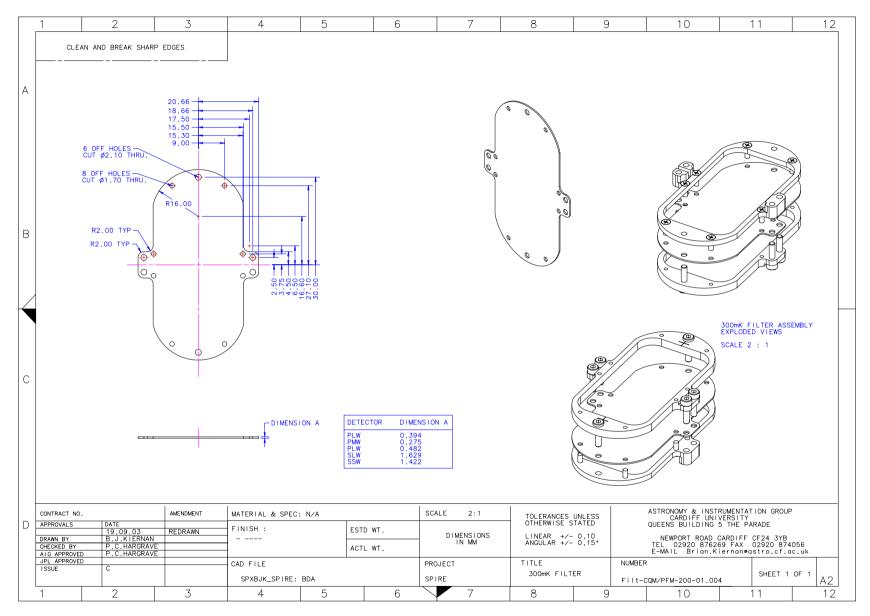


Figure 4 300mK Filter

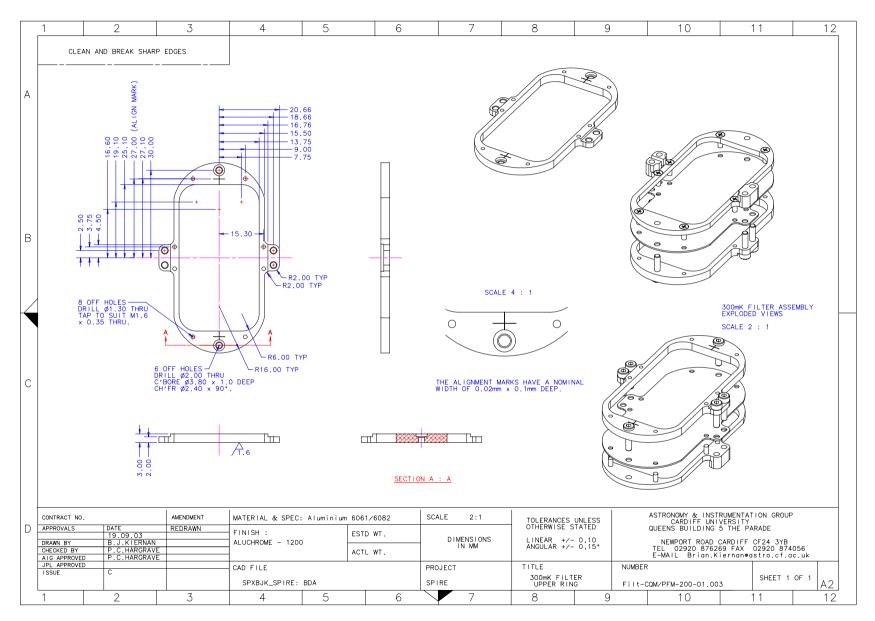


Figure 5 300mK Filter Upper Ring

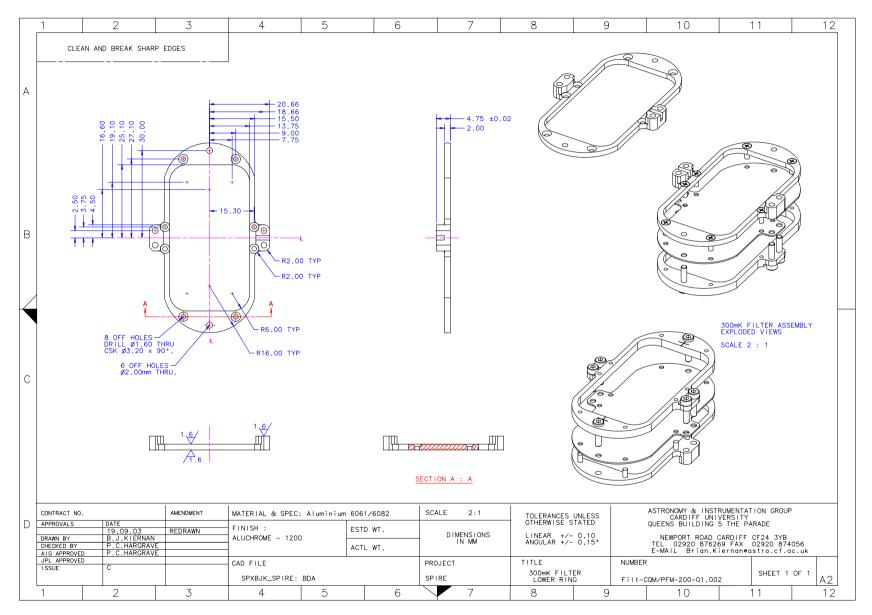


Figure 6 300mK Filter Lower Ring

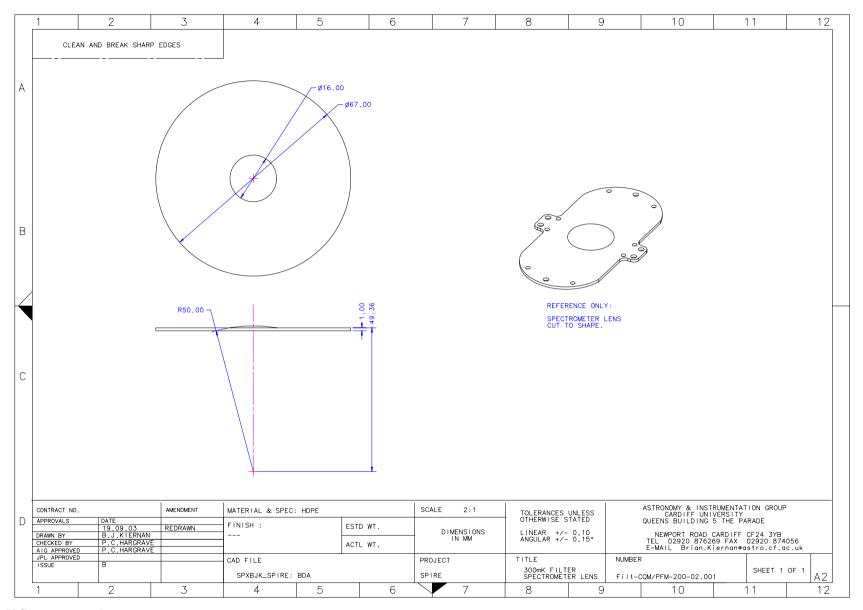


Figure 7 300mK Spectrometer lens

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stack\300mK_SLW_FS_HSO-CDF-EIDP-089.doc	End Item Data Package (EIDP)	_

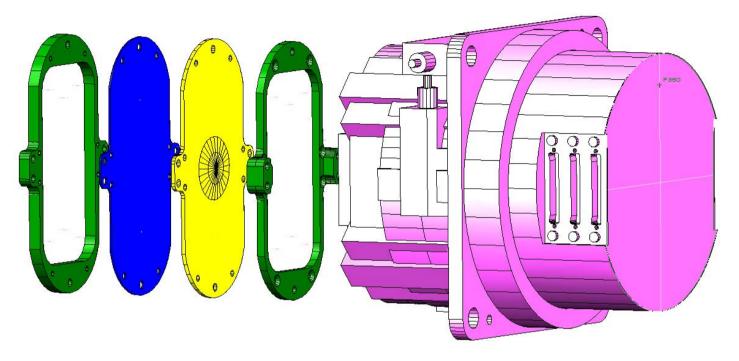


Figure 8 Location of spectrometer lens in 300-mK filter stack. Note that the SLW filter assembly has two filters and one lens in the stack.

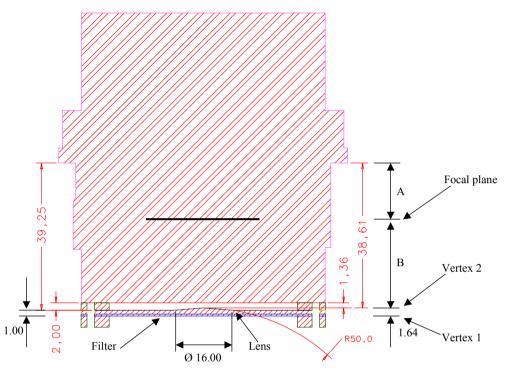


Figure 9 Dimensions of spectrometer lens – filter – detector assembly.

SECTION 09 - As Built Configuration Items Status List

Item	Reference	Location	Notes
Filter drawings and		\\Darkstar\Astroworld\Projects\SPIRE\Cardiff_workpackages\Configured_documents\Filt	
manufacturing files		ers\Drawings\300MK-filter-CQM-PFM.doc	
Material certificates of		Available at Cardiff for inspection	
conformance		Available at Cardin for inspection	
FILT-FS-210		\\Darkstar\Astroworld\Projects\SPIRE\Cardiff_workpackages\Configured_Documents\Iss	
Spectroscopic test data SLW-FS assembly		ued\Data\FILT-FS-210_FS_SLW_stack.xls	
SLVV-FS assembly			

Part number	Description	Details
FILT-FS-210	FS SLW FILTER ASSEMBLY	
FILT-FS-211	SLW FS lower filter ring	Aluminium-6082 – Aluchrom 1200 coated
FILT-FS-212	SLW FS upper filter ring	Aluminium-6082 – Aluchrom 1200 coated
FILT-FS-213	SLW FS lens	Polypropylene lens
FILT-FS-214	SFIL4L – FS – B683#2 filter	34.7 cm-1 LPE blocker
FILT-FS-215	SFIL5L – FS- B675#1 filter	31.9 cm-1 LP edge definer

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stack\300mK_SLW_FS_HSO-CDF-EIDP-089.doc

SECTION 11 - List of Waivers

HSO-CDF	F-RFW-063	SPIRE PFM Blocking Filters RFW	Closed	

SECTION 12 - Copies of Waivers

CLRC	Rutherford Appleton Laboratory	REQUES1	FOR WAIVER / DEVIATION (RFW/RFD)	PRODUCT ASSURANCE Space Science and Technology Department
		WRFD mber:	HR-SP-CDF-RFW-XX	+, HSO-CDF-RFW-063

Spacecraft / Project	HERSCHEL	Originator's Name	Peter Hargrave	
System / Experiment / Model	SPIRE-PFM	Signature / Date	2 /4	religion (spile by some religions of the control of
Sub-System	Filters	Request Type (Highlight applicable request)	Waiver (RFW)	Deviation (RFD)
Assembly		Organisation	Cardiff Ur	niversity
Sub-Assembly		Ref. Doc. / Drwg No.		
Item	All flight model blocking filters	References		
Serial No.		References		
RFW/RFD Title	Request for waiver against blocking filter edges			

End Items(s) Affected (Hardware, Software)							
Name	CI-Number				Model(s)		
SPIRE PFM blocking filters		FI			Flig	Flight	
	Requirem	ent / Interface Docu	ments Affec	ted			
Specification/Drawing Title Number Issue Date				App. Paragraph			
Filters specification document	HSO-CDF-SP-002		2.2	29/10/02		3.2 table 1 3.3 table 2	
		eviation / Discrepan					
This note requests a waiver on the nominal edge positions for the flight model instrument blocking filters.							
Other Items or Requirements (Potentially) Affected							
None							

Need for RFW/RFD and Rationale for Acceptance

Need for RFW/RFD and Rationale for Acceptance

The flight blocking filters have been tuned in such a way as to optimise the in-band transmission and out-of-band rejection for each SPIRE band. This means that the actual edge positions are not exactly as stated in HSO-CDF-SP-002 (filters spec. document). This is not important, as the band edges are defined by edge defining filters, which are all exactly to specification, and are not included in this request for waiver.

The differences in edge position are summarised in Table 1.

Informal MRB held by Eric Sawyer & Bruce Swinyard. 11th August 2004 This RFW is accepted / agreed by SPIRE PROJECT, No Agreement required from Industry or Customer.

	Approved	Rejected	Name	Date
Engineering:	Sharkestavim		Bruce Swinyard	
Product Assurance:	Mar Between residen		Eric Clark	
CCB-Chairman:				
Principle Investigator				
Product Assurance:				
Co-Investigator				
Prime Contractor				
ESA Project Office				

CLRC	Rutherford Appleton Laboratory	REQUEST	FOR WAIVER / DEVIATION (RFW/RFD)	PRODUCT ASSURANCE Space Science and Technology Department
		WRFD mber:	HR SP CDF RFW XXX	, HSO-CDF-RFW-063

Table 1 Comparison of nominal edges as stated in HSO-CDF-SP-002 with actual PFM blocker edge positions.

Name	Filter type	Edges		Function T = Transmit		Comments	PFM filter performance			Difference from specification			
		Trans	cm-1	μm	B = E	Block;	R = R	eflect		Trans	cm-1	μm	cm-1
CFIL1	Low-	90%	60.0	166.7	Т		- 50	cm-1	Thermal blocker.	90%	71.0	140.8	11.0
	pass	50%	100.0	100.0		666.7	- 200	μm	Common to Photometer	50%	95.0	105.3	-5.0
	edge	10%	105.0	95.2	В		- UV		and FTS.	10%	98.0	102.0	-7.0
					_	90.91		μm					
PFIL2	Low-	90%	60.0	166.7	Т		- 50	cm-1	Thermal blocker.	90%	71.5		11.5
	pass	50%	90.0	111.1			- 200		1	50%	84.5		
	edge	10%	94.5	105.8	В		- UV			10%	86.8	115.2	-7.7
PFIL3	Low-	90%	57.0	175.4	Ψ.		- 50	μm cm-1	Thermal blocker.	90%	50.2	199.2	-6.8
FFILS	pass	50%	60.0	166.7	'		- 200		Thermal blocker.	50%	55.3	180.8	
	edge	10%	63.0	158.7	В		- UV	μm cm-1	1	10%	56.9		
	euge	1076	03.0	130.7	ь.		- UV	um		1076	30.9	175.7	-6.1
SFIL2	Low-	90%	60.0	166.7	_		- 50	cm-1	Thermal blocker.	90%	66.9	149.5	6.9
	pass	50%	90.0	111.1	Т	666.7	- 200		Identical to PFIL2.	50%	89.0	112.4	-1.0
	edge	10%	94.5	105.8	_		- UV			10%	91.0		-3.5
					В		- UV	μm					
SFIL3S	Low-	90%	66.5	150.4	т	31.2	- 51.3	cm-1	Blocker	90%	59.1	169.2	-7.4
	pass	50%	70.0	142.9		320.5	- 195	μm		50%	63.9	156.5	
	edge	10%	73.5	136.1	В		- UV	cm-1		10%	65.8	152.0	-7.7
					_		- UV	μM					
SFIL3L	Low-	90%	57.0	175.4	T		- 66.5		Blocker	90%	47.8		-9.2
	pass	50%	60.0	166.7			- 150			50%	66.4		6.4
	edge	10%	63.0	158.7	В		- UV			10%	68.2	146.6	5.2

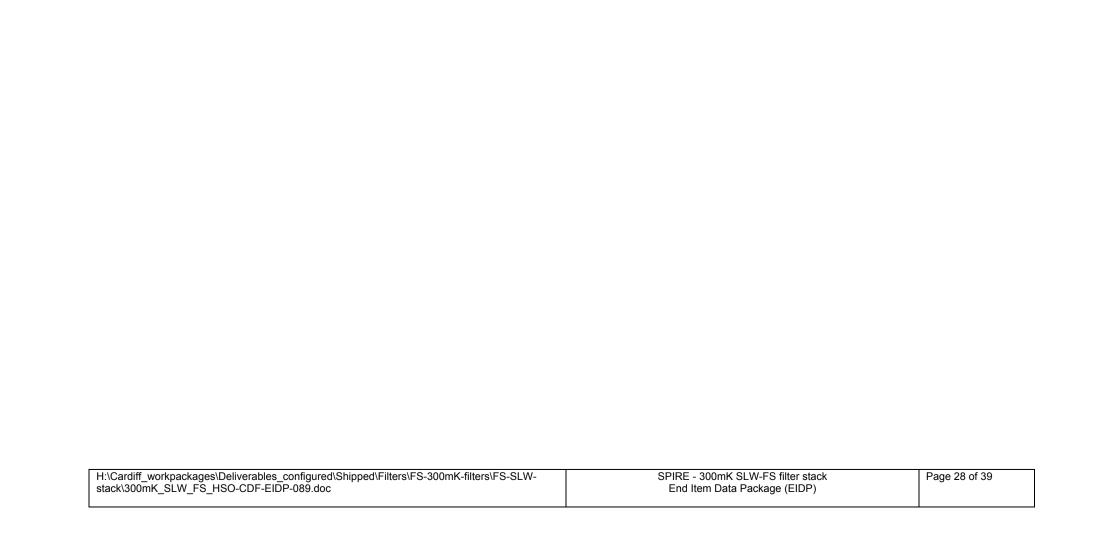
ISO9: Form PA 016 Request for Waiver/deviation (RFW/RFD)

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ISO9: Form PA 016 Request for Waiver/deviation (RFW/RFD)

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SECTION 13 - Operations Manual

No operating manual is supplied.

SECTION 14 - Historical Record

The following table contains *brief* historical details of the manufacture, assembly and testing of the FS 300mK SLW filter assembly, including the levels of environmental cleanliness.

A *full* historical record of every stage of manufacture for each individual grid integral to the final mounted filter is traceable at UWC, in both hard copy logbook format and on a Microsoft Access database.

SLW FS filter stack

Date	Action	UWC Test reference
24/5/02	Upper and lower filter clamp rings manufactured – Cardiff MEC. Ref. Q/1731.1	
1/8/03	Filter B675 manufactured in class 1000 clean room	
5/8/03	Filter B675 spectroscopically tested in the range 10-140cm-1	T0146r31
6/8/03	Filter B675 spectroscopically tested in the range 5-40cm-1	T0147r7
13/8/03	Filter B683 manufactured in class 1000 clean room	
14/8/03	Filter B683 spectroscopically tested in the range 10-140cm-1	T0153r19
15/8/03	Filter B683 spectroscopically tested in the range 5-40cm-1	T0155r10
11/8/04	Filter B675 cut to SLW drawing (B675#1)	
11/8/04	B675#1 spectroscopically tested in the range 10-140cm-1	T0405r31
11/8/04	Filter B683 cut to SLW drawing (B683#2)	
11/8/04	B683#2 spectroscopically tested in the range 10-140cm-1	T0405r22
18/8/04	Filters B675#1 and B683#2 bonded together	
19/8/04	Bonded filters B675#1 and B683#2 spectroscopically tested in the range 15-140cm-1 at two	T0411r19, T0411r22
	locations over area	
24/8/04	Bonded filters B675#1 and B683#2 thermally shocked 5 times between 300K and 77K	THERM 0196
31/03/04	2mm polypropylene sheet ordered from North Sea Plastics	
07/04/04	Polypropylene lenses manufactured by MEC – Q/3661	
6/12/04	Filters & polypropylene lens mounted as SPIRE_FS_SLW filter stack	
6/12/04	FS-SLW Assembly spectroscopically tested in the range 10-140cm-1 at two locations over area	T0476r10, T0476r13
7/12/04	FS-SLW Assembly spectroscopically tested in the range 5-40cm-1	T0477r4
8/12/04	FS-SLW baked for 17hrs at 350K	
9/12/04	FS-SLW stack final clean, 24Hr bake-out	
16/12/04	FS SLW 300mK stack DRB meeting	
17/12/04	FS-SLW shipped to JPL	

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SECTION 15 - Logbook / Diary of Events

Not provided – available from subsystem provider upon request.

Cardiff log-book, labelled "Cardiff SPIRE filters Log-book", will be stored in a secure archive.

SECTION 16 - Operating Time / Cycle Record

See historical record.

SECTION 20 - Calibration Data Record

The recommended 300mK filter transmission for the SLW channel to be used for calibration purposes is indicated in this section. This trace is composed of data measured over the ranges 0-40cm⁻¹ and 0-140cm⁻¹.

These are the measured transmission spectra prior to final cleaning and packing.

The raw data is stored in the file

\\Darkstar\Astroworld\Projects\SPIRE\Cardiff_workpackages\Configured_Documents\Issued\Data\FILT-FS-210_FS_SLW_stack.xls (Microsoft Excel workbook). This file is available from Cardiff, and is under configuration control on Livelink (managed by RAL). Calibration data for all SPIRE flight model filters may be found in the file

\\Darkstar\Astroworld\Projects\SPIRE\Cardiff_workpackages\Configured_documents\Issued\ Data\ PFM-filters-summary.xls

FS SLW Filter assembly - FILT-FS-210

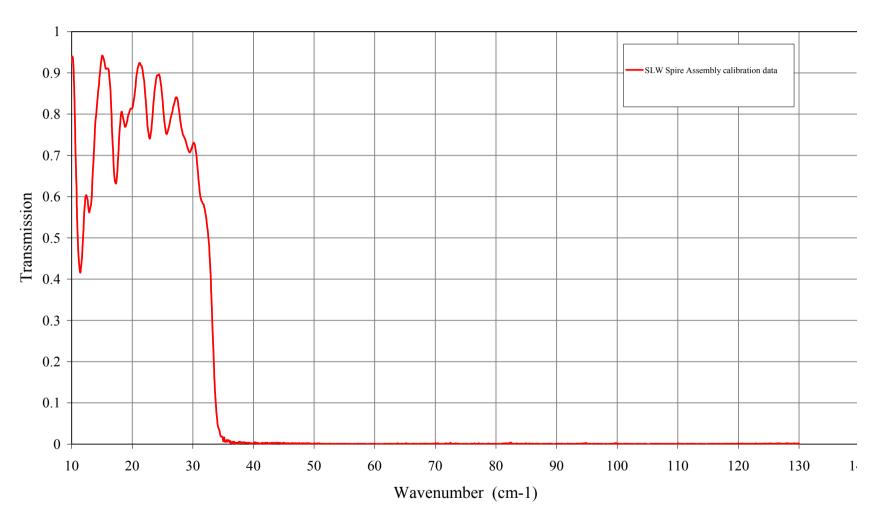


Figure 10 Spectroscopic data for FS-SLW stack

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SECTION 21 – Temporary Installation Record

See historical record.

SECTION 22 - Open Work / Deferred Work / Open Tests

Off-cuts of the filter material are securely stored, and may be measured to $15\mu m$ using the Bomen spectrometer if required.

SECTION 23 - List of Non-Conformance Reports

None

SECTION 24 - Copies of Non-Conformance Reports

None

SECTION 25 - Test Reports

SPIRE FS SLW test summary - CT

1 Visible inspection

As standard practice, each filter element is checked individually for pattern geometry and defects under an optical microscope, following the procedures laid out in the UWC internal document "UWC_Filter_production_PA_V2.0.doc".

The assembled filter then undergoes a series of optical, thermal and mechanical tests.

2 Optical measurements

The FIR spectral tests were carried out at UWC, using two Martin-Puplett polarizing Fourier transform interferometers. These instruments allow spectral evaluation from 2 to 650 cm-1, using a series of in-house detectors.

The as-manufactured, unmounted, uncut filters were spectrally tested in- and near-band, following the standard FTS procedures of UWC.

The individual filter components (SFIL4L, SFIL5L) were then bonded together.

The bonded filter stack was then re-measured spectrally, and then machined to the 300mK filter drawing. Measurements were then made in transmission at two extreme locations, as a test for uniformity.

Following thermal cycling tests and mounting with the lens, the SLW filter stack was spectrally re-tested at two locations in one frequency range to verify component integrity.

3 Thermal tests

3.1 Thermal shock

Thermal shocking of the SLW filter stack prior to cutting and mounting was performed using a liquid nitrogen bath. This cycle (300K - 77K - 300K) was performed 5 times. All spectroscopic measurements made thereafter verified no filter de-lamination or degradation. (If any part of a filter is seen to de-laminate, or show any other signs of weakness, it is rejected and the component remade).

3.2 Thermal cycling

Once machined, the SLW stack underwent a more controlled thermal cycle 3x(300K - 77K - 300K). The component showed no signs of degradation.

4 Mechanical tests

During the evacuating of the Martin-Puplett FTS, the filter stack has been subjected to a differential pressure rate of change of at least 10mB/sec. It has been taken to a vacuum pressure of 0.5mbar, within the FTS, on at least 8 separate occasions.

The filter stack has been cleaned using an ultrasonic acetone bath, and has been vacuum baked at 350 K for 17 hours with no signs of degradation.

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FS SLW Stack uniformity

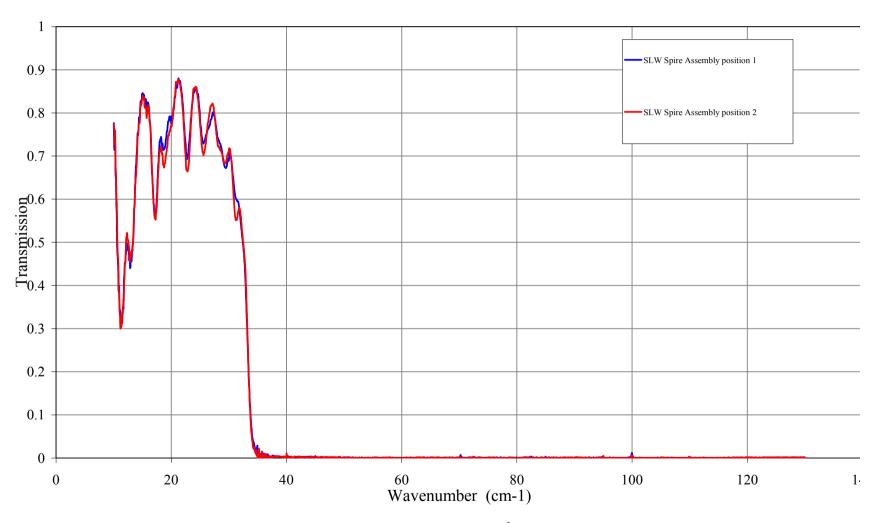


Figure 11 FS SLW stack uniformity – note that these data were measured on a 0-140cm⁻¹ spectrometer range, which results in lower signal to noise at lower frequencies. The calibration data shown in section 20 are produced from several higher quality scans over smaller frequency ranges.

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SECTION 27 - Reference List of EIDP's

This EIDP will become an annex to the JPL FS SLW BDA.

Associated

Title (Listed in alphabetical order)	ID (Serial No.)	Acronym	Document No.	<u>Issue</u>	<u>Date</u>
SLW BDA PFM /FS EIDP					

Lower Level

<u>Title</u> (Listed in alphabetical order)	ID (Serial No.)	<u>Acronym</u>	Document No.	<u>Issue</u>	<u>Date</u>

SECTION 28 - Mass Records

Assembly	Final measured mass		
FILT-FS-210 – FS SLW assembly	11.2 ± 0.1 g		

SECTION 29 - Cleanliness Statement **Statement**

The FS 300mK SLW filter assembly (FILT-FS-210) has been cleaned and assembled within a class 1000 clean room to meet the requirements of the Cardiff PA plan (HSO-CDF-PL-007).

Signed	Peter Hargrave, Technical Manager, Cardiff-SPIRE deliverables
Signed	Carole Tucker, Cardiff Filter Production Manager
Signed	lan Walker, Programme Manager, Cardiff AIG.
Date17th D	December 2004

Extra Information

The manufacture of these filter elements took place within a class 1000 clean-room, following the procedures laid out in the UWC document, "UWC Filter Fabrication Procedures.doc". Although filter testing took place within a standard laboratory environment, the mounted filters were subsequently cleaned (using acetone and a de-ionised air-gun), in a class 100 laminar flow cabinet, prior to packaging.

SECTION 30 - Other Useful Information



Figure 12 Photographs of the FS SLW assembly prior to shipping

SECTION 31 - DPL/DML

Refer to the Cardiff-SPIRE PFM deliverables lists.

Cardiff-SPIRE-DML	HSO-CDF-LI-074
Cardiff-SPIRE-DMPL	HSO-CDF-LI-075
Cardiff-SPIRE-DPL	HSO-CDF-LI-076

SECTION 32 – List of Appendices/Attachments

Appendix #	<u>Title</u> (Listed in alphabetical order)	Document No.	<u>Issue</u>	<u>Date</u>	<u>Notes</u>

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